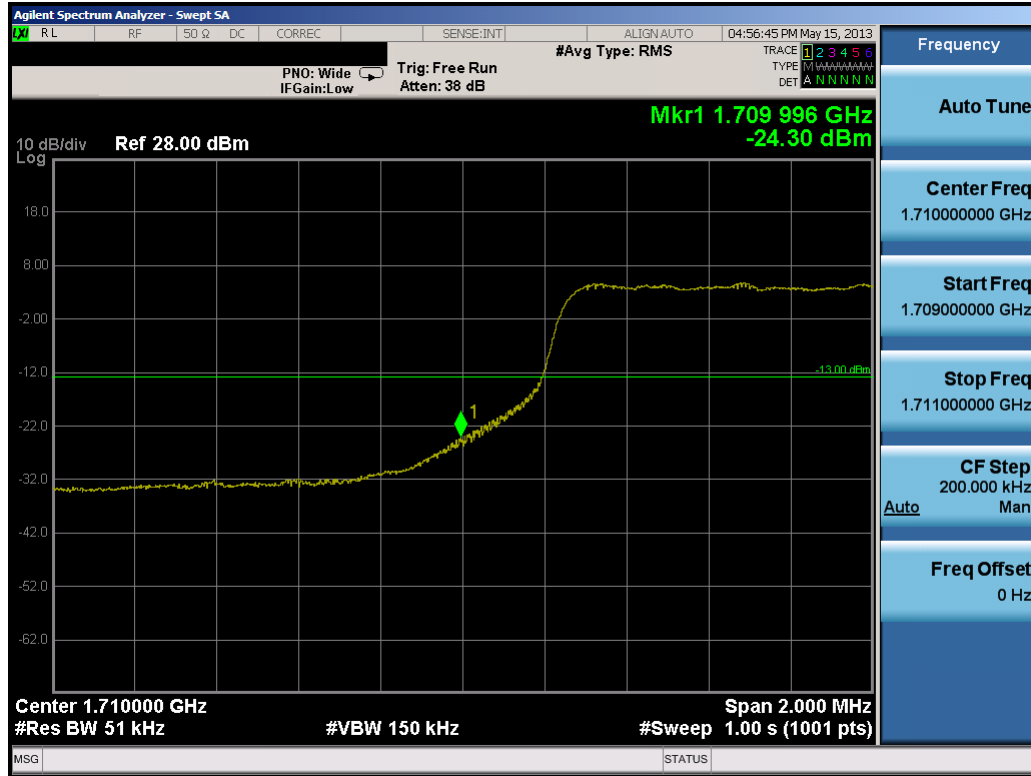


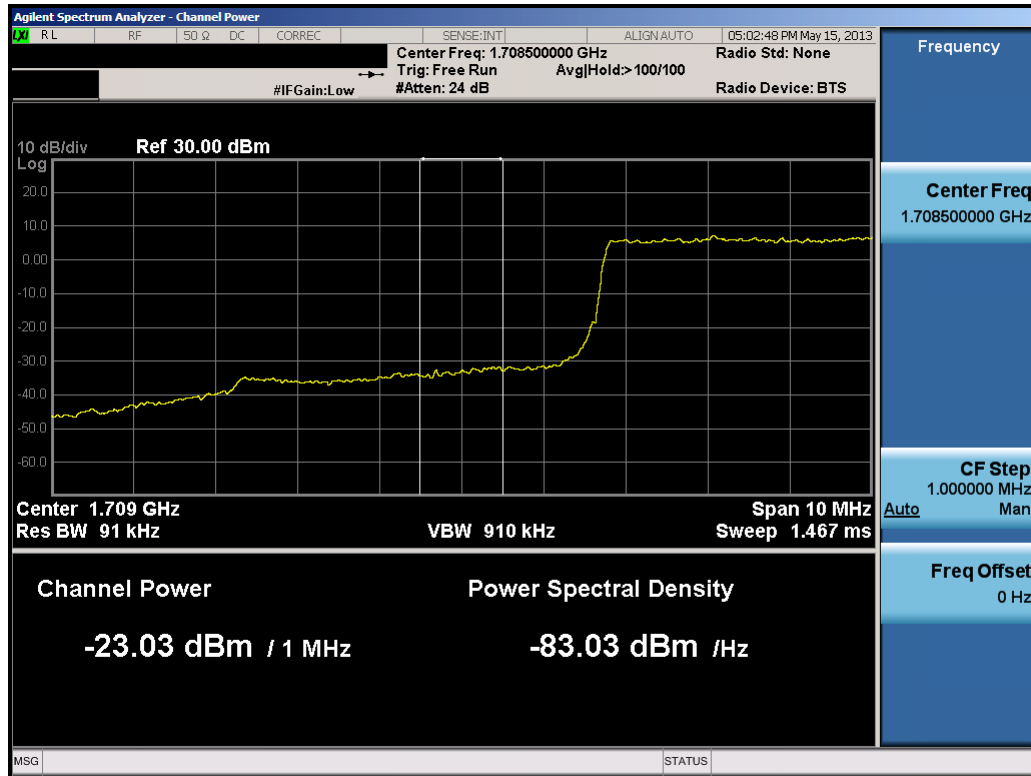
9.0 BAND 4 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.

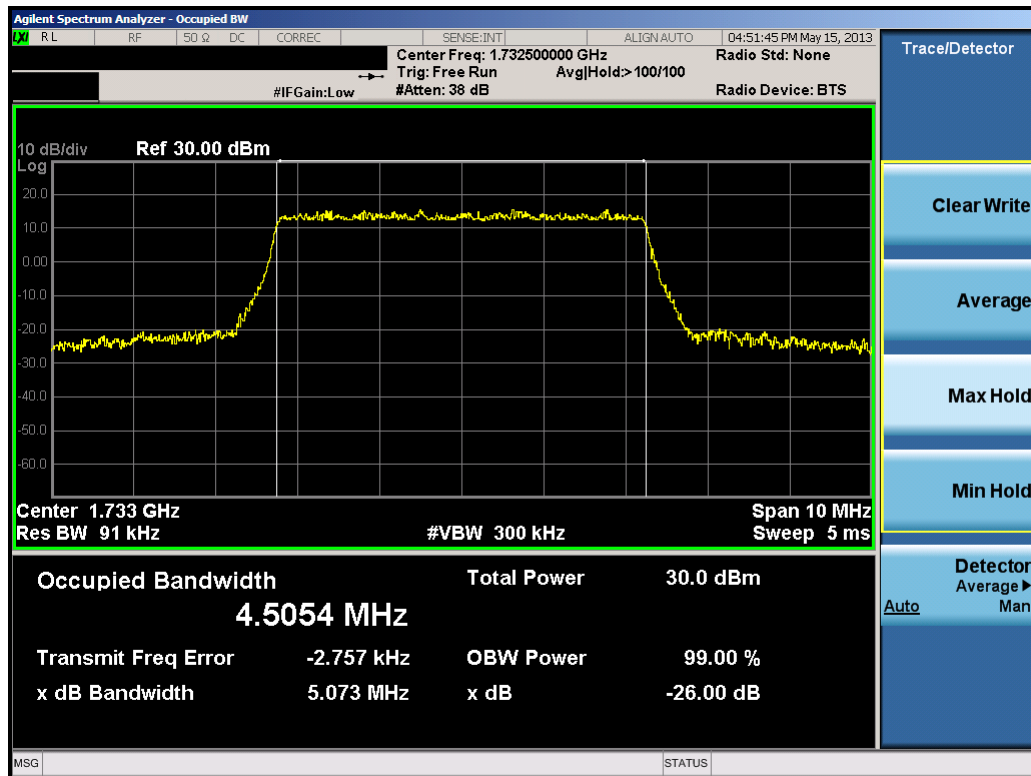


Plot 9-1. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 60 of 118

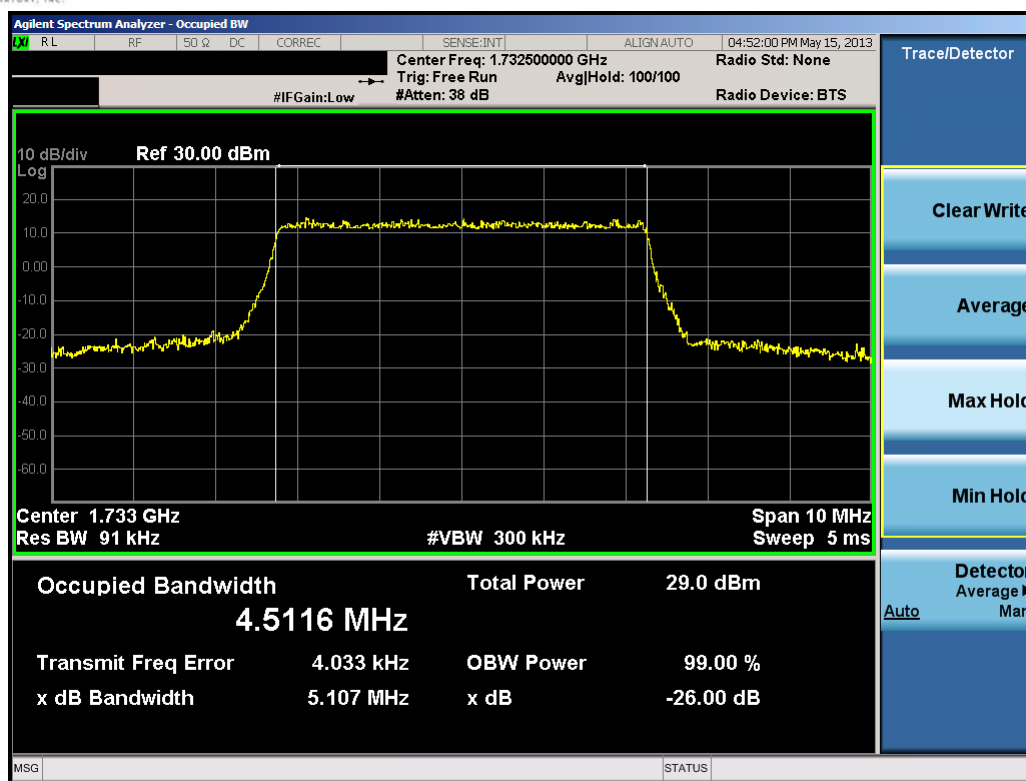


Plot 9-2. Lower Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

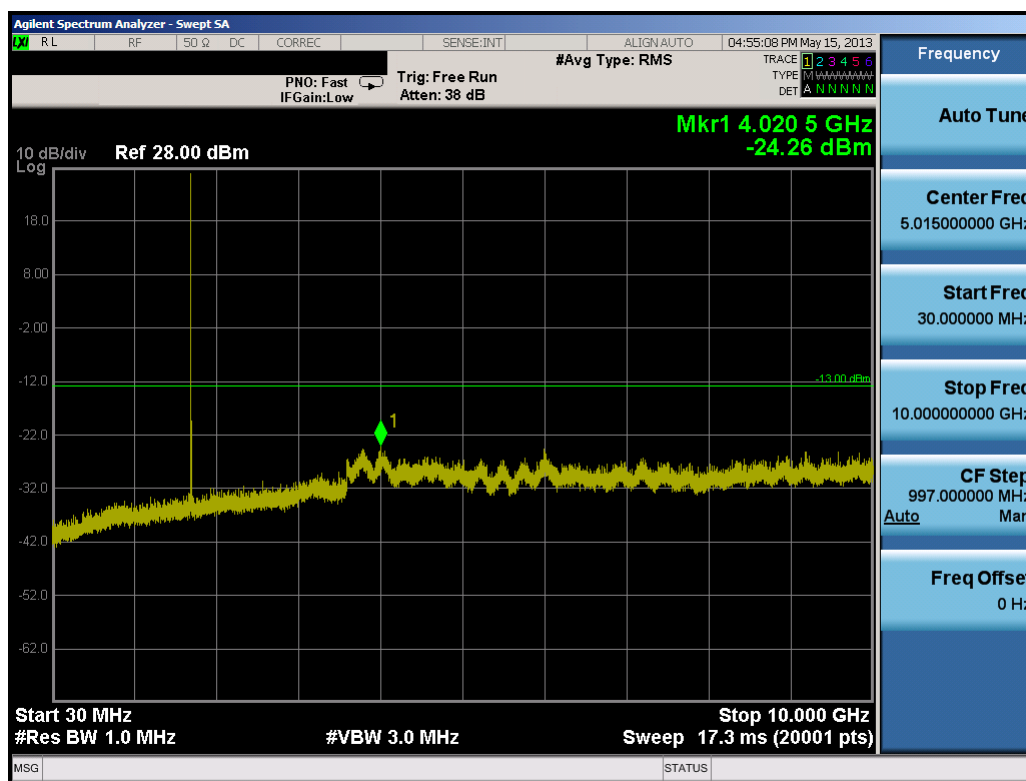


Plot 9-3. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 61 of 118

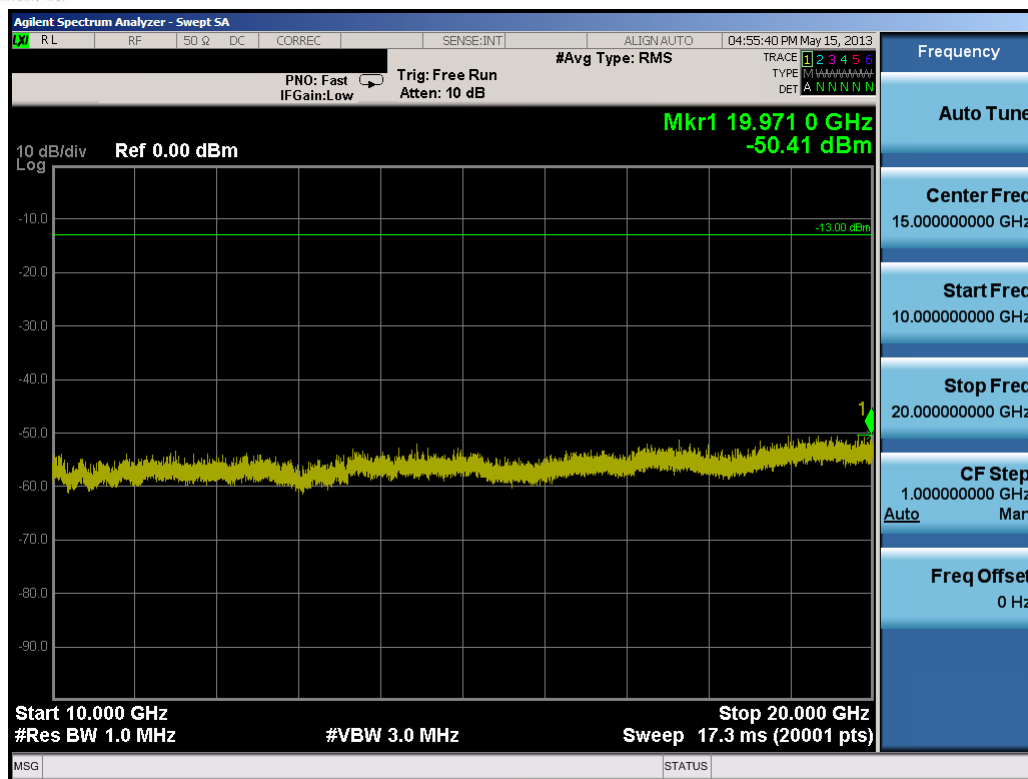


Plot 9-4. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)

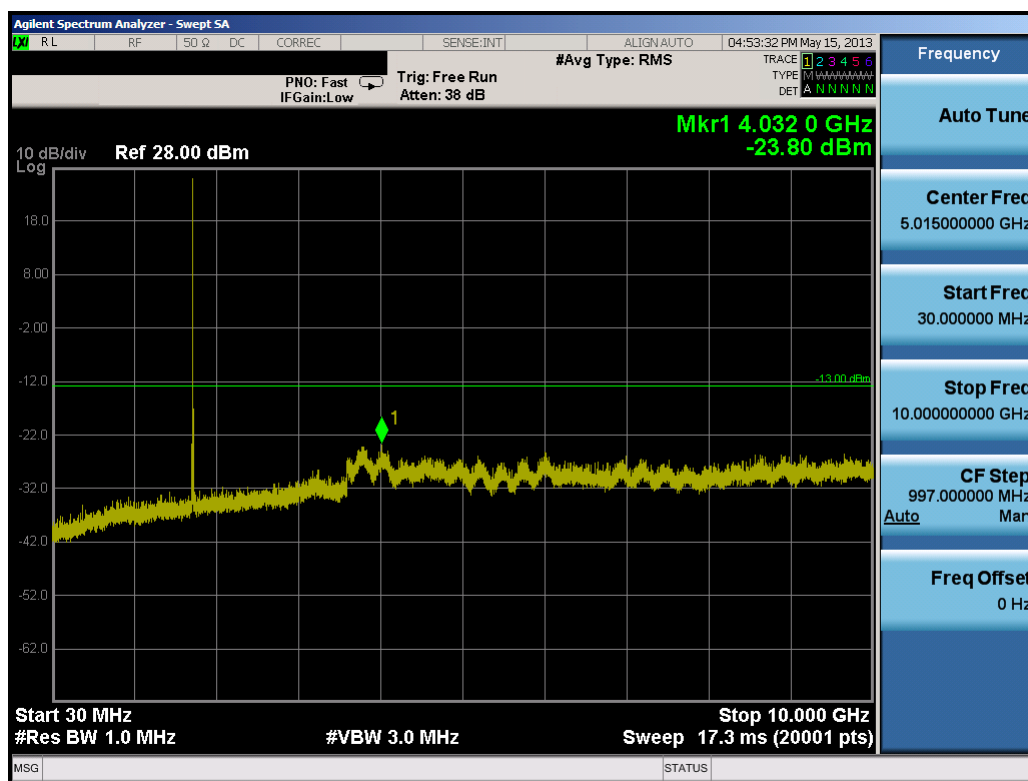


Plot 9-5. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 62 of 118

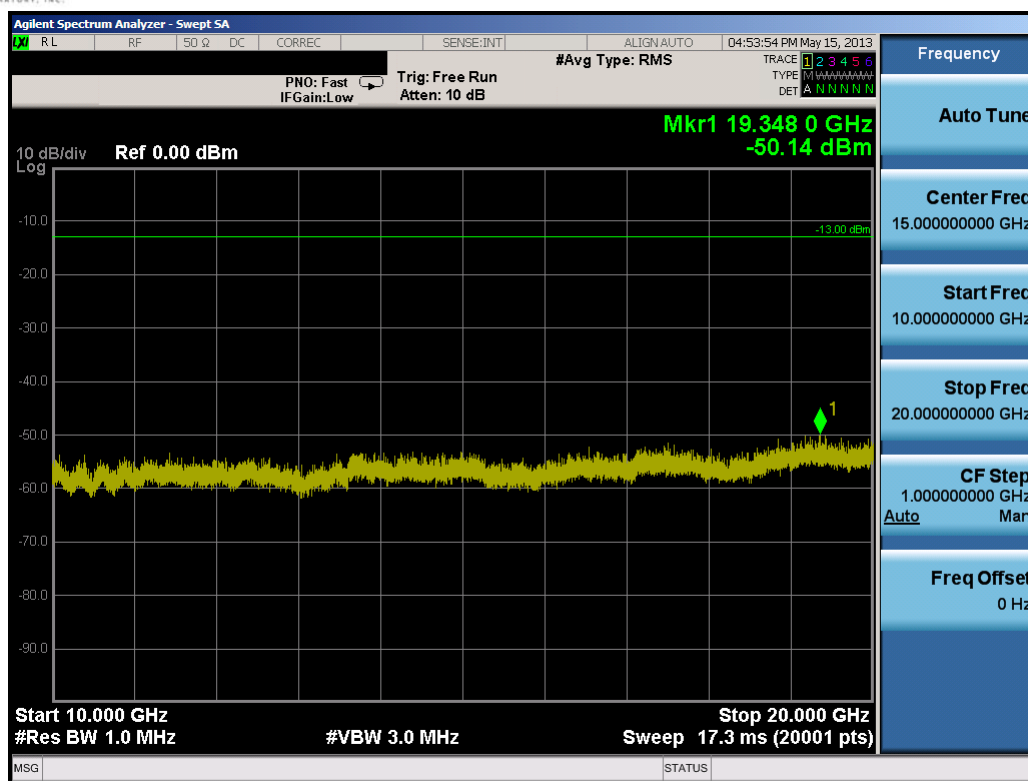


Plot 9-6. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

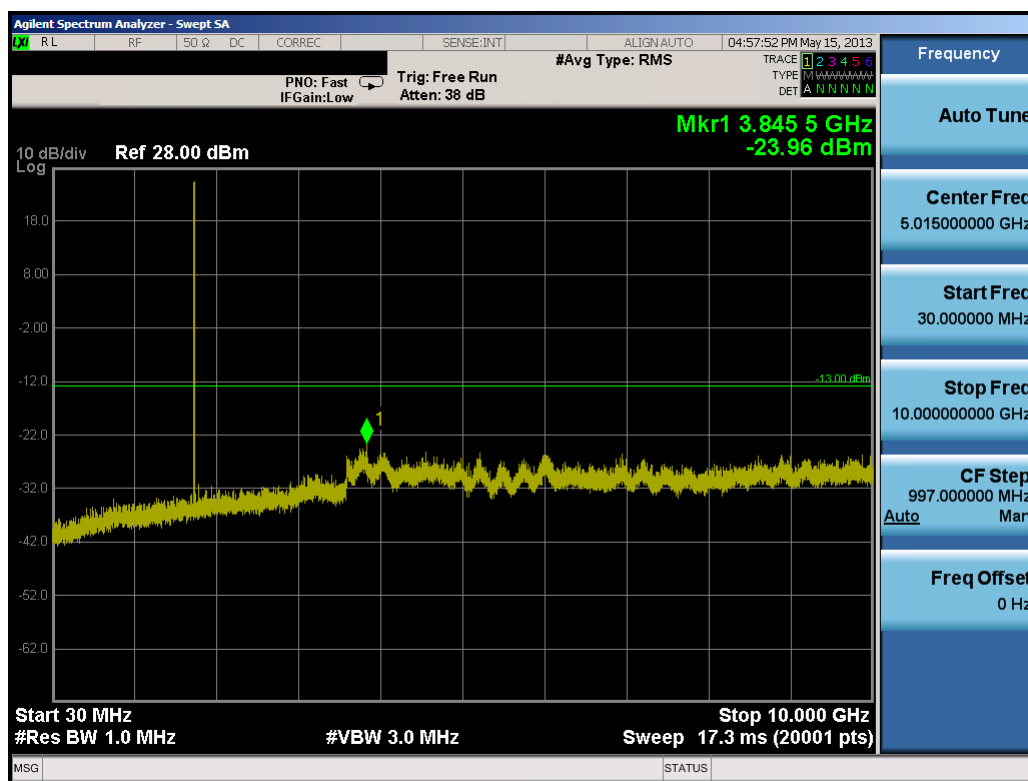


Plot 9-7. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 63 of 118

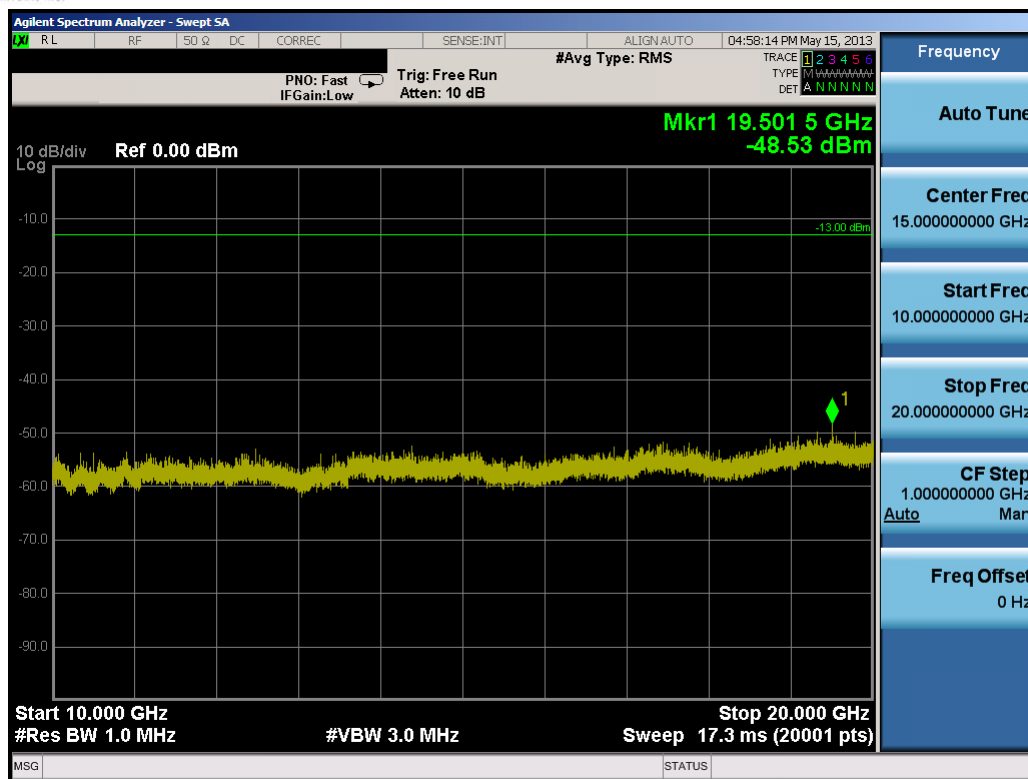


Plot 9-8. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 9-9. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 64 of 118



Plot 9-10. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

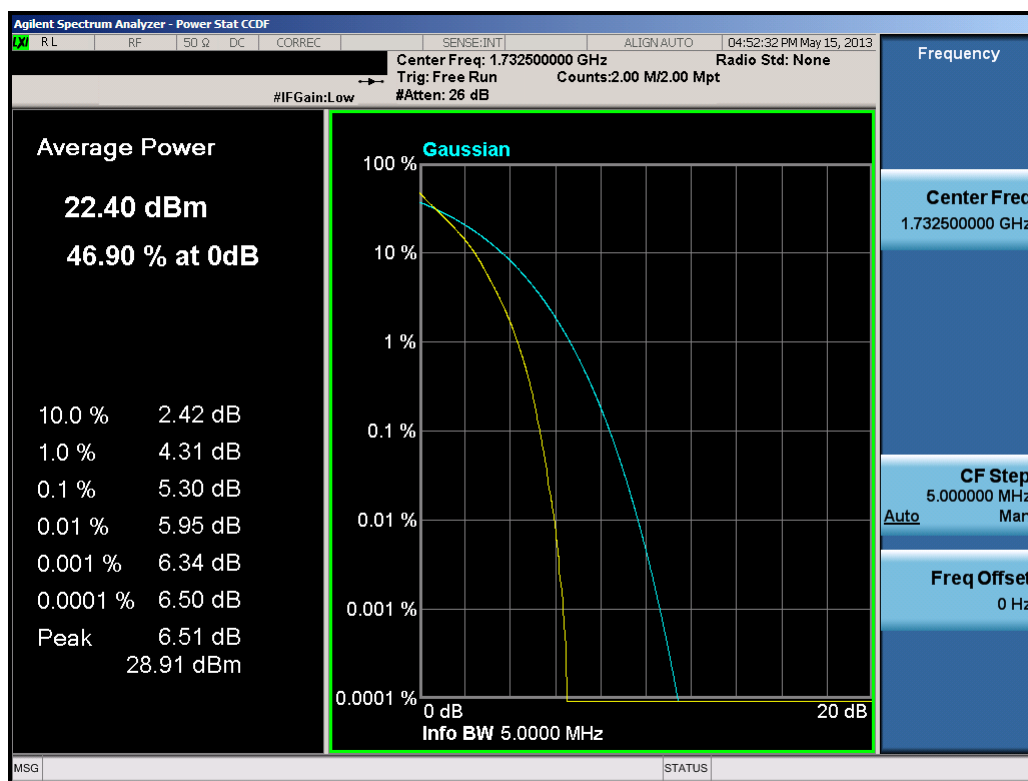


Plot 9-11. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 65 of 118

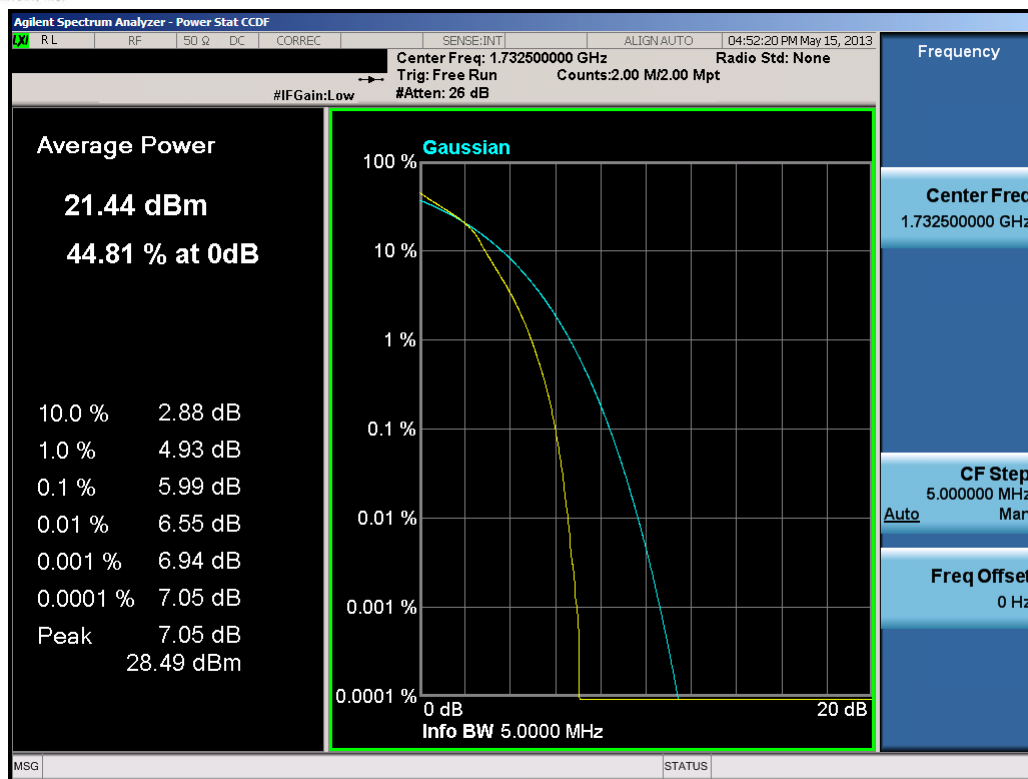


Plot 9-12. Upper Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

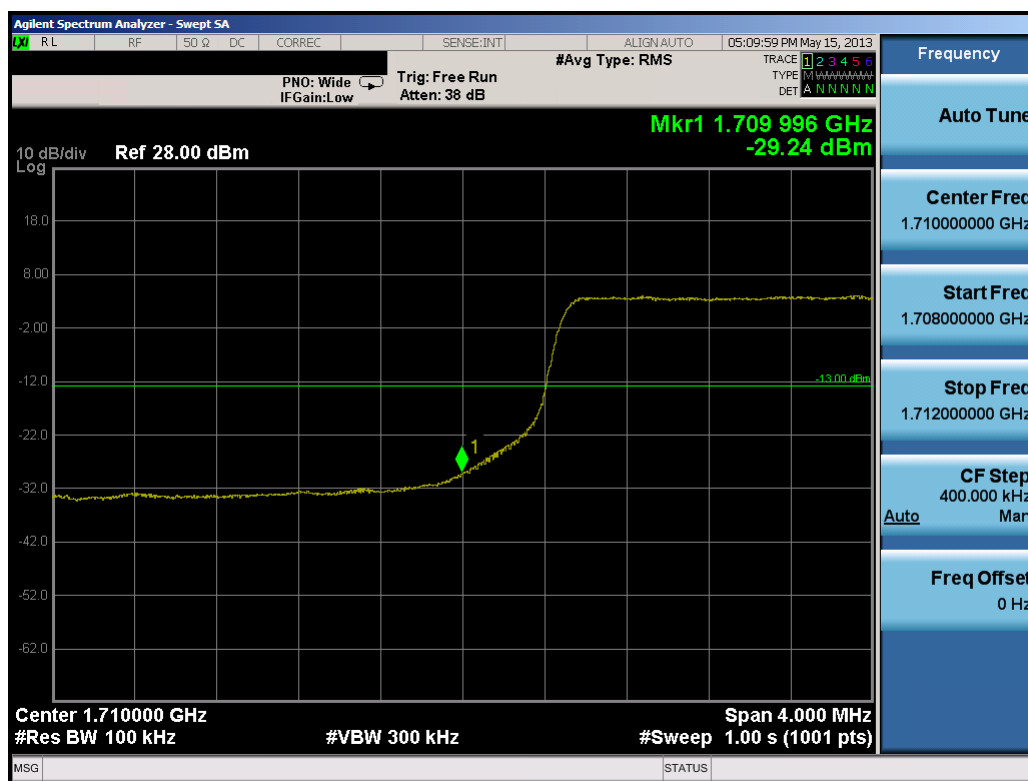


Plot 9-13. PAR Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 66 of 118

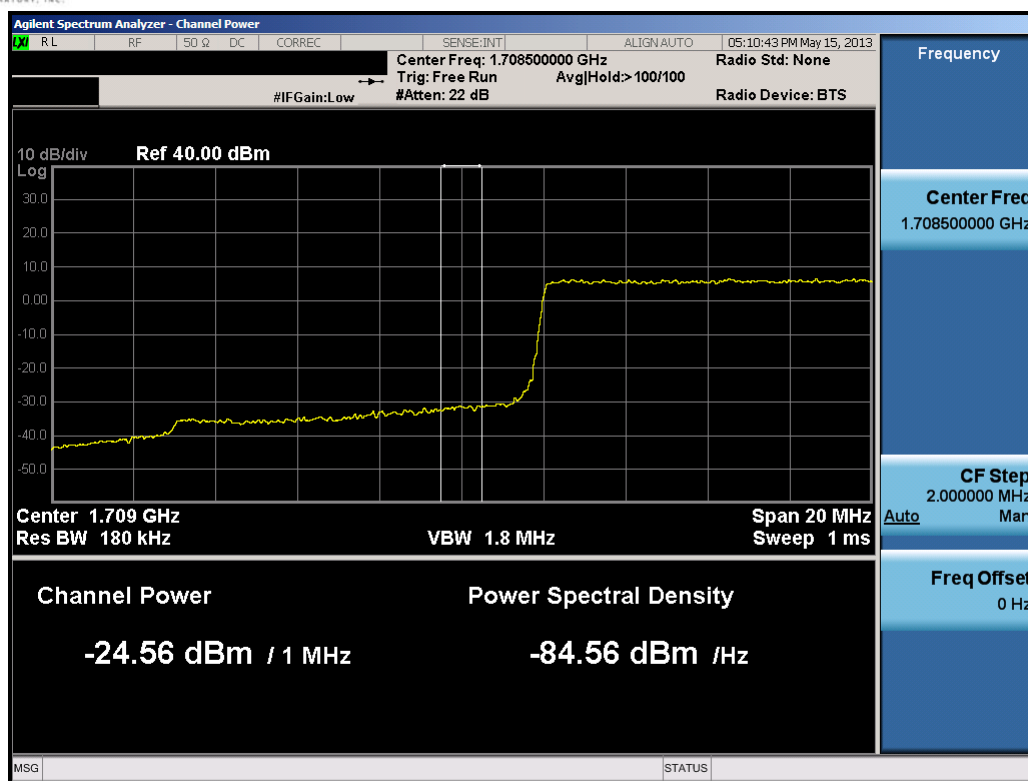


Plot 9-14. PAR Plot (5.0MHz 16-QAM - RB Size 25)

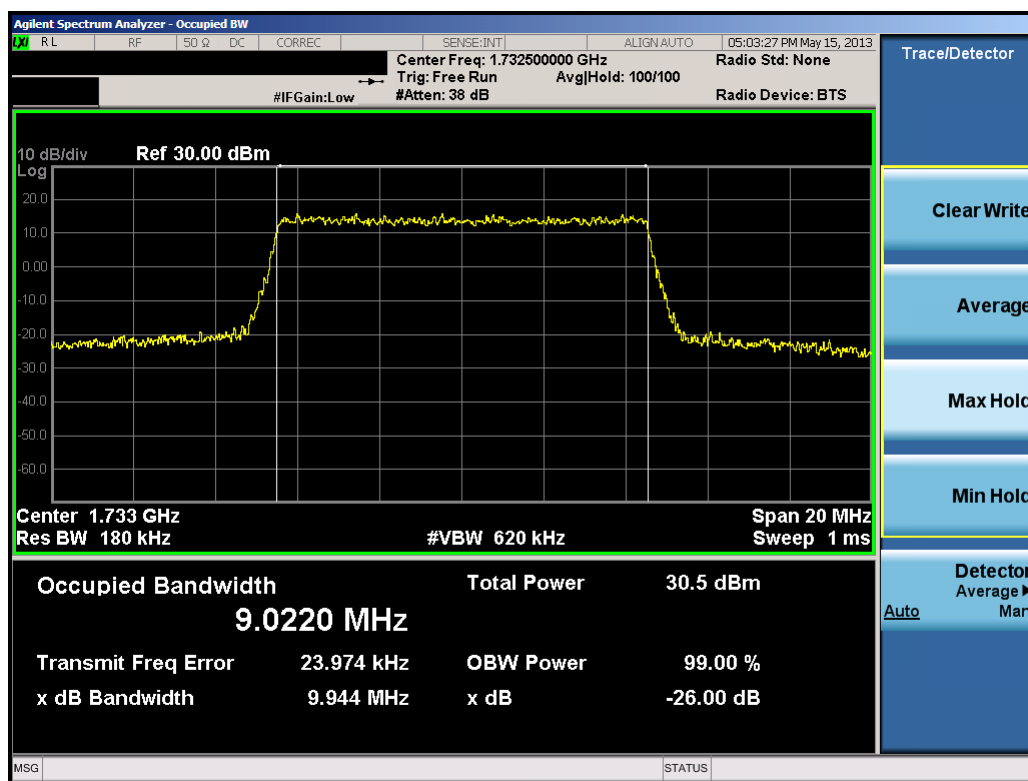


Plot 9-15. Lower Band Edge Plot (10.0MHz QPSK - RB Size 50)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 67 of 118

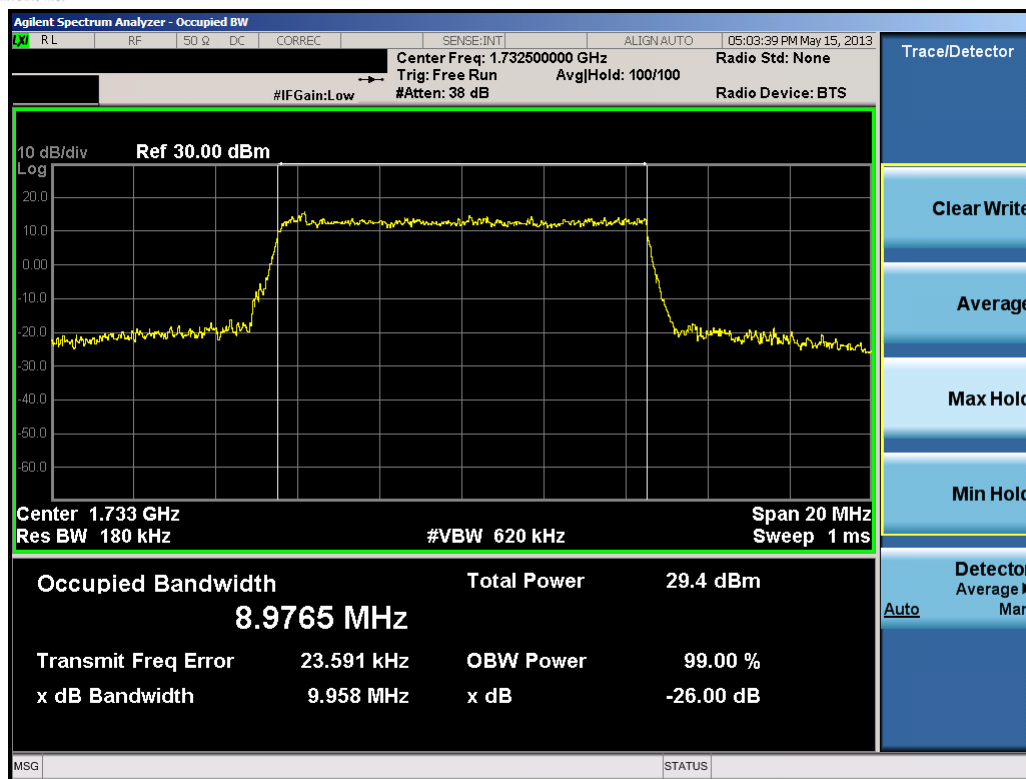


Plot 9-16. Lower Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

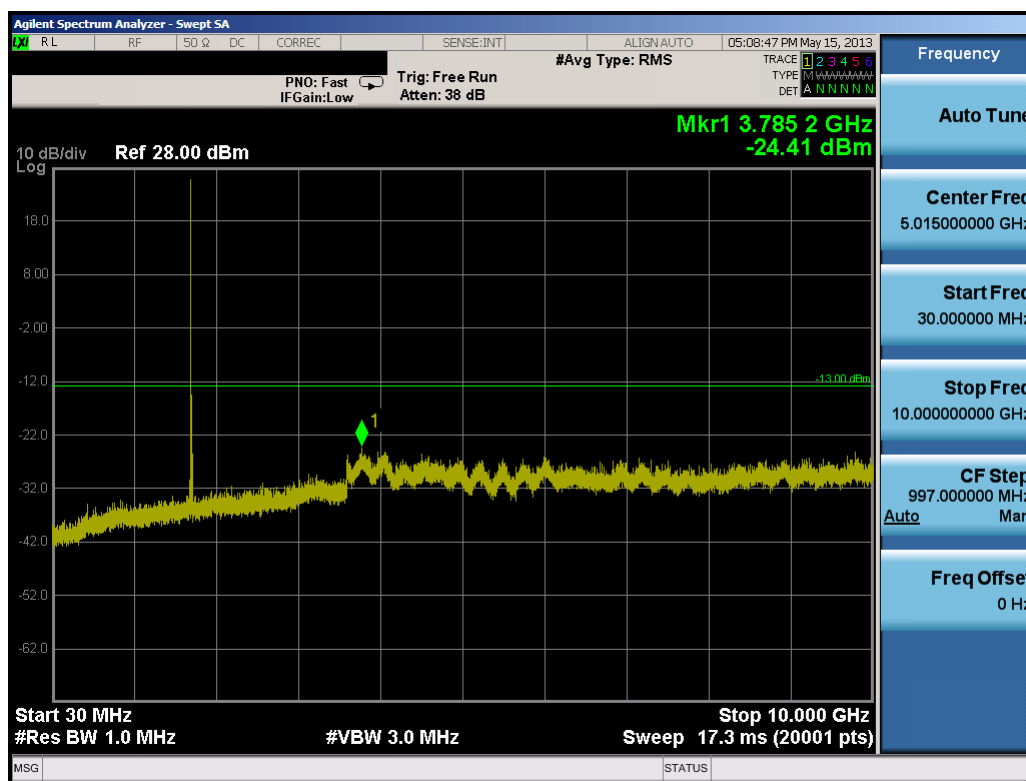


Plot 9-17. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)



FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 68 of 118

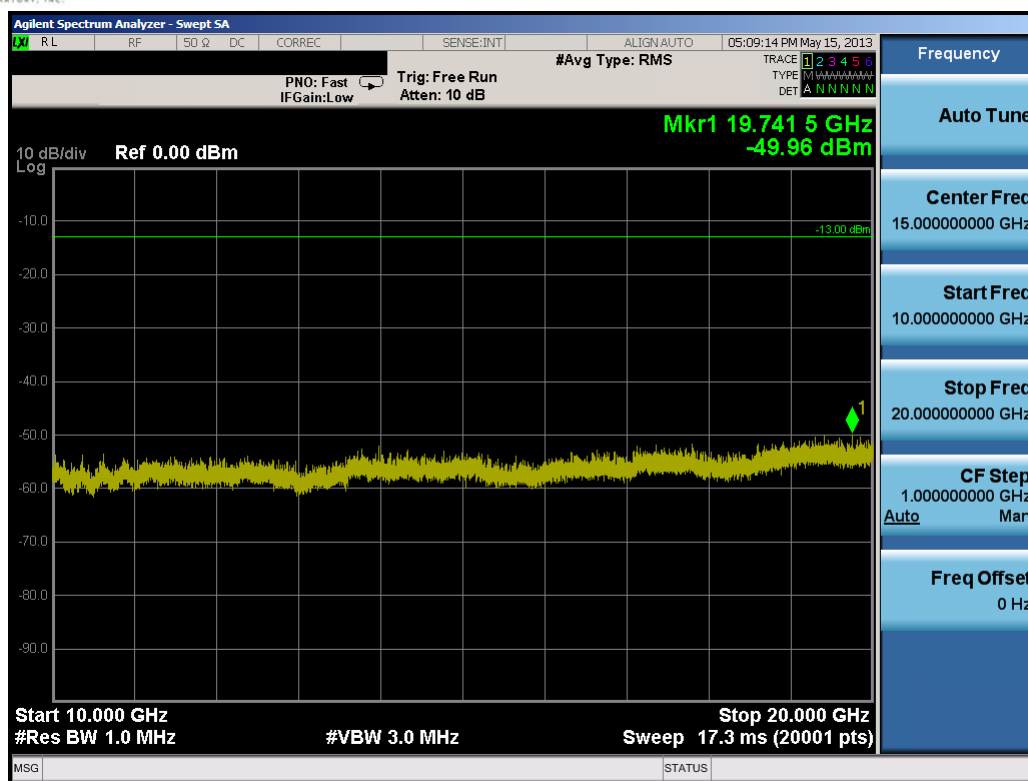


Plot 9-18. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)

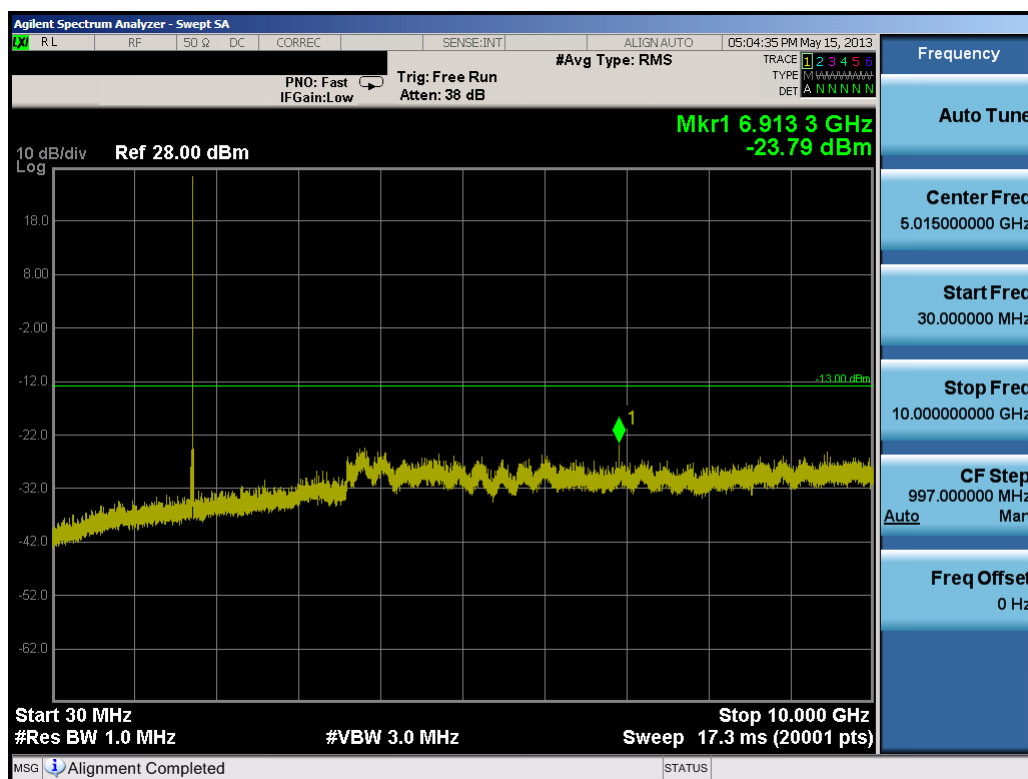


Plot 9-19. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

FCC ID: A3LSGHI527	 FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset	Page 69 of 118

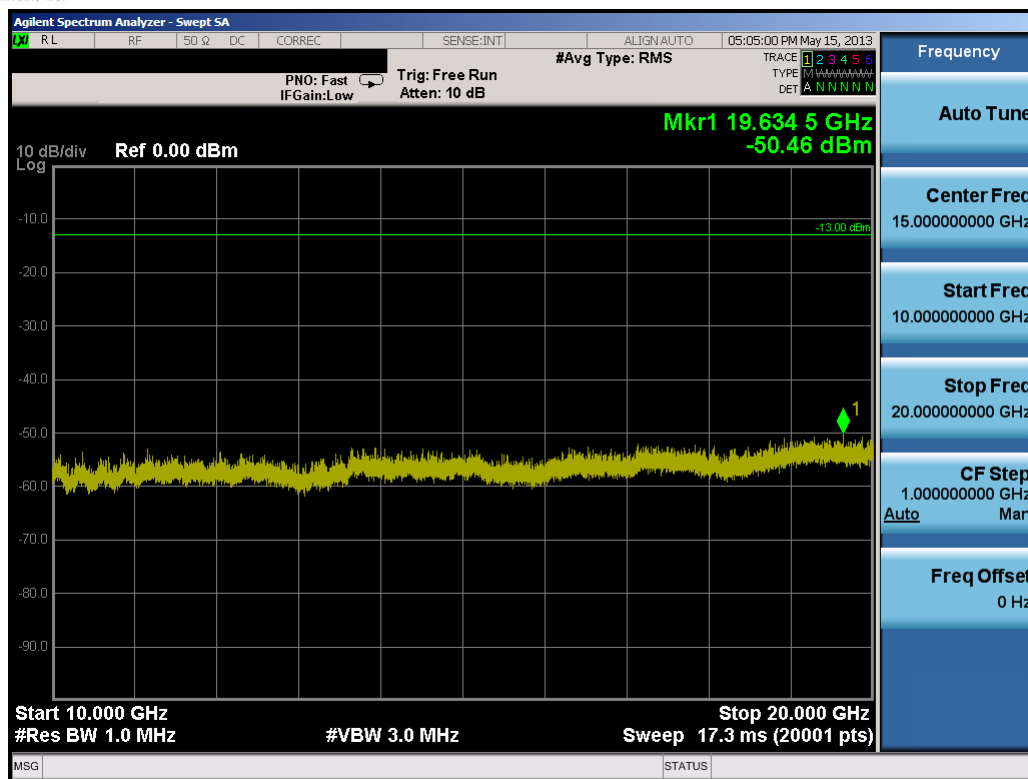


Plot 9-20. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

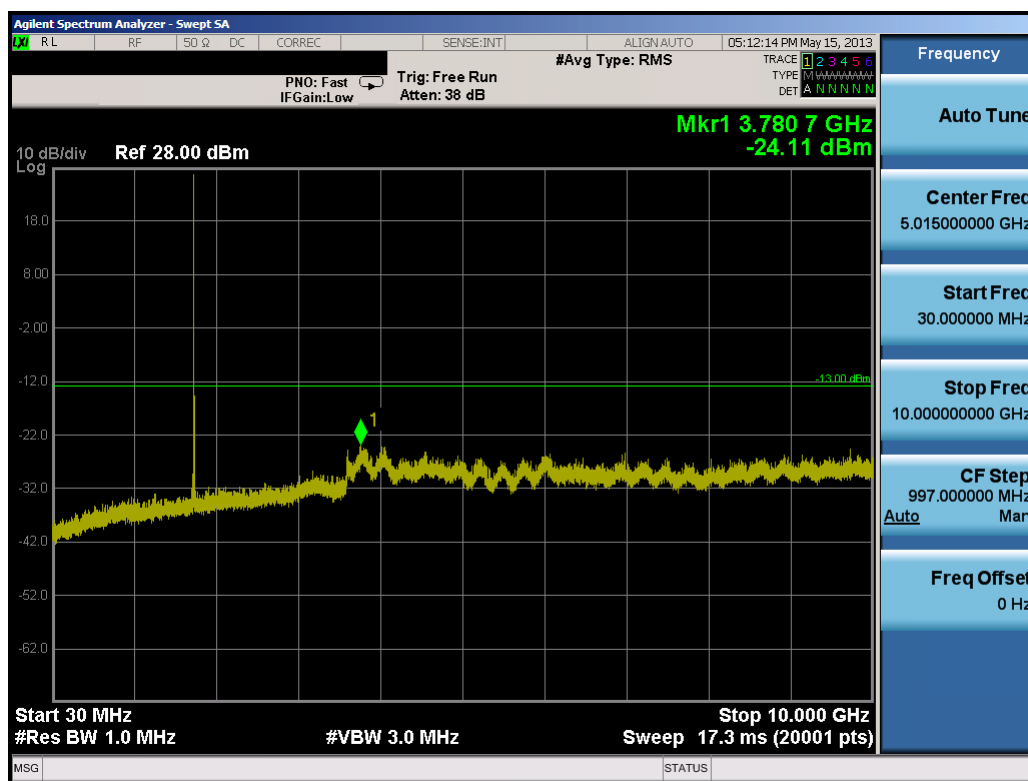


Plot 9-21. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 70 of 118

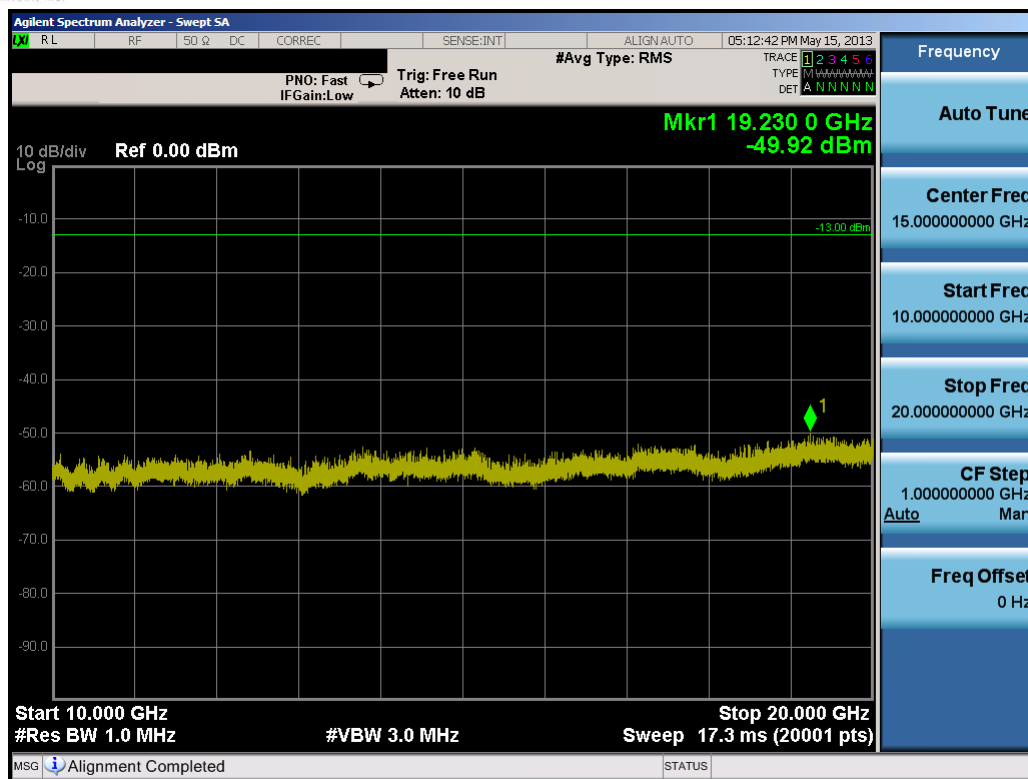


Plot 9-22. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

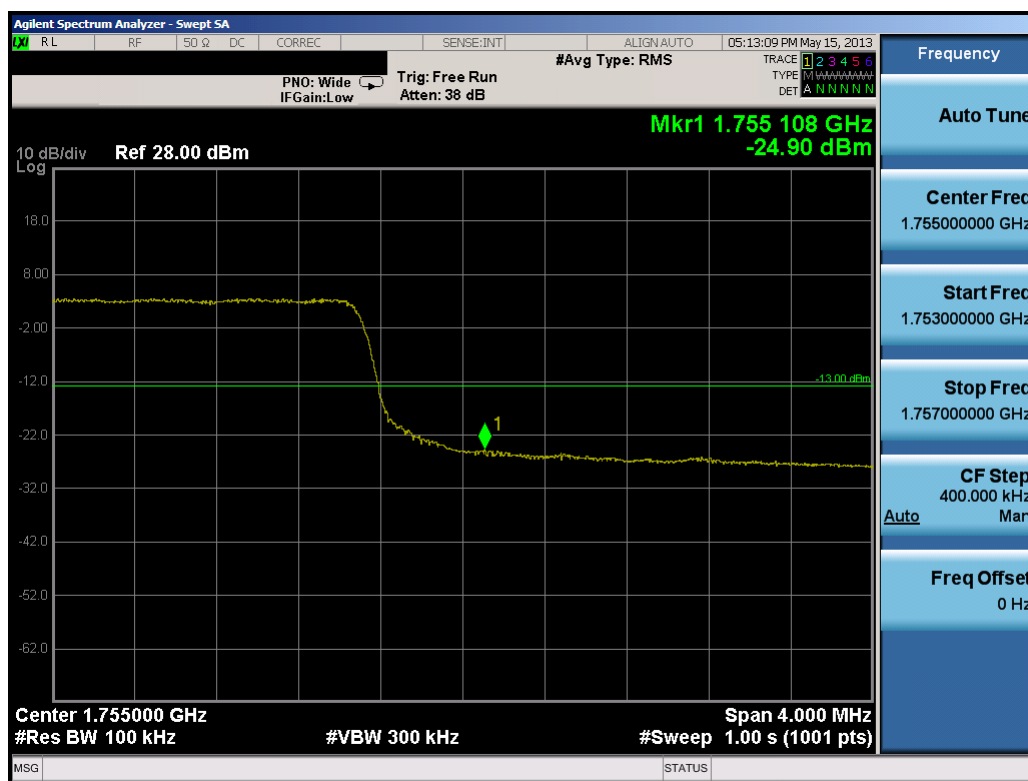


Plot 9-23. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 71 of 118



Plot 9-24. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

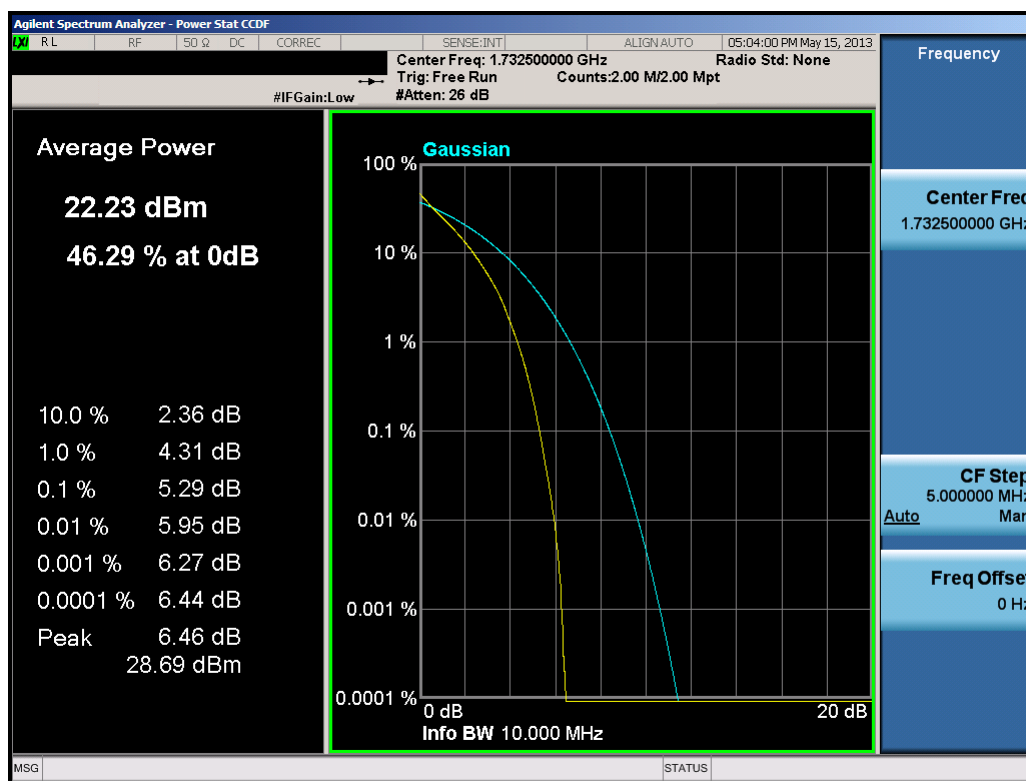


Plot 9-25. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 72 of 118

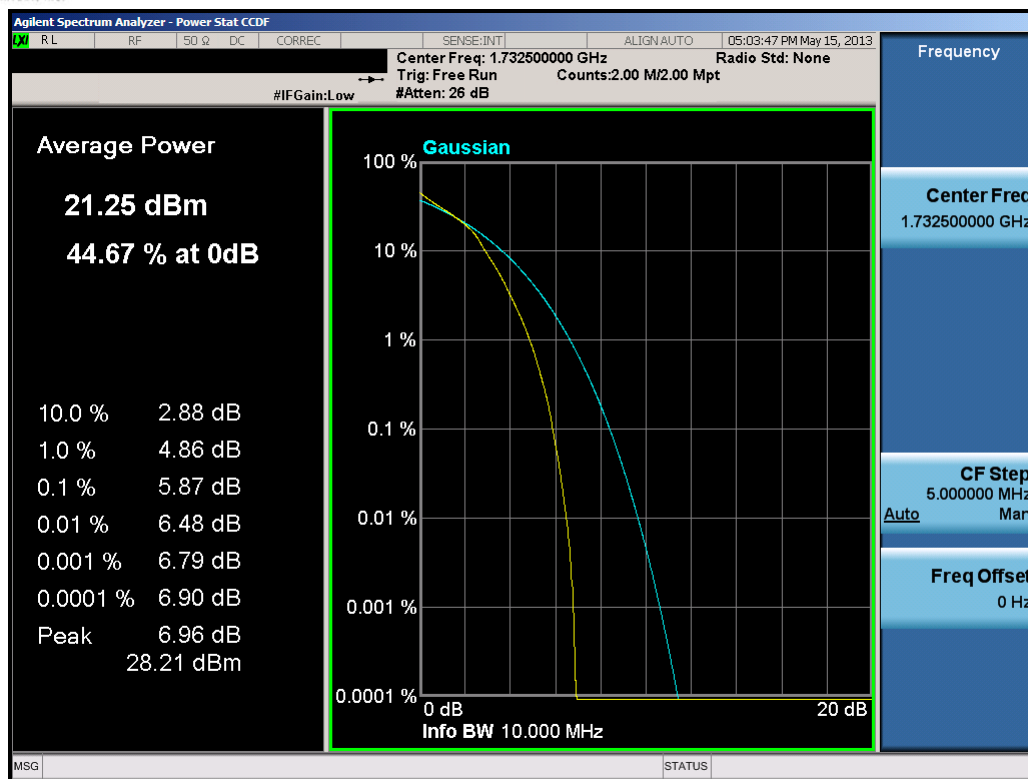


Plot 9-26. Upper Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

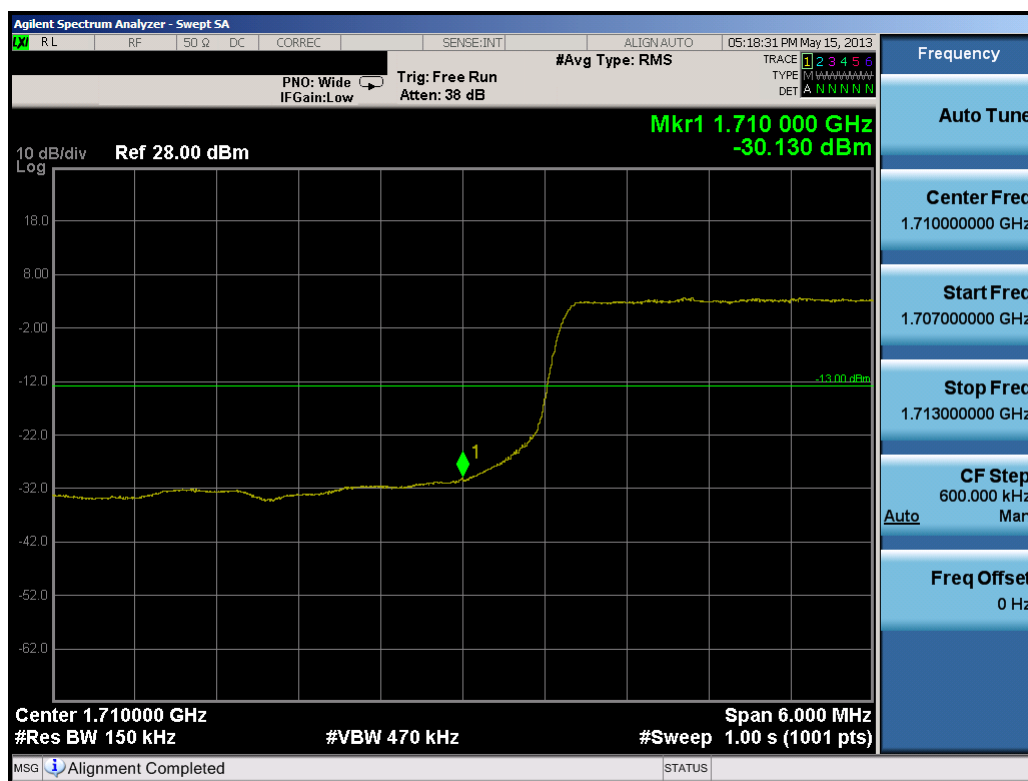


Plot 9-27. PAR Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 73 of 118

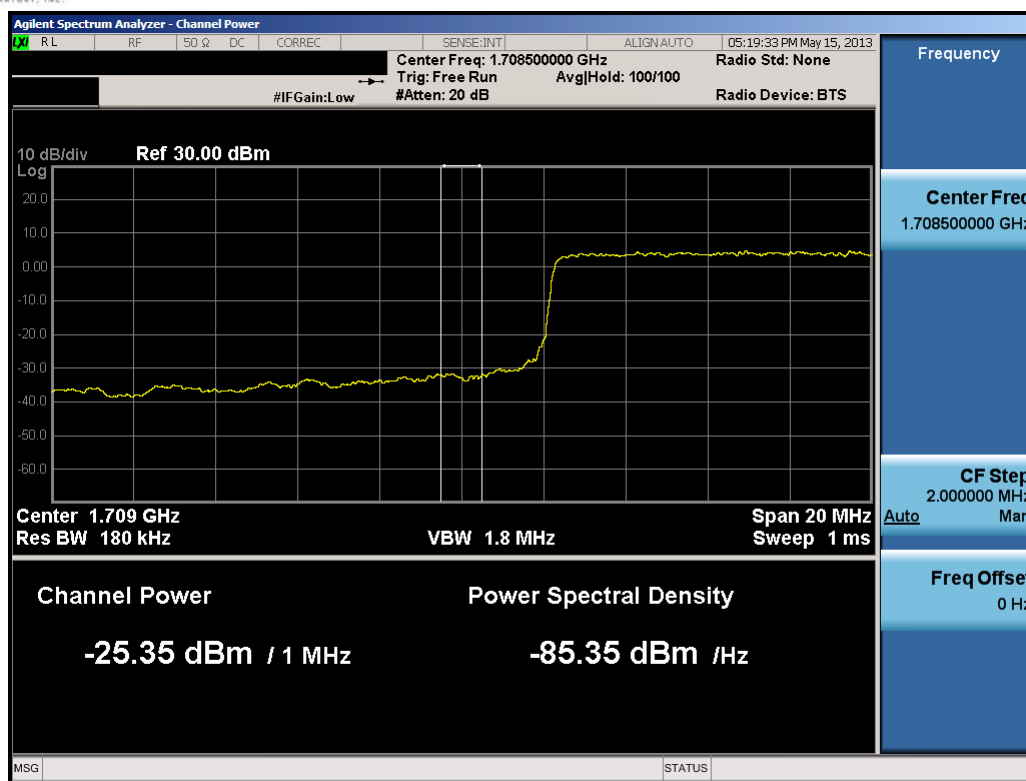


Plot 9-28. PAR Plot (10.0MHz 16-QAM – RB Size 50)

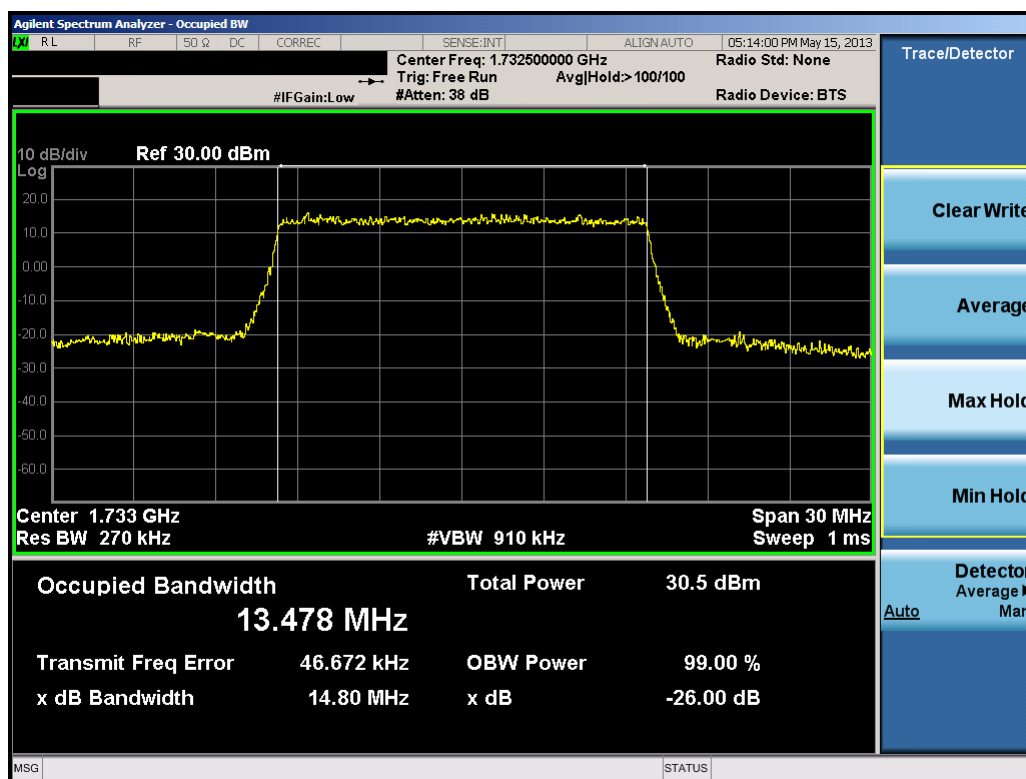


Plot 9-29. Lower Band Edge Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 74 of 118

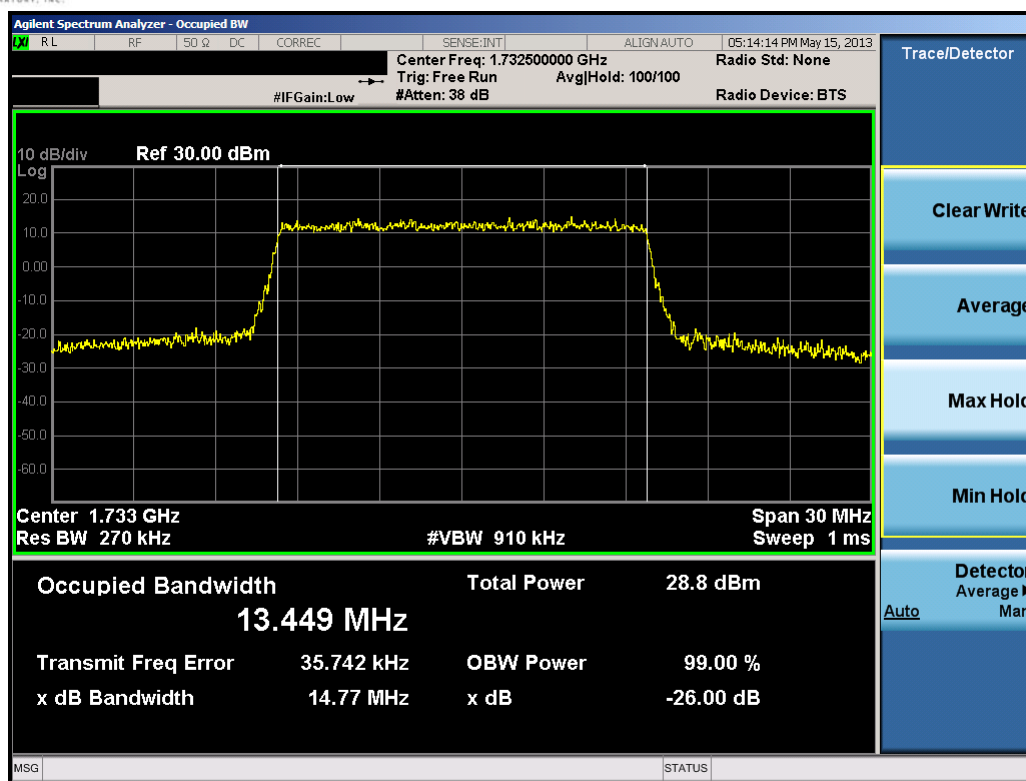


Plot 9-30. Lower Extended Band Edge Plot (15.0MHz QPSK – RB Size 75)

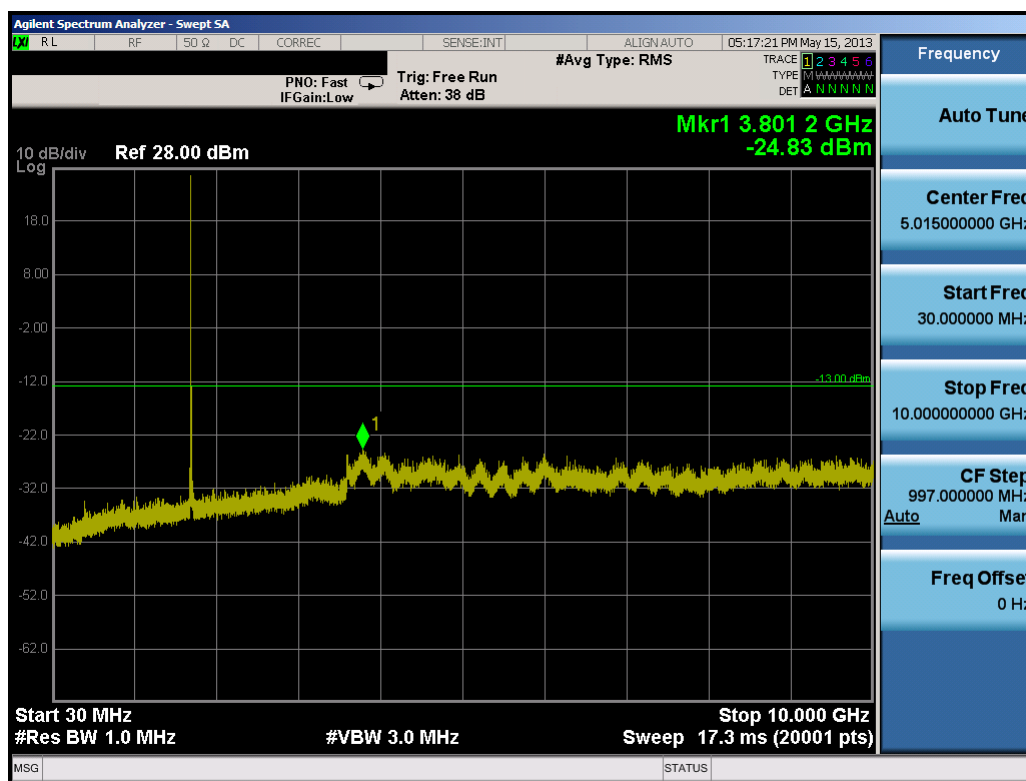


Plot 9-31. Occupied Bandwidth Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 75 of 118

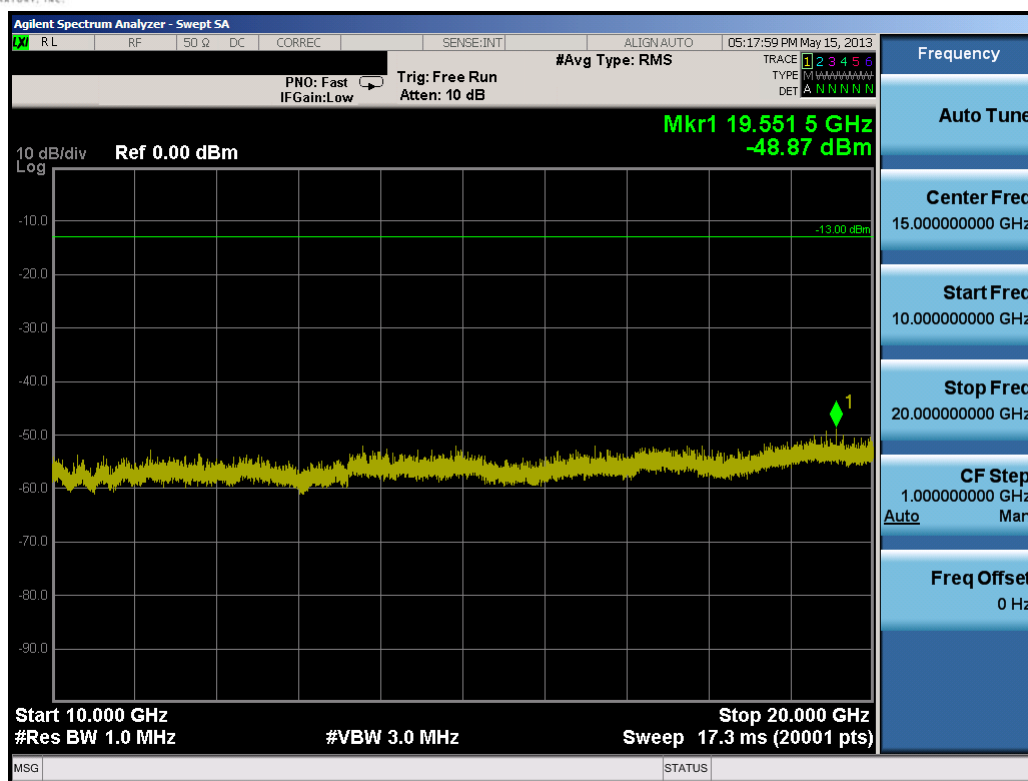


Plot 9-32. Occupied Bandwidth Plot (15.0MHz 16-QAM – RB Size 75)

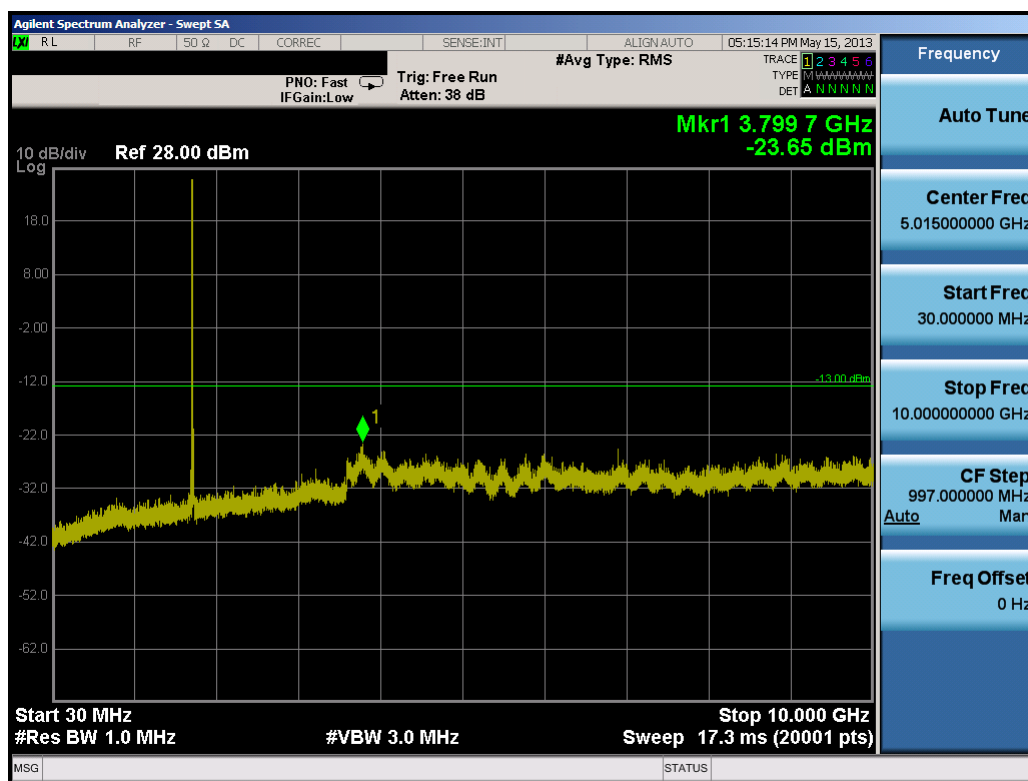


Plot 9-33. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 76 of 118

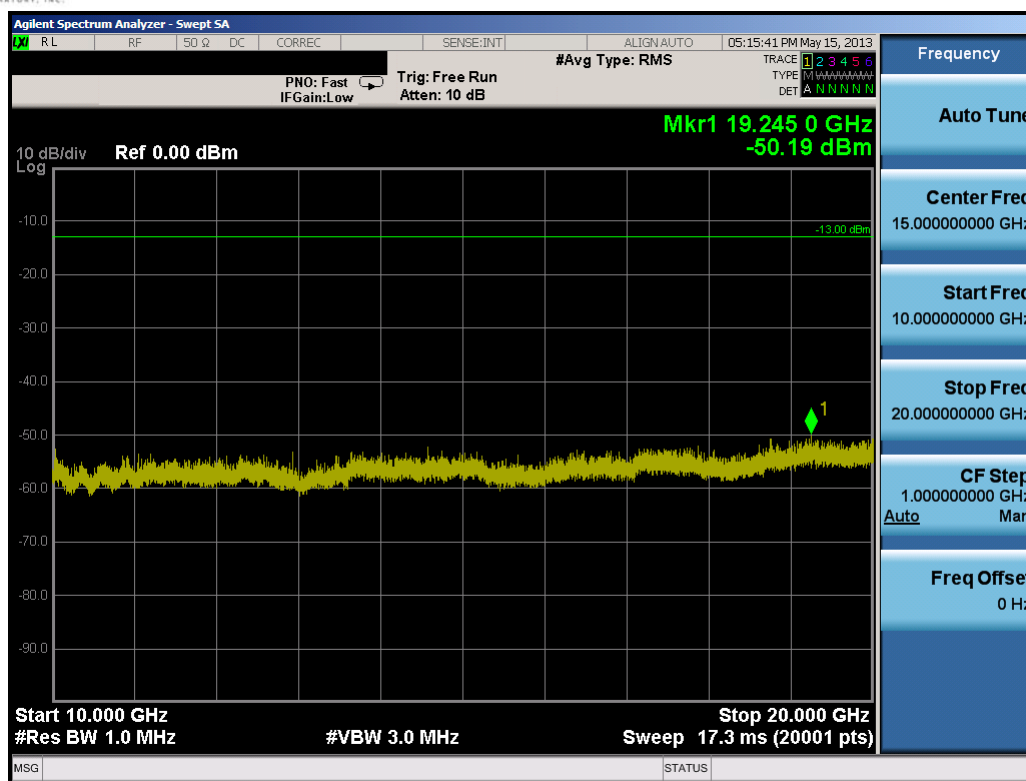


Plot 9-34. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

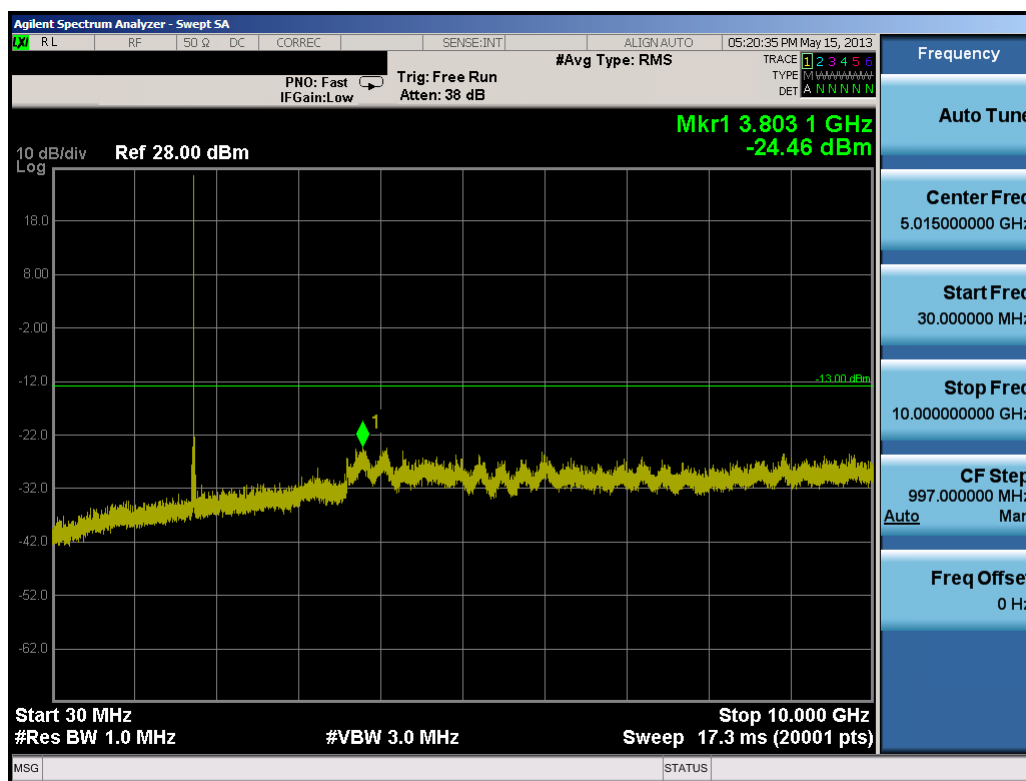


Plot 9-35. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 77 of 118

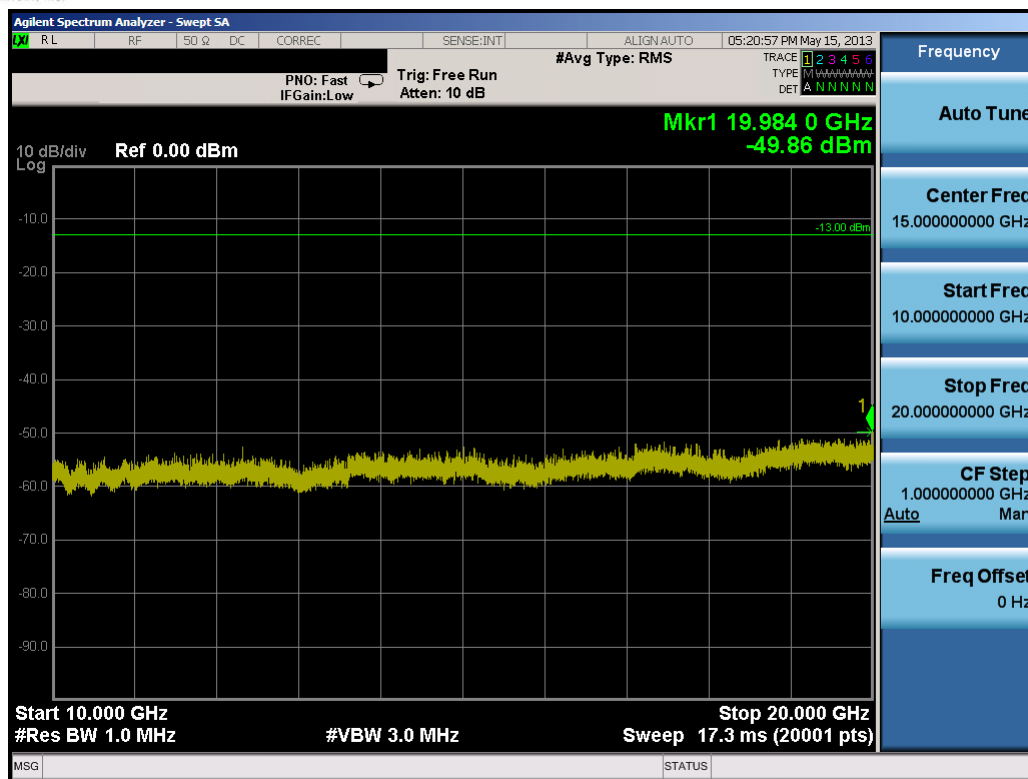


Plot 9-36. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

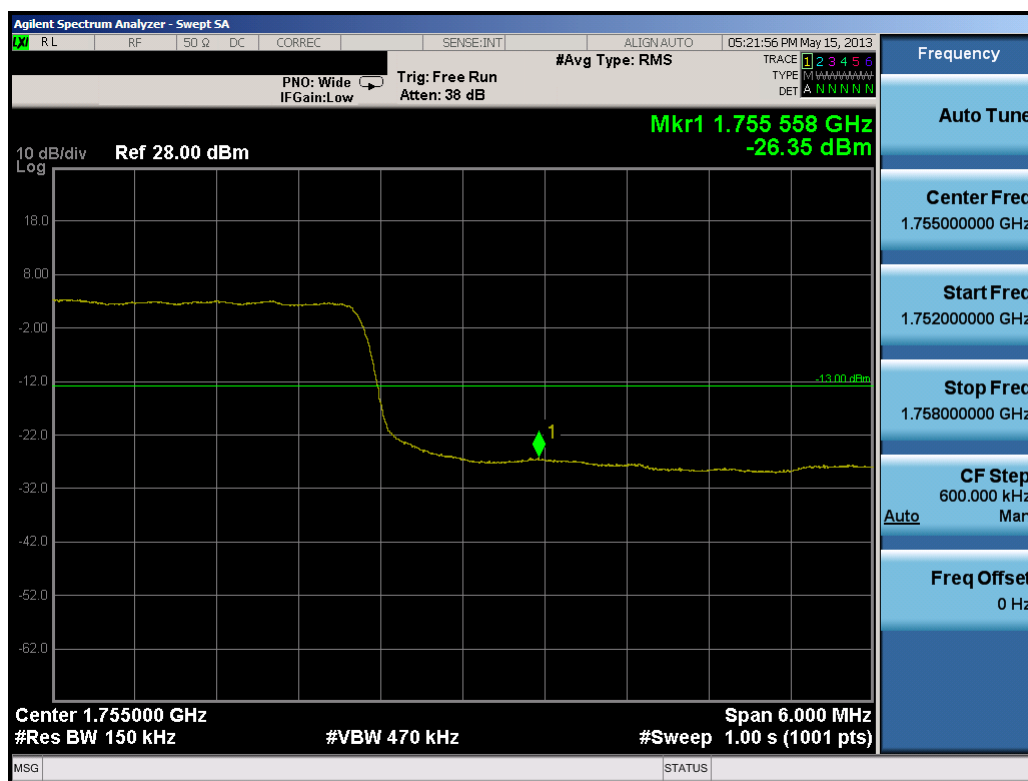


Plot 9-37. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	 FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset	Page 78 of 118

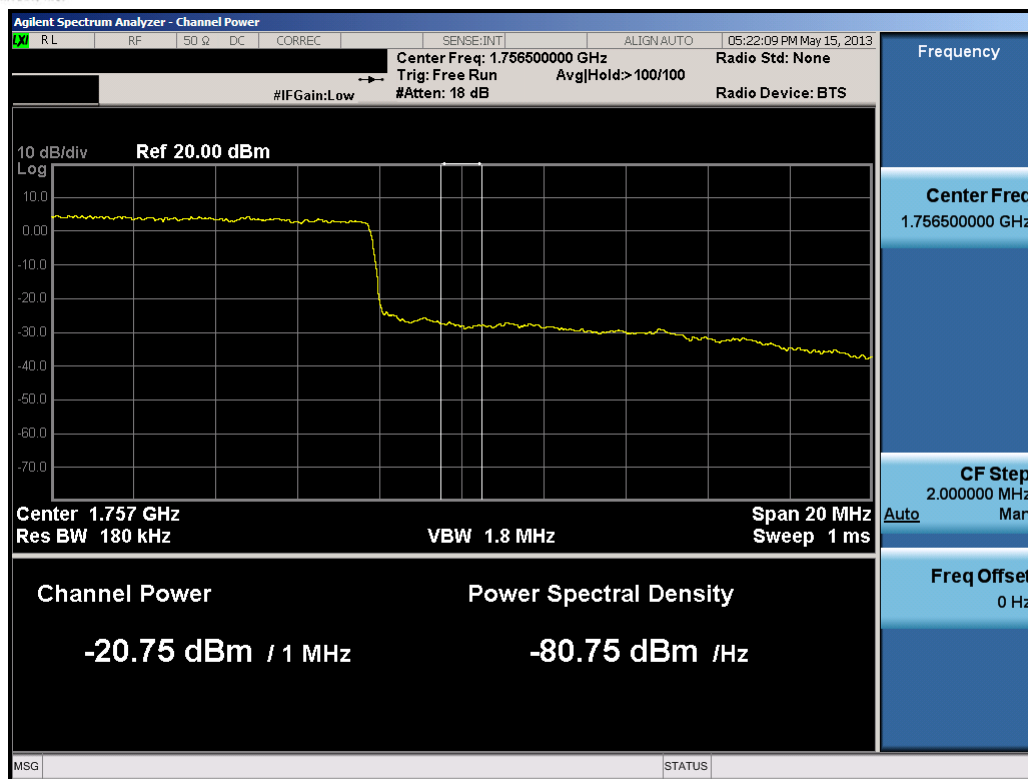


Plot 9-38. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

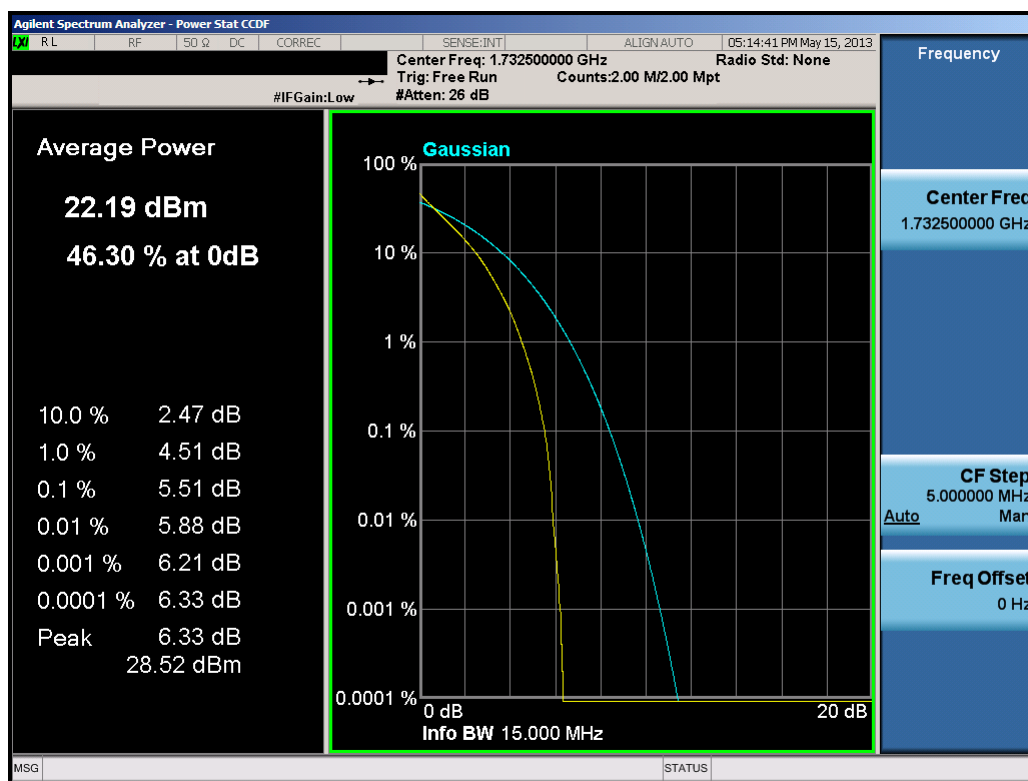


Plot 9-39. Upper Band Edge Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 79 of 118

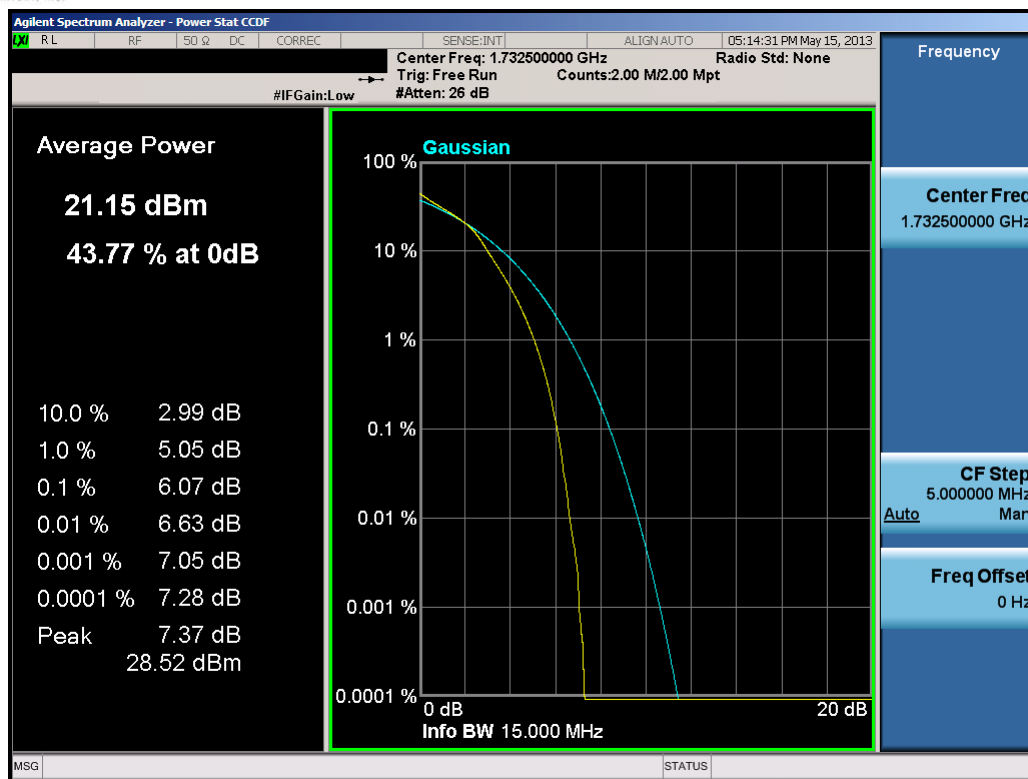


Plot 9-40. Upper Extended Band Edge Plot (15.0MHz QPSK – RB Size 75)

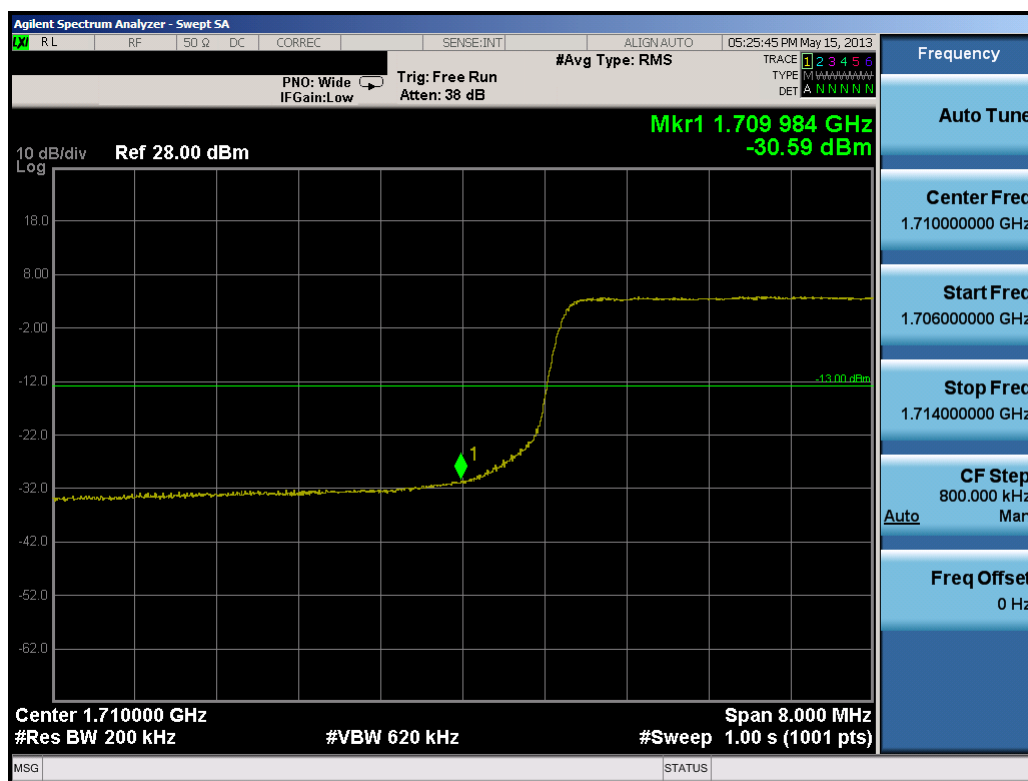


Plot 9-41. PAR Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 80 of 118

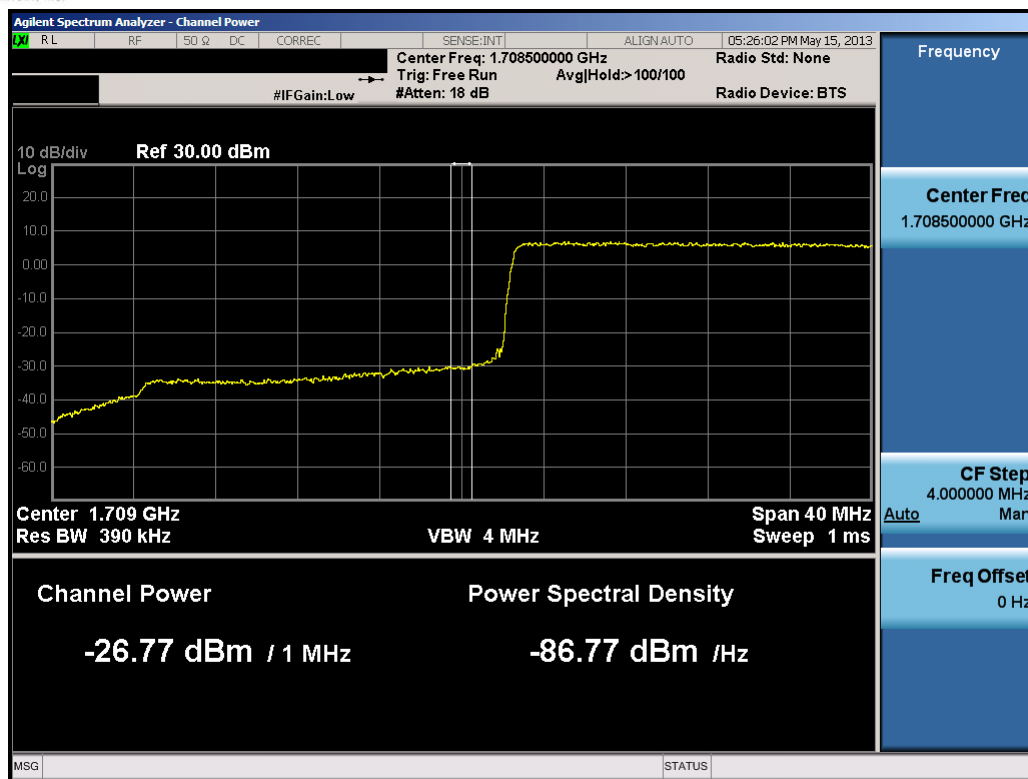


Plot 9-42. PAR Plot (15.0MHz 16-QAM – RB Size 75)

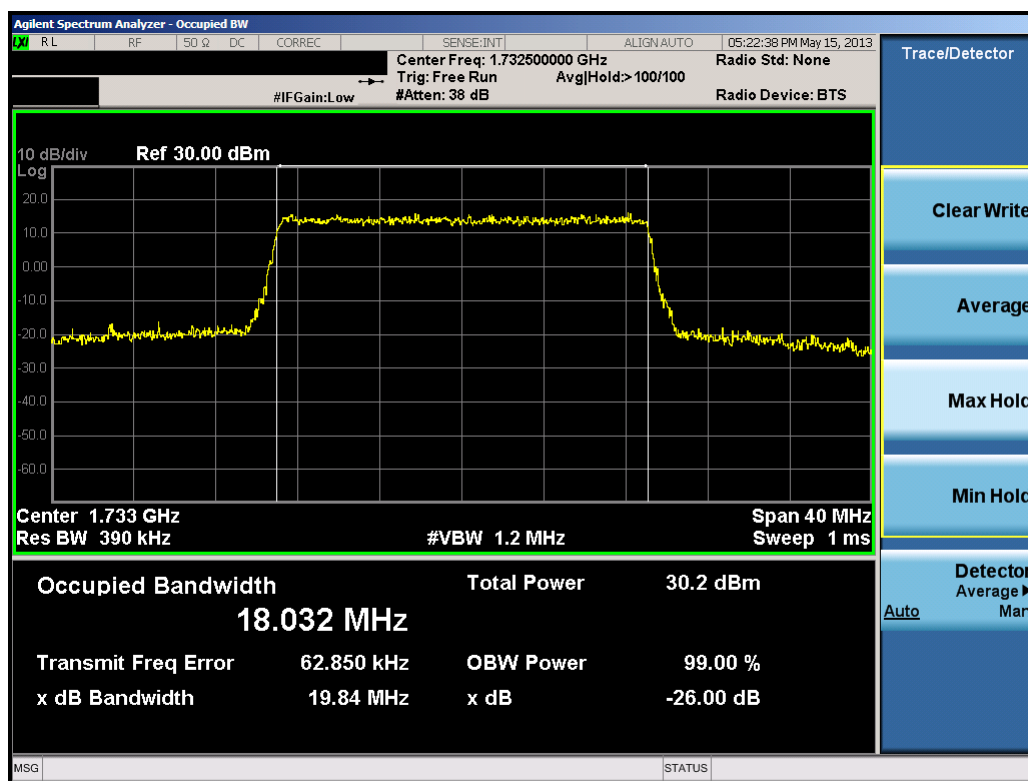


Plot 9-43. Lower Band Edge Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 81 of 118

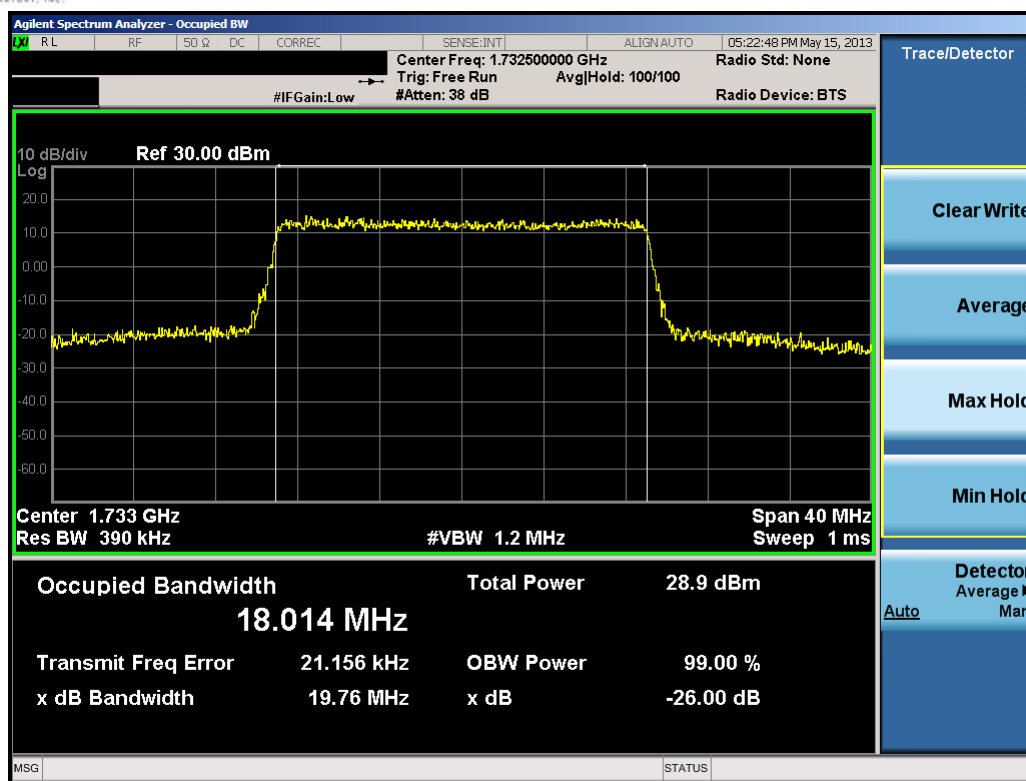


Plot 9-44. Lower Extended Band Edge Plot (20.0MHz QPSK – RB Size 100)

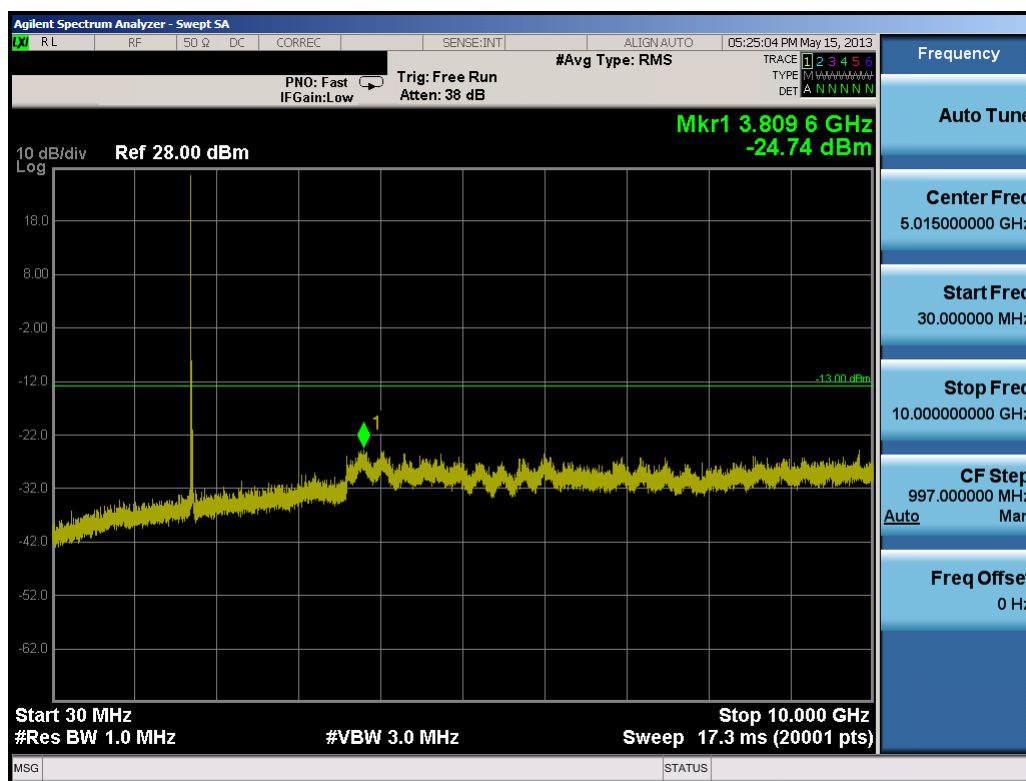


Plot 9-45. Occupied Bandwidth Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 82 of 118

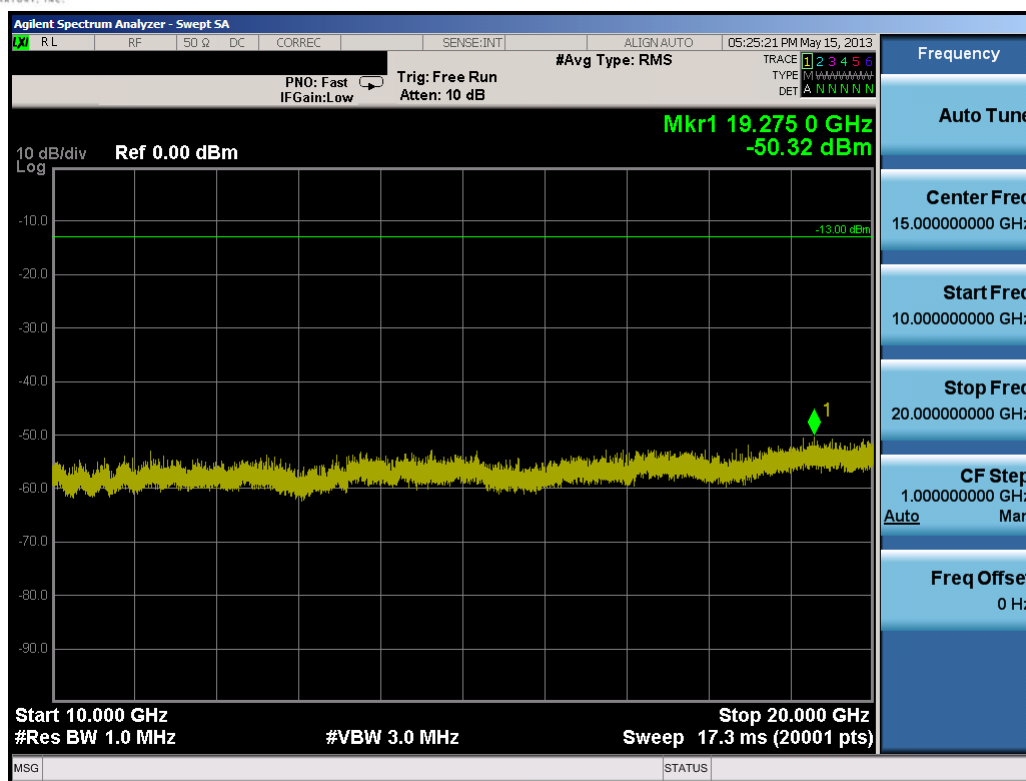


Plot 9-46. Occupied Bandwidth Plot (20.0MHz 16-QAM – RB Size 100)

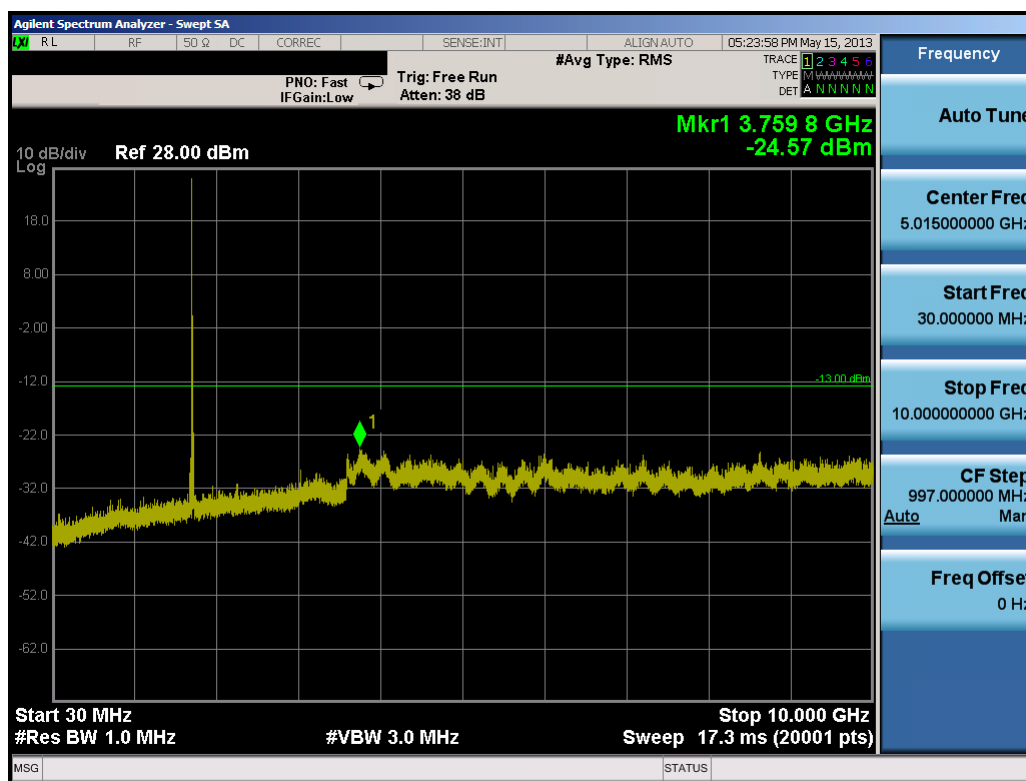


Plot 9-47. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 83 of 118

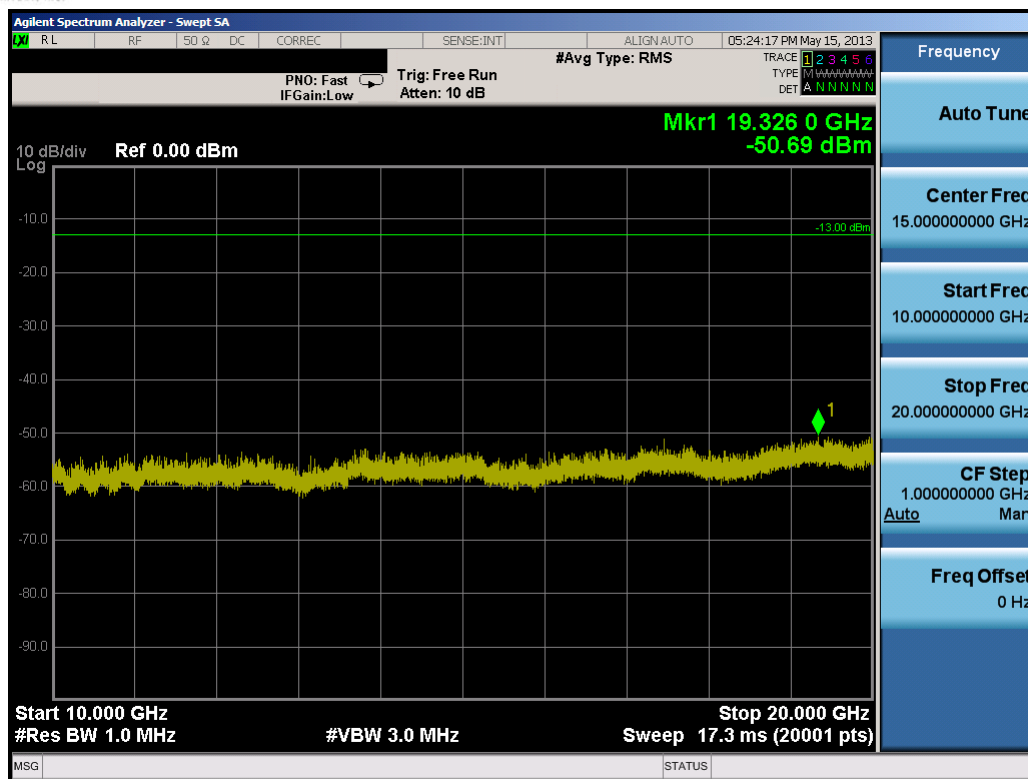


Plot 9-48. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

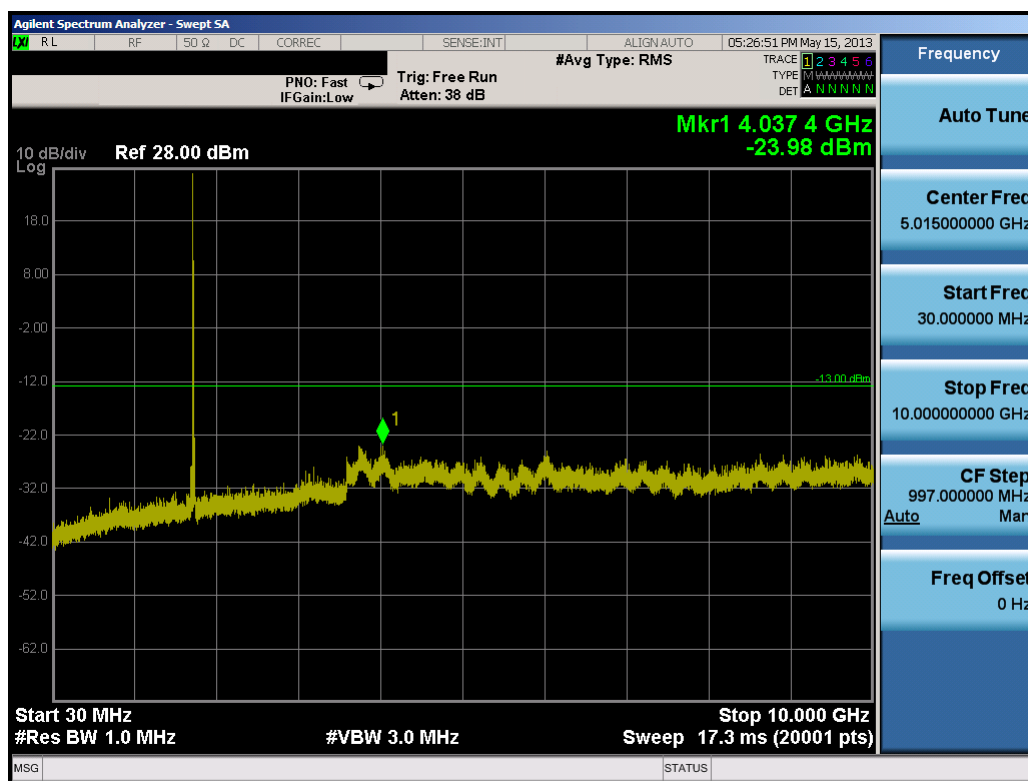


Plot 9-49. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 84 of 118

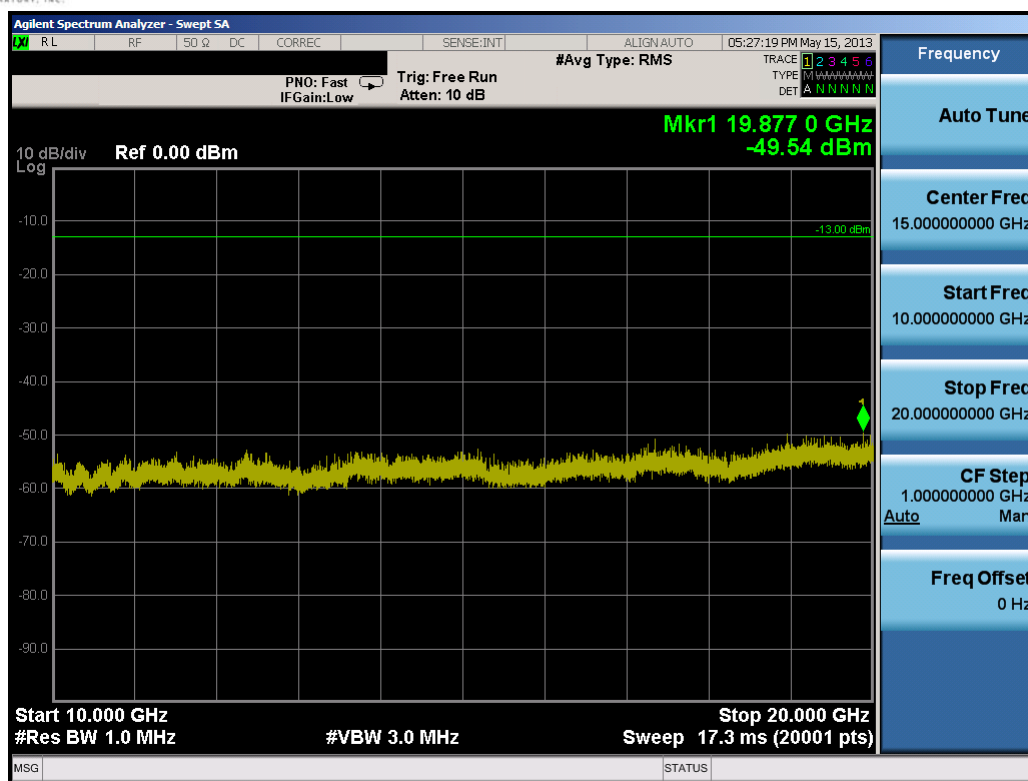


Plot 9-50. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 9-51. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 85 of 118

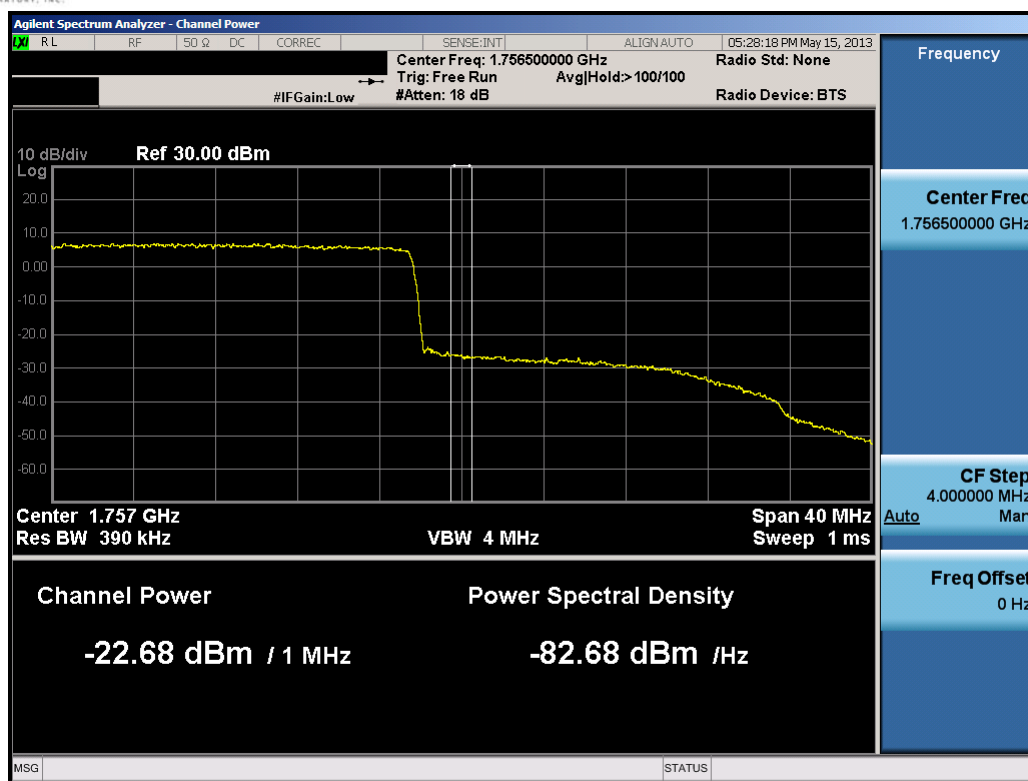


Plot 9-52. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

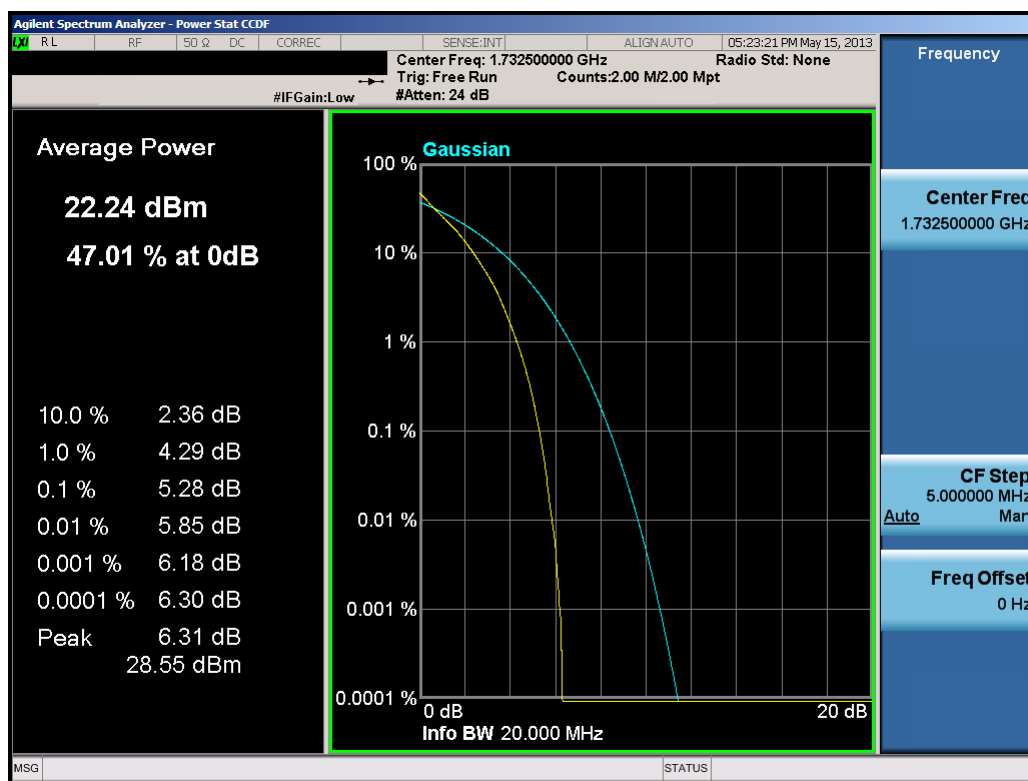


Plot 9-53. Upper Band Edge Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 86 of 118

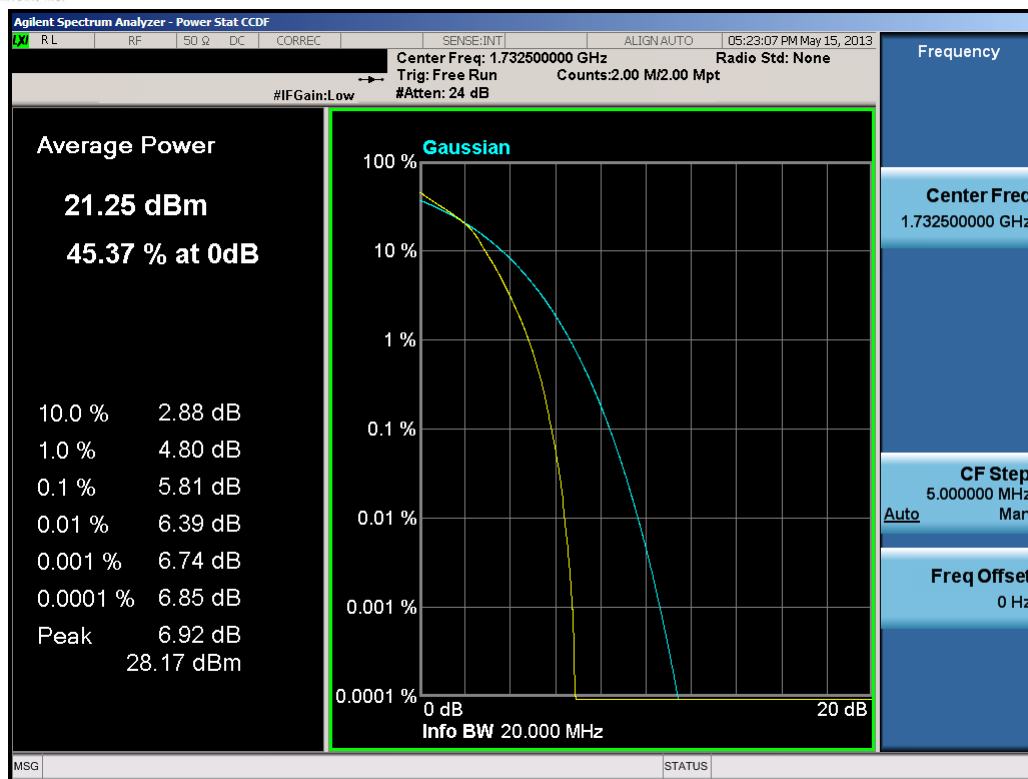


Plot 9-54. Upper Extended Band Edge Plot (20.0MHz QPSK – RB Size 100)



Plot 9-55. PAR Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 87 of 118

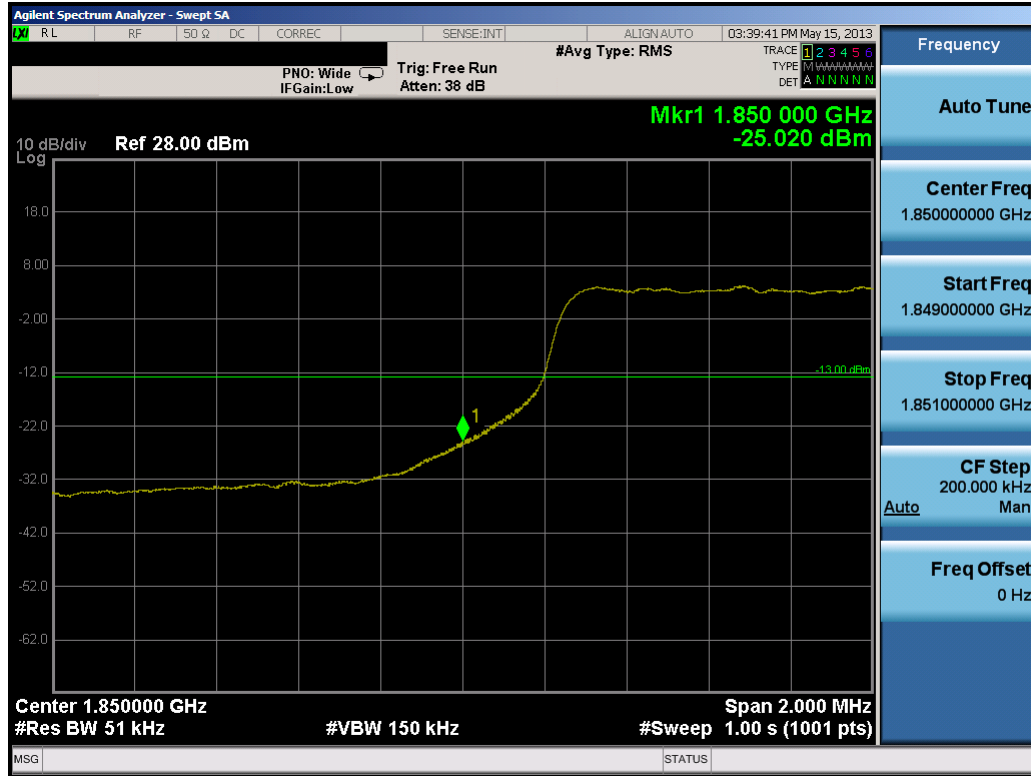


Plot 9-56. PAR Plot (20.0MHz 16-QAM – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 88 of 118

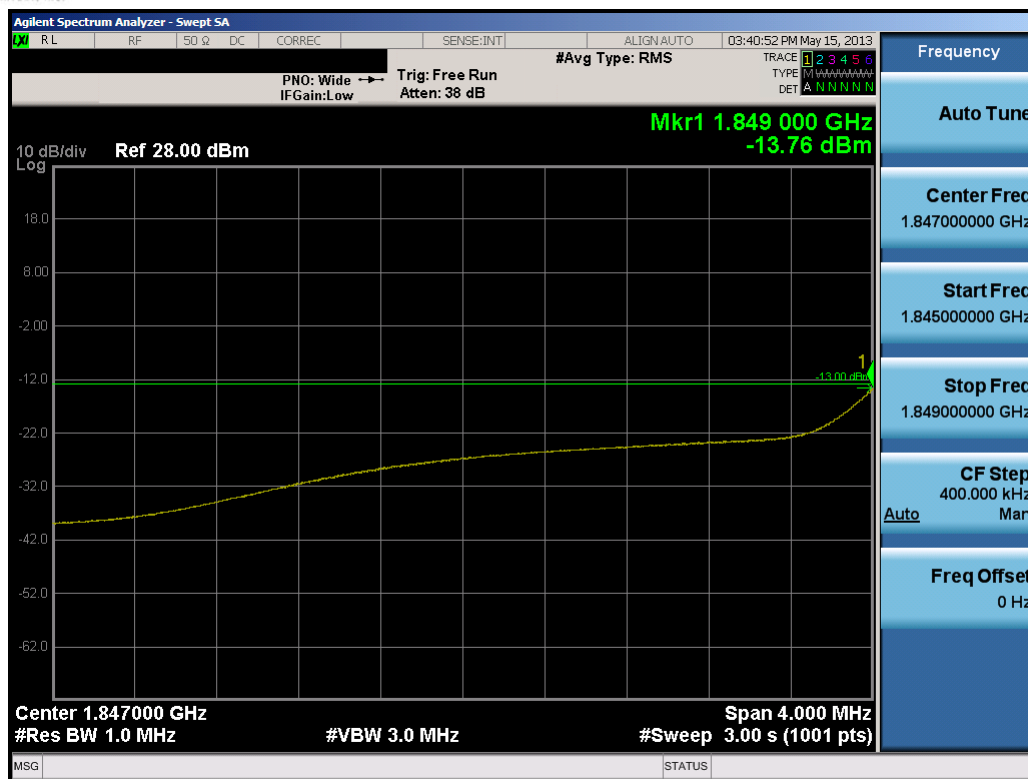
10.0 BAND 2 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.

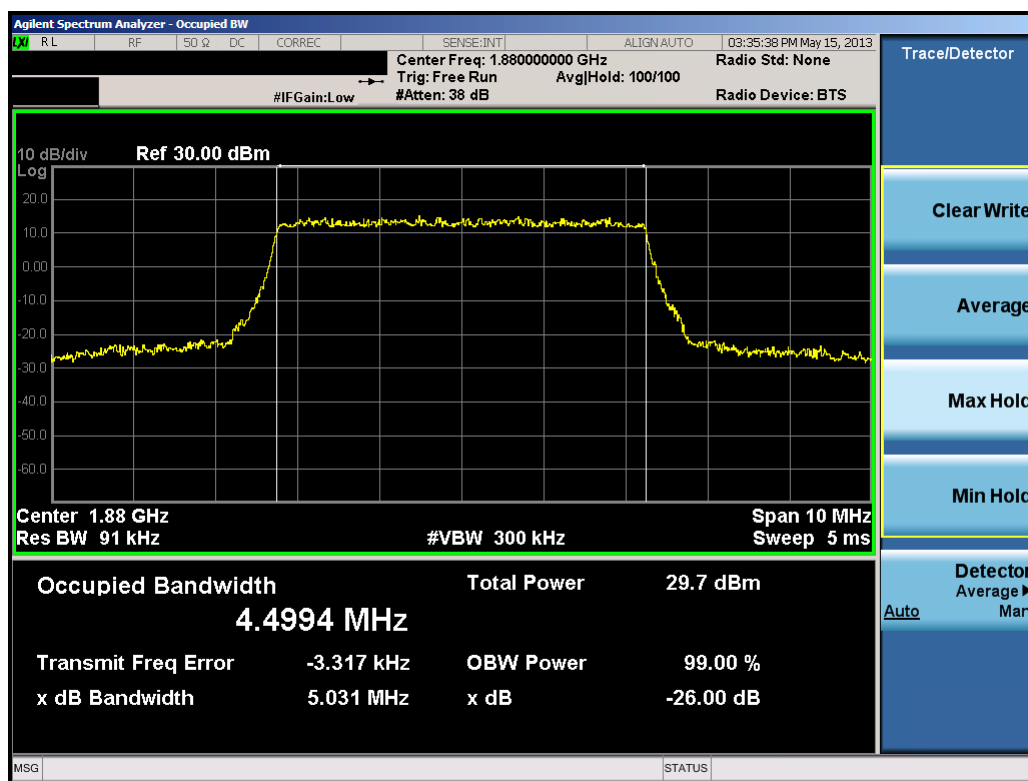


Plot 10-1. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 89 of 118

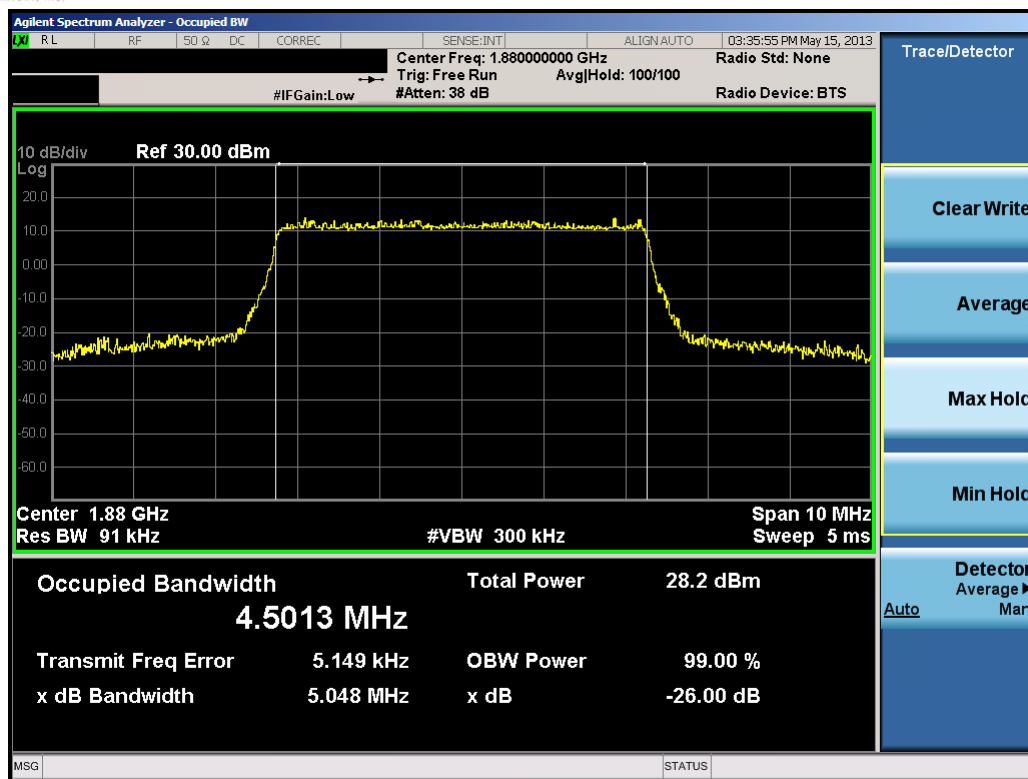


Plot 10-2. Lower Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

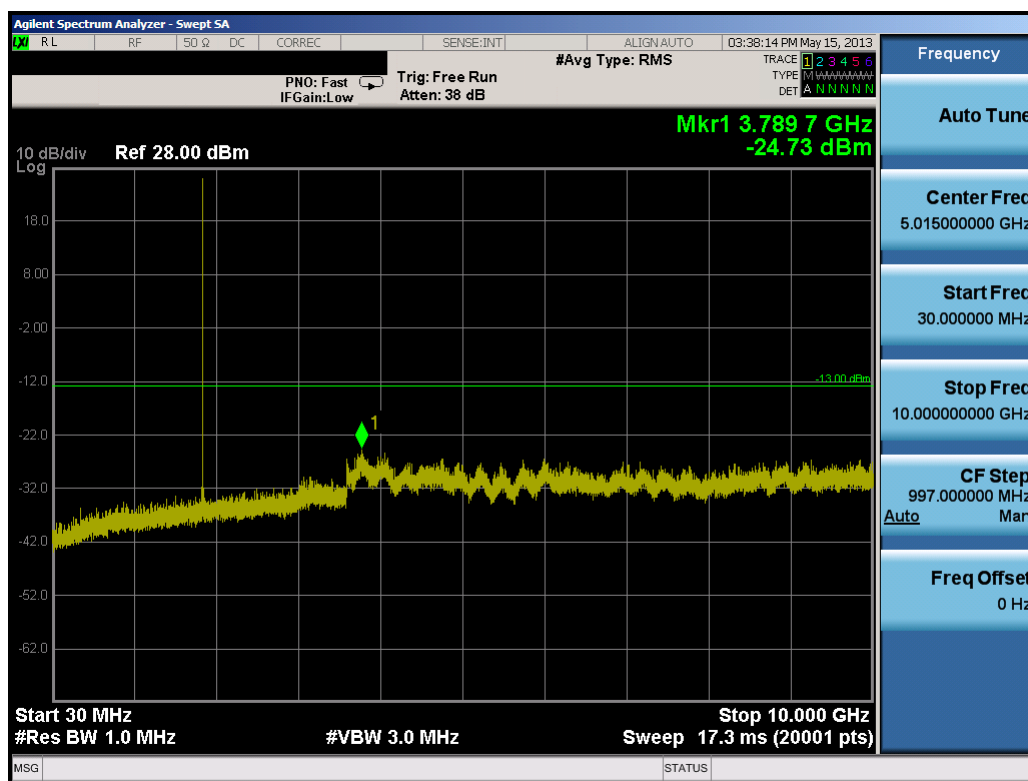


Plot 10-3. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 90 of 118

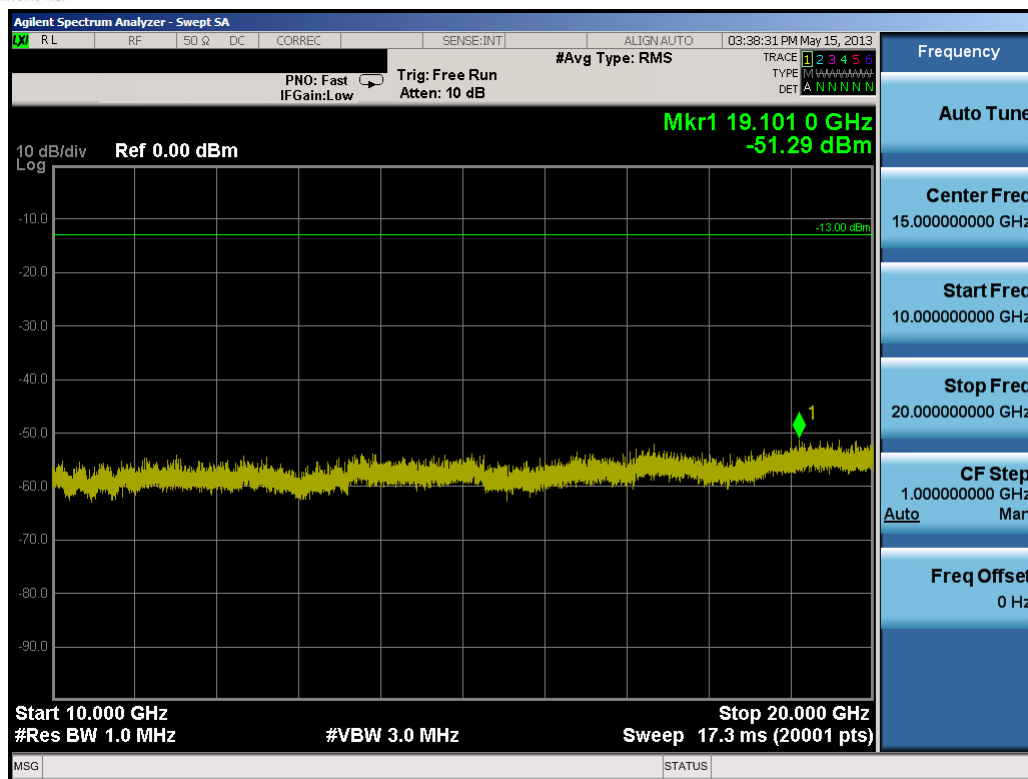


Plot 10-4. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)

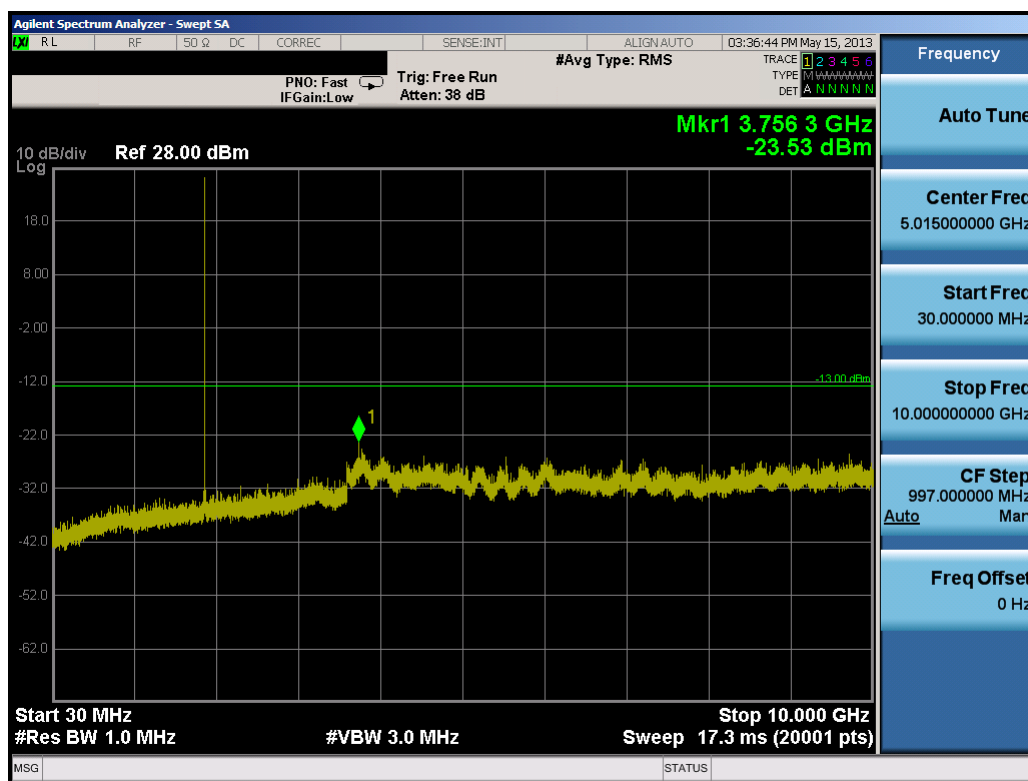


Plot 10-5. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 91 of 118

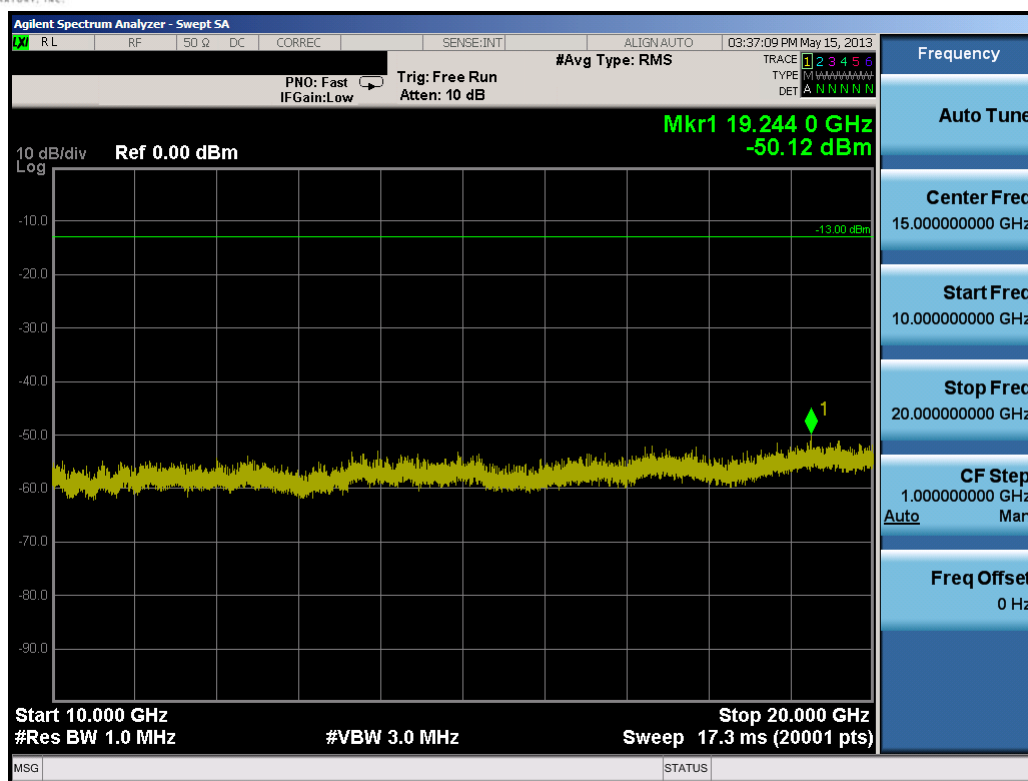


Plot 10-6. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

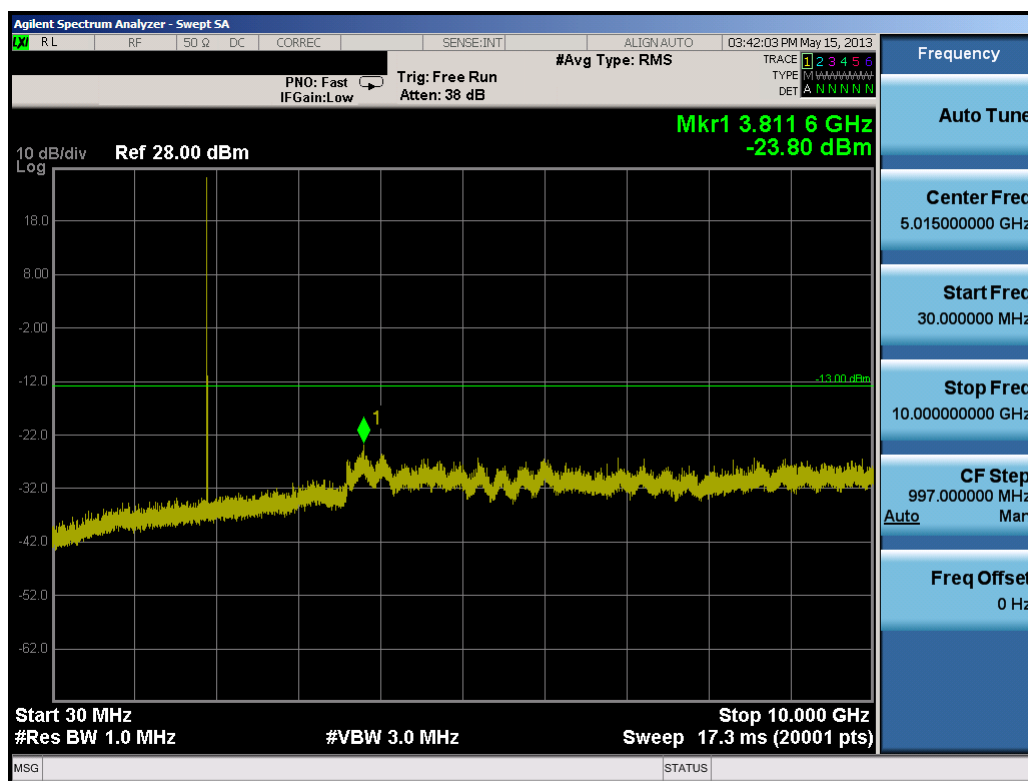


Plot 10-7. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 92 of 118

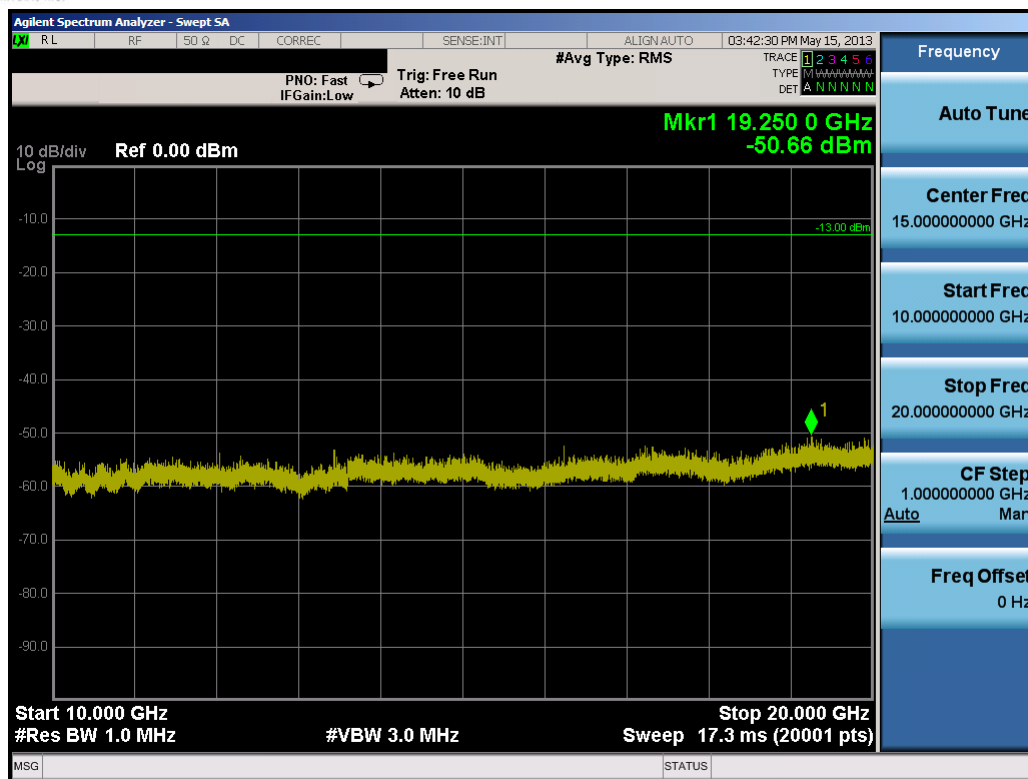


Plot 10-8. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 10-9. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 93 of 118

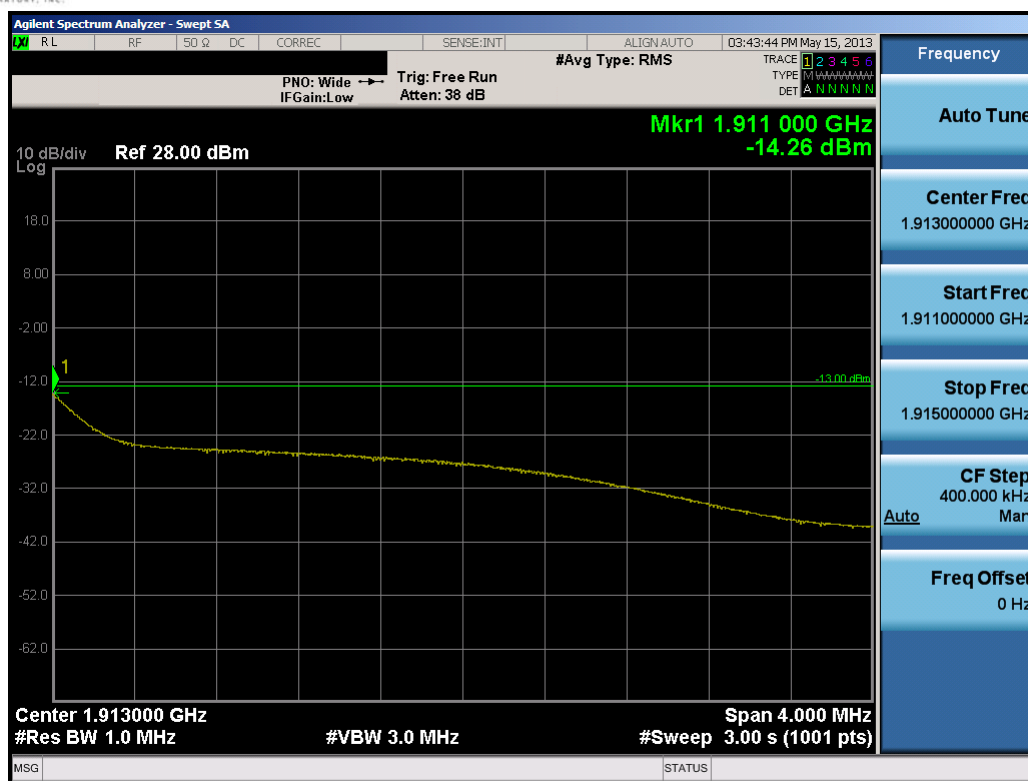


Plot 10-10. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

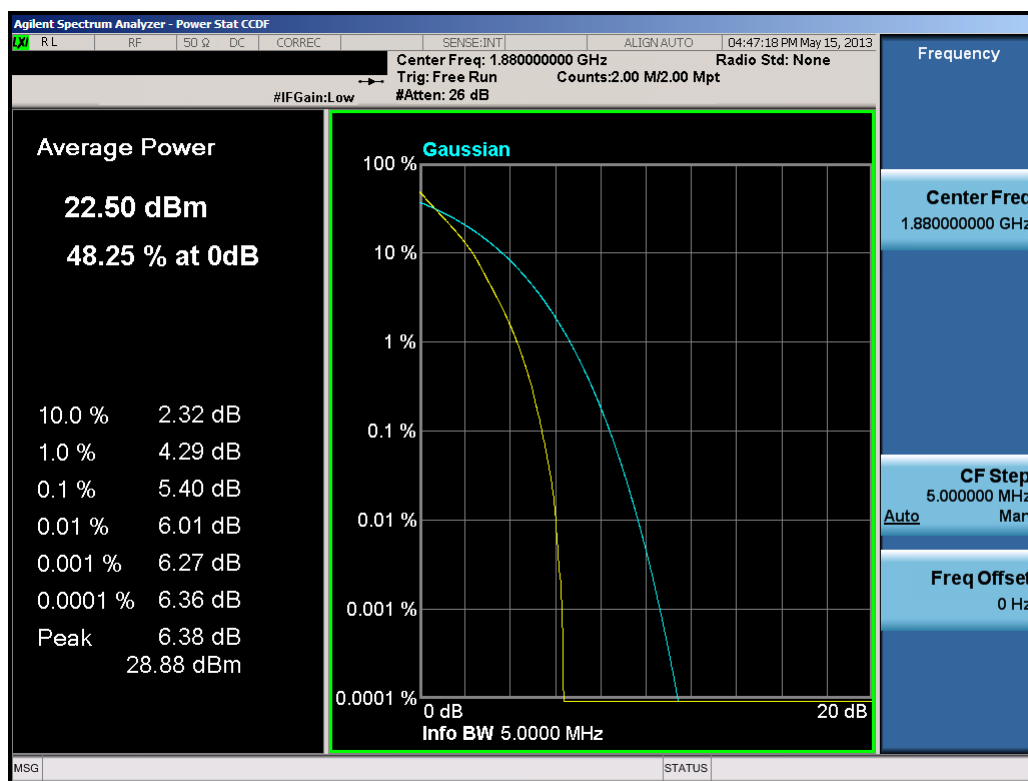


Plot 10-11. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 94 of 118

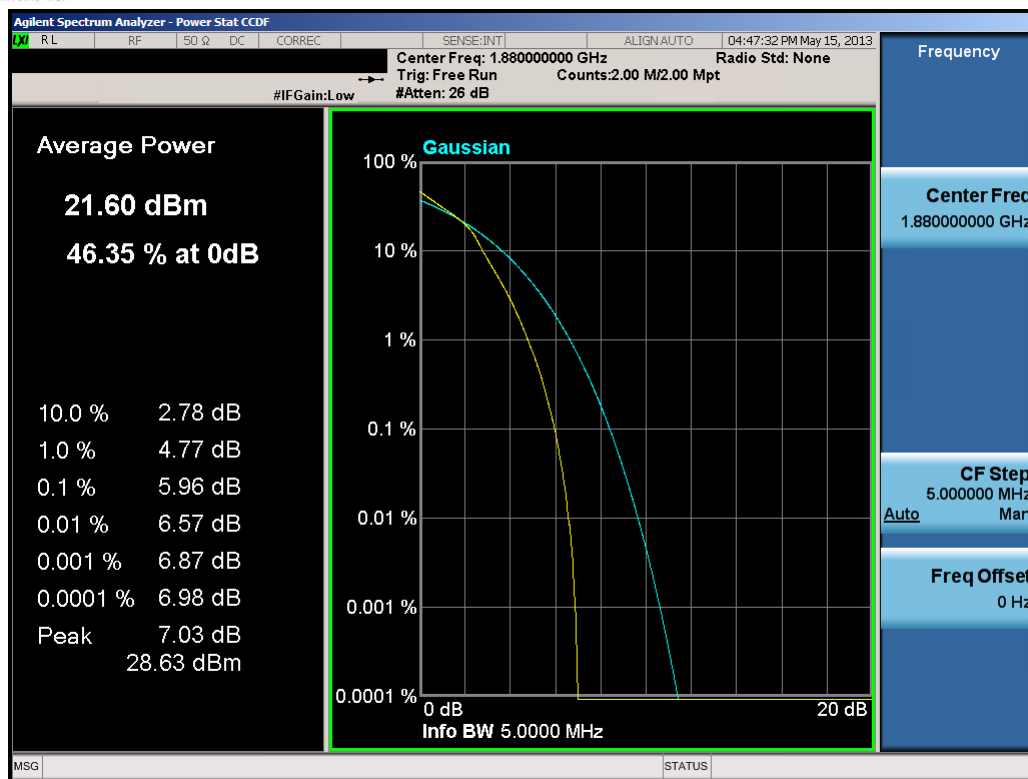


Plot 10-12. Upper Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

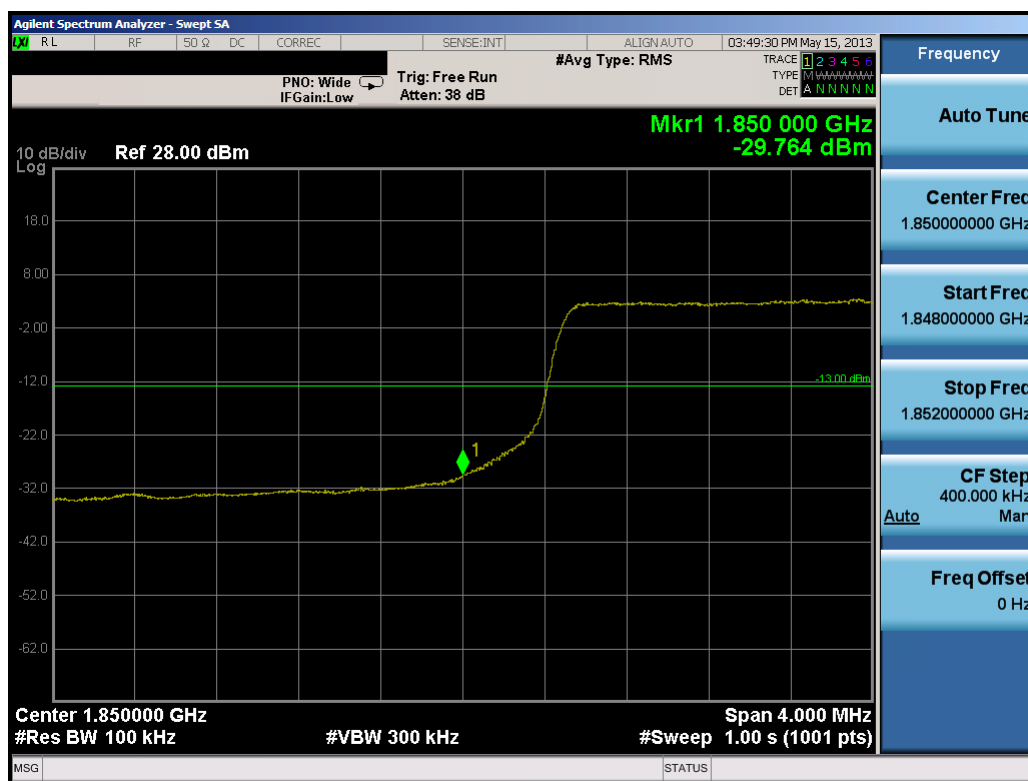


Plot 10-13. PAR Plot (5.0MHz QPSK – RB Size 25)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 95 of 118

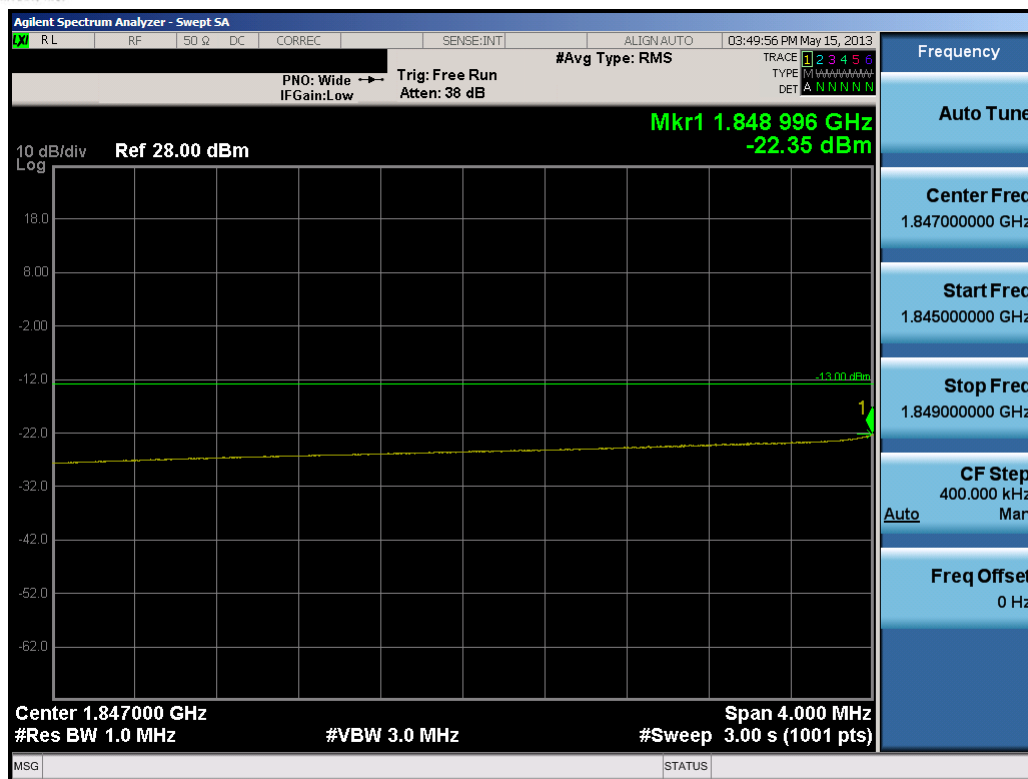


Plot 10-14. PAR Plot (5.0MHz 16-QAM – RB Size 25)

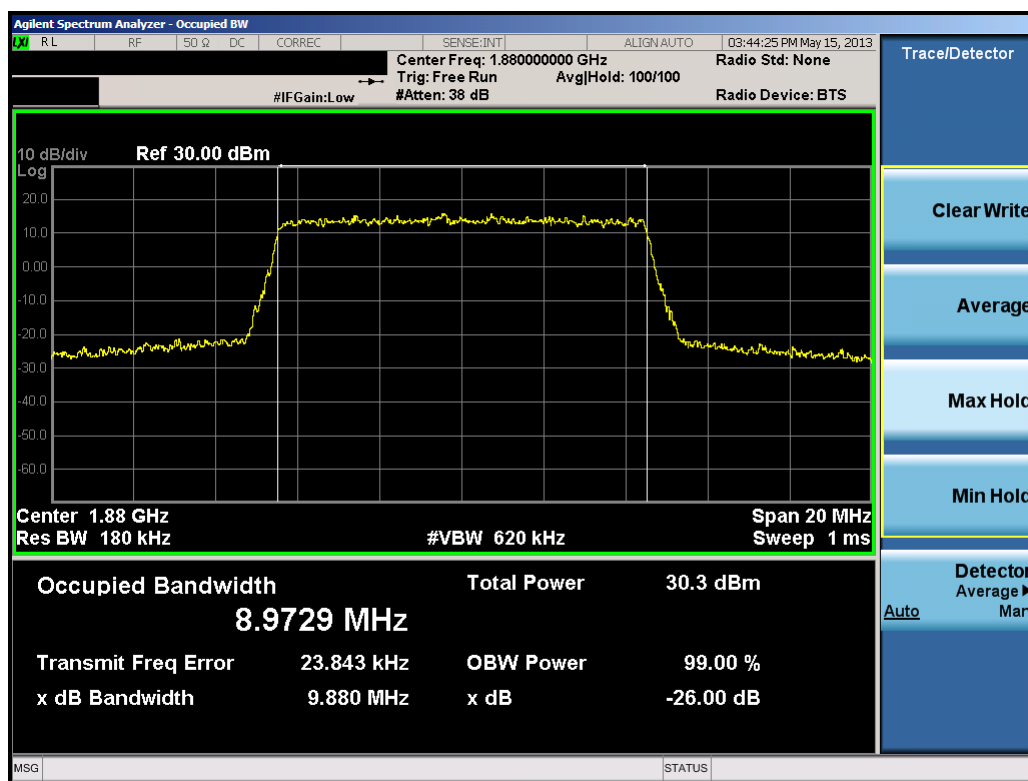


Plot 10-15. Lower Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 96 of 118

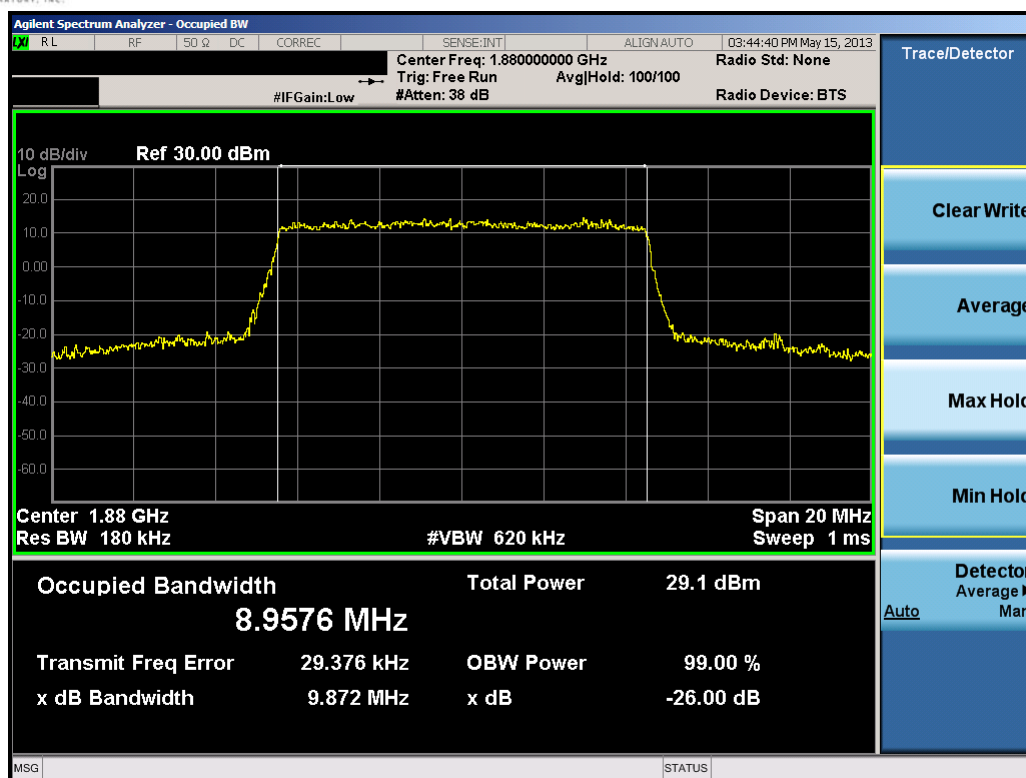


Plot 10-16. Lower Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

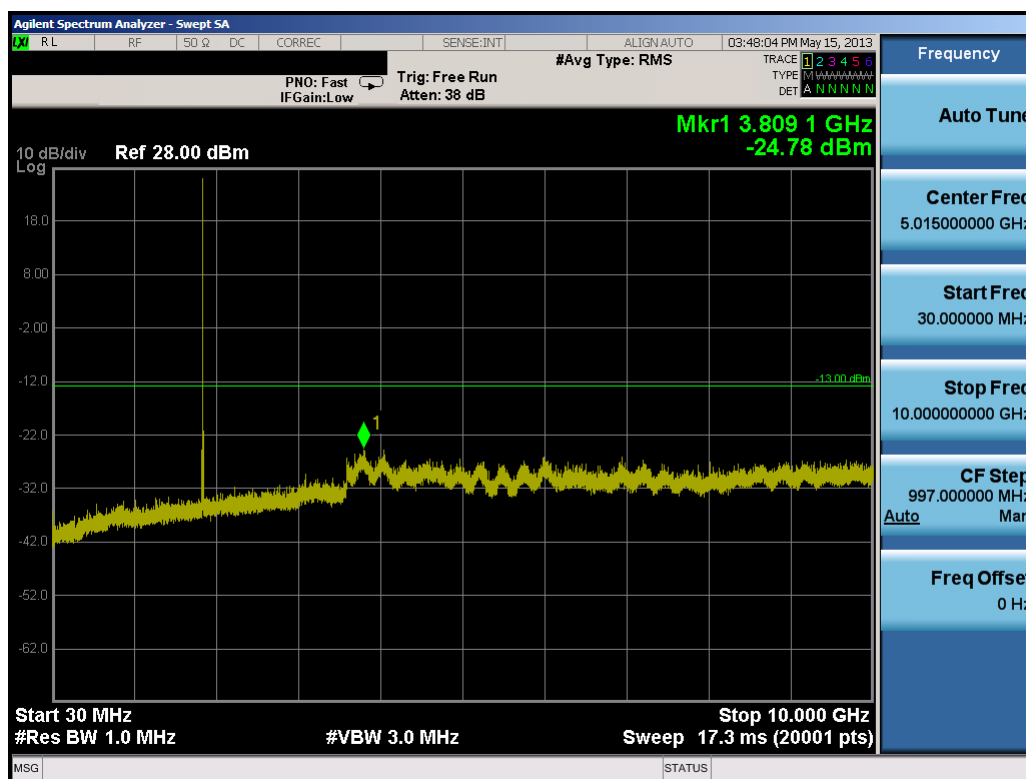


Plot 10-17. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)



FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 97 of 118

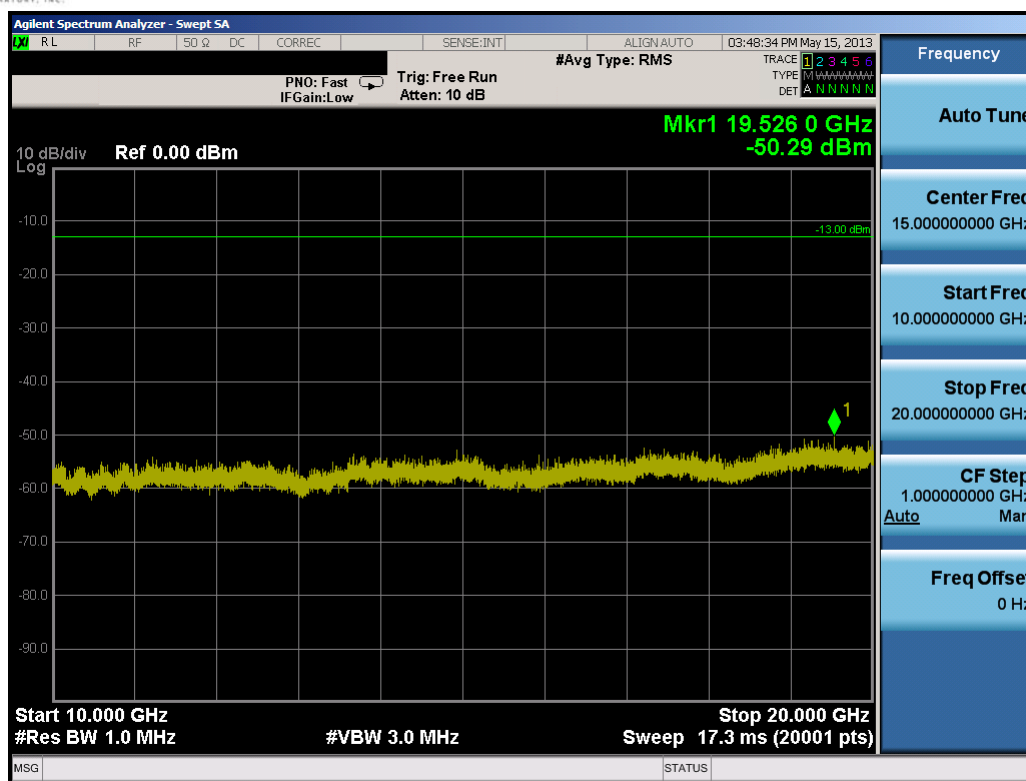


Plot 10-18. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)

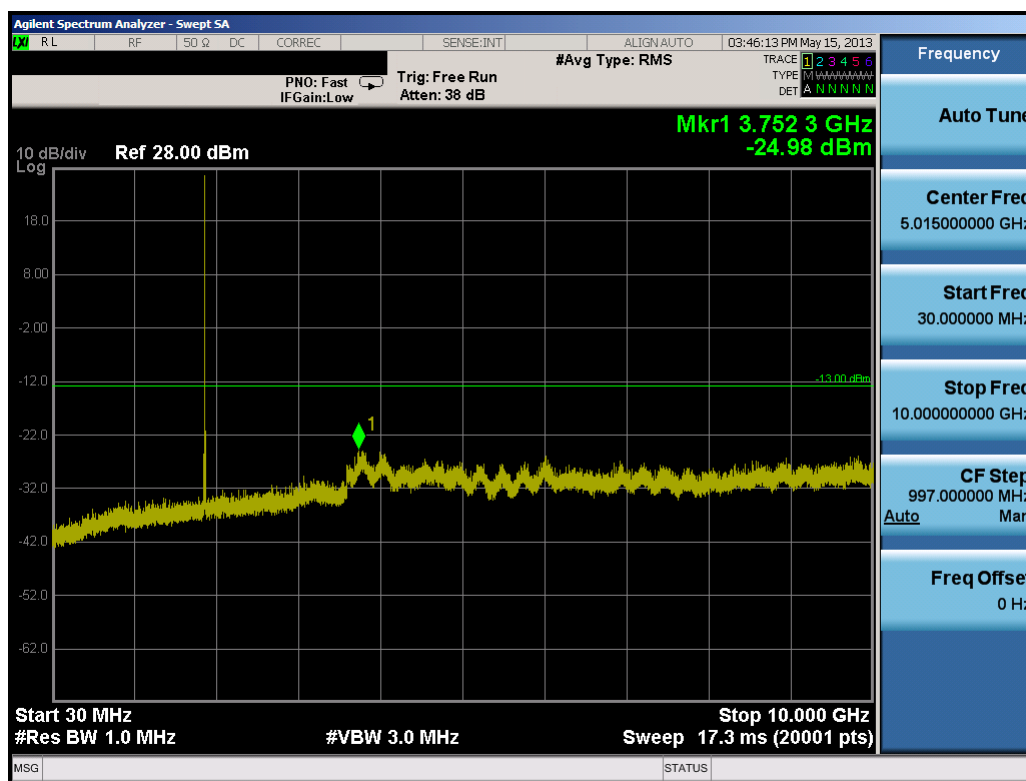


Plot 10-19. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

FCC ID: A3LSGHI527	 FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset	Page 98 of 118

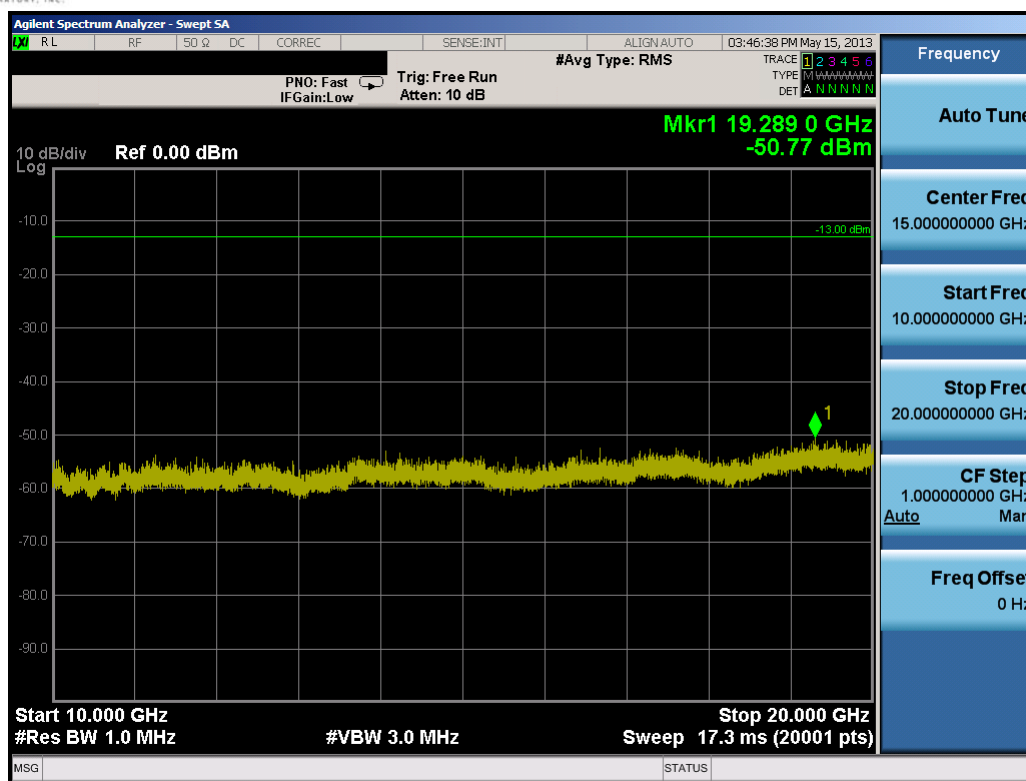


Plot 10-20. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

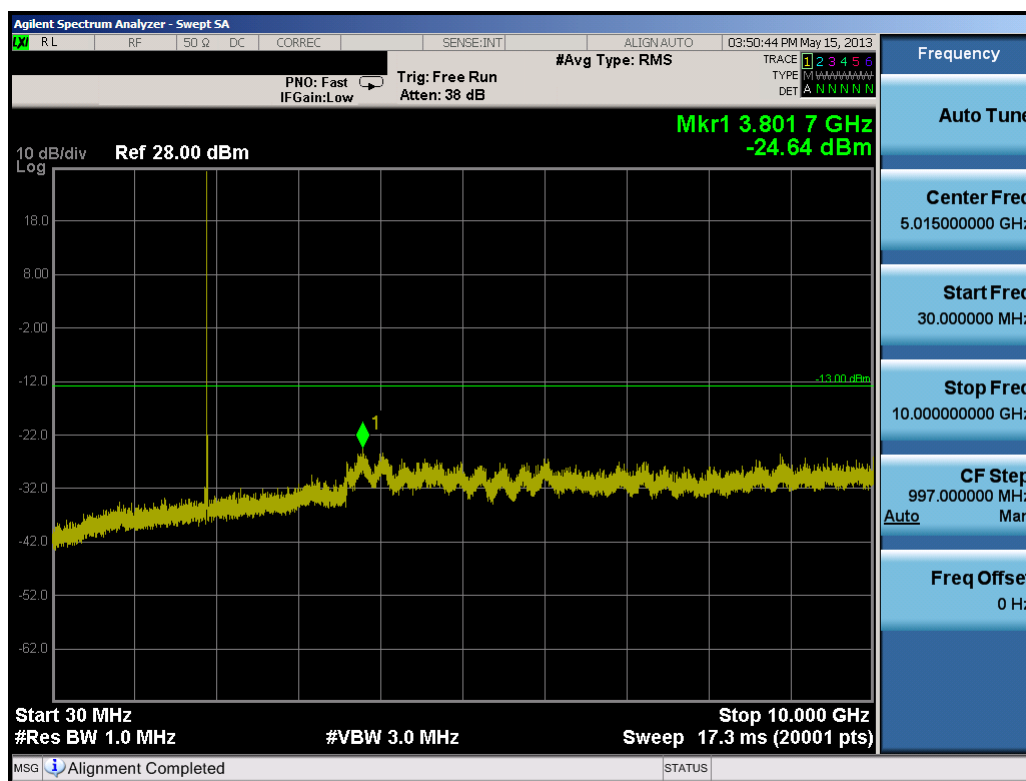


Plot 10-21. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 99 of 118

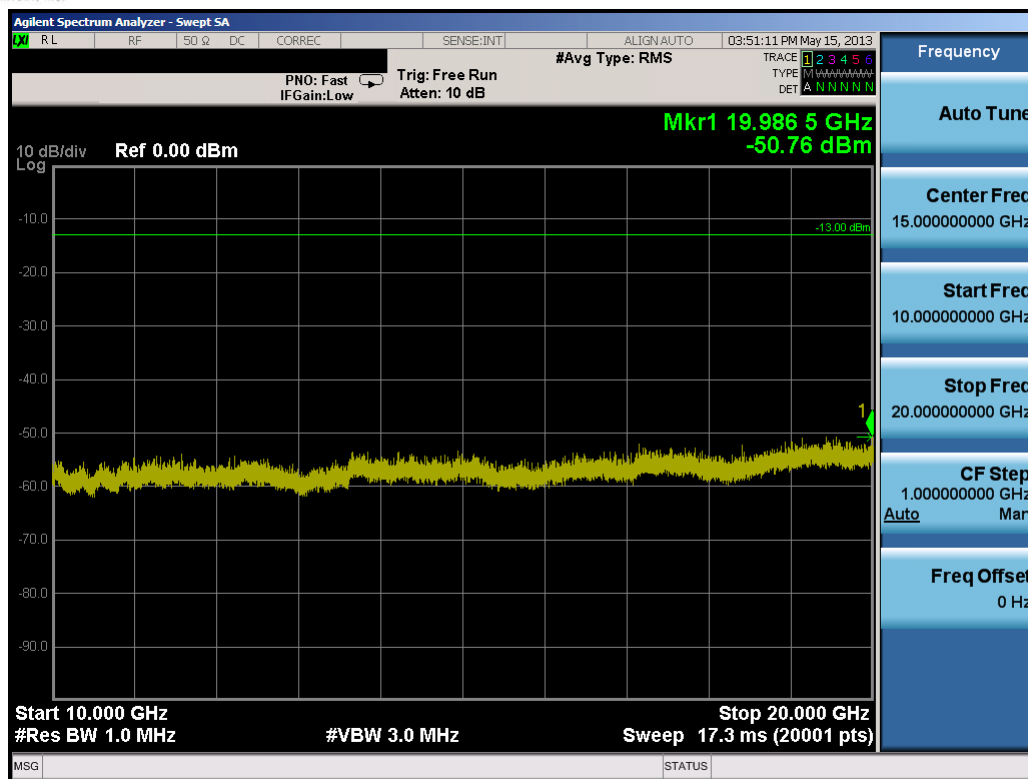


Plot 10-22. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 10-23. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 100 of 118

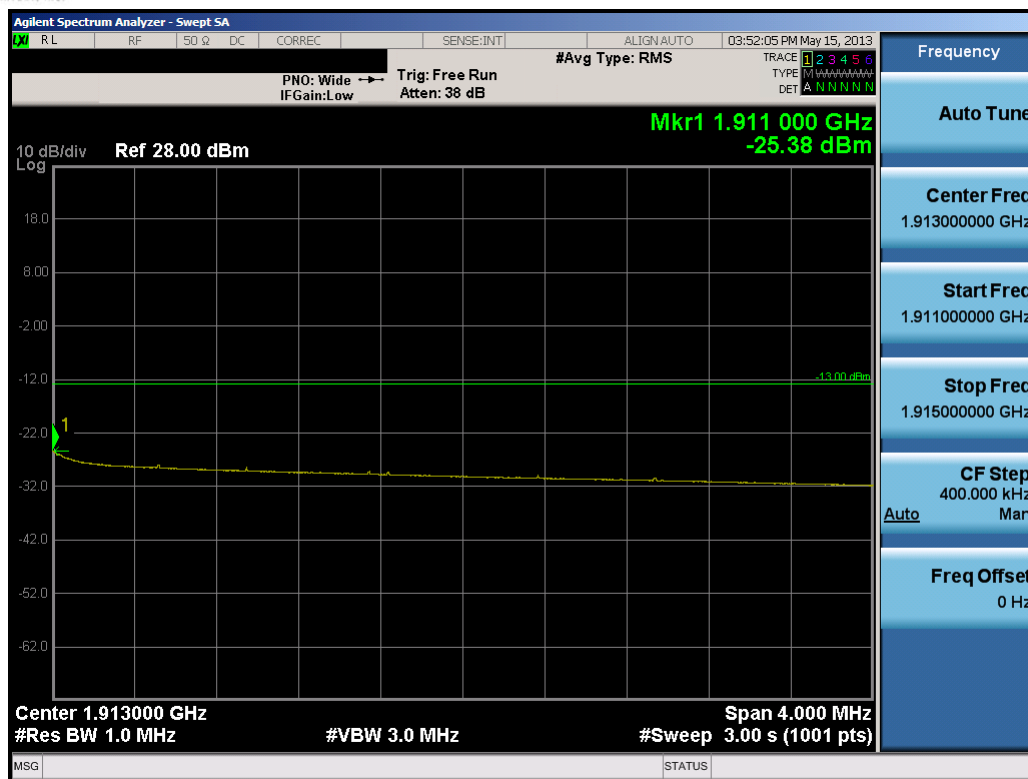


Plot 10-24. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

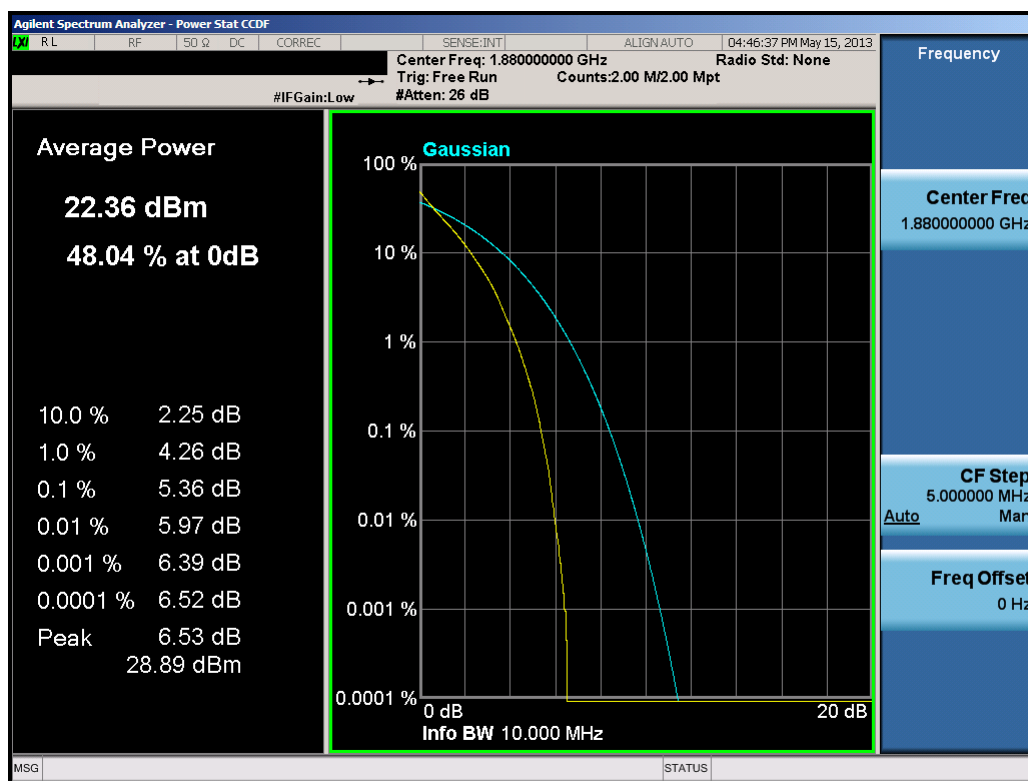


Plot 10-25. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 101 of 118

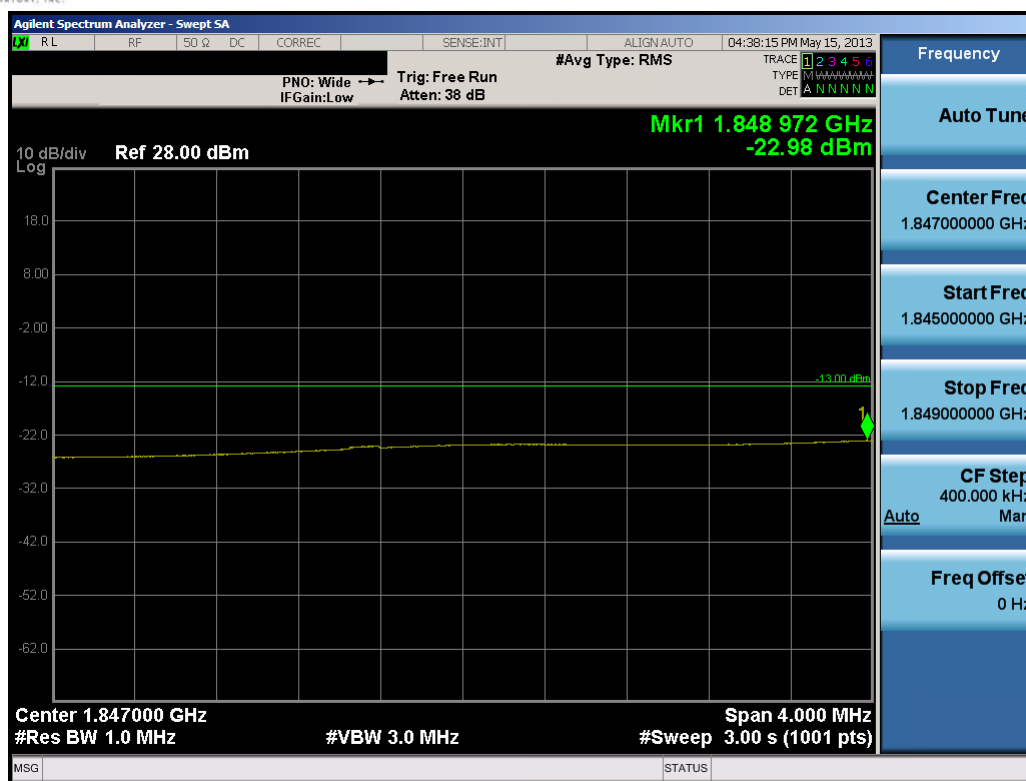


Plot 10-26. Upper Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)

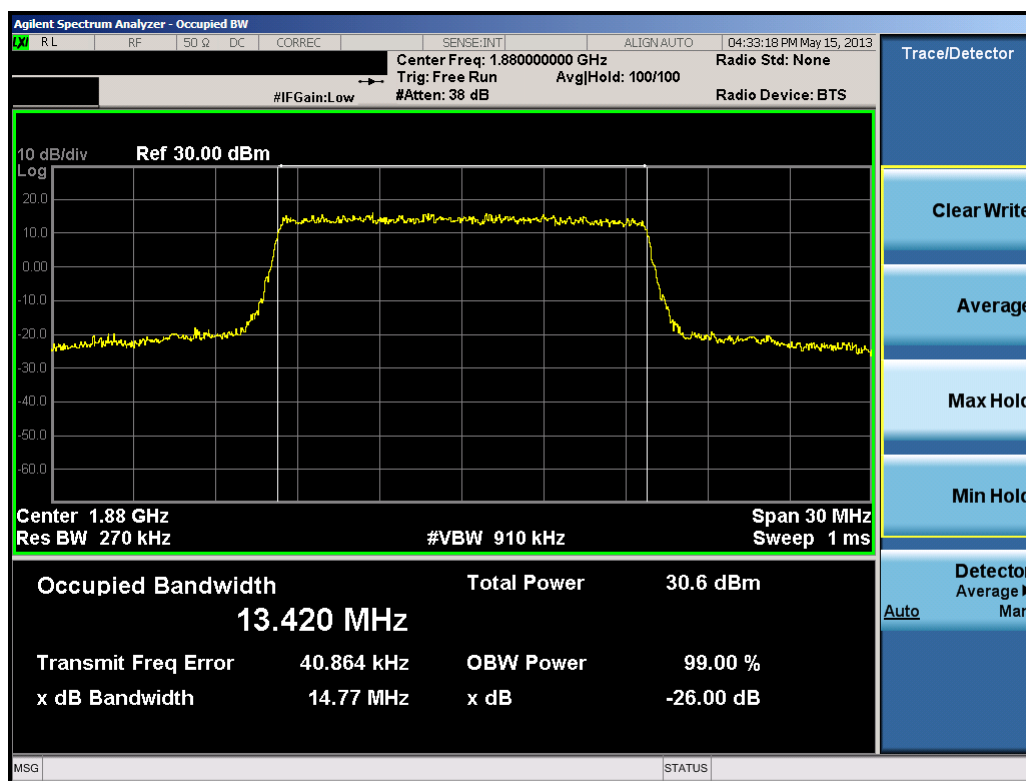


Plot 10-27. PAR Plot (10.0MHz QPSK – RB Size 50)



FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 102 of 118

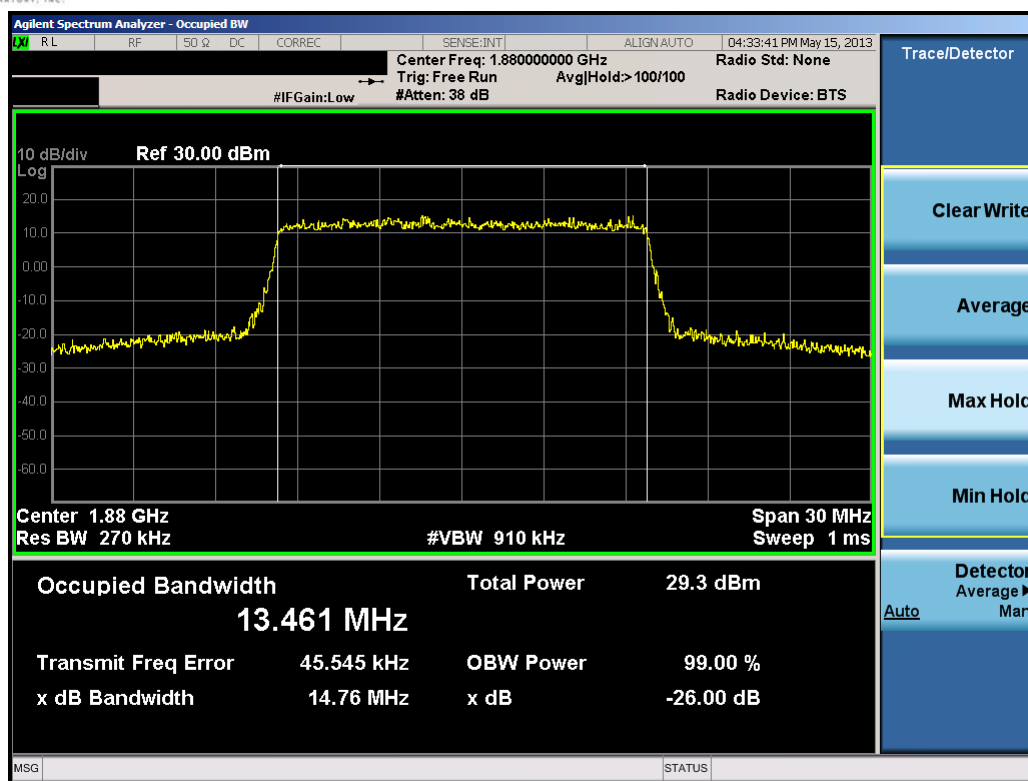


Plot 10-30. Lower Extended Band Edge Plot (15.0MHz QPSK – RB Size 75)

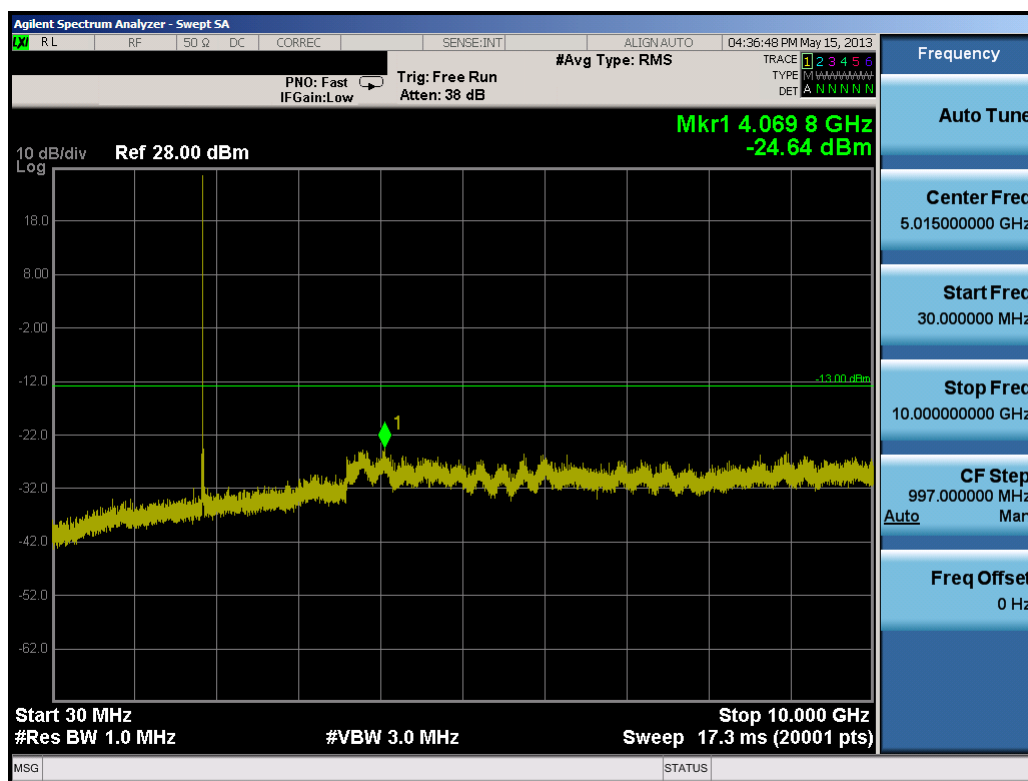


Plot 10-31. Occupied Bandwidth Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	 FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset	Page 104 of 118

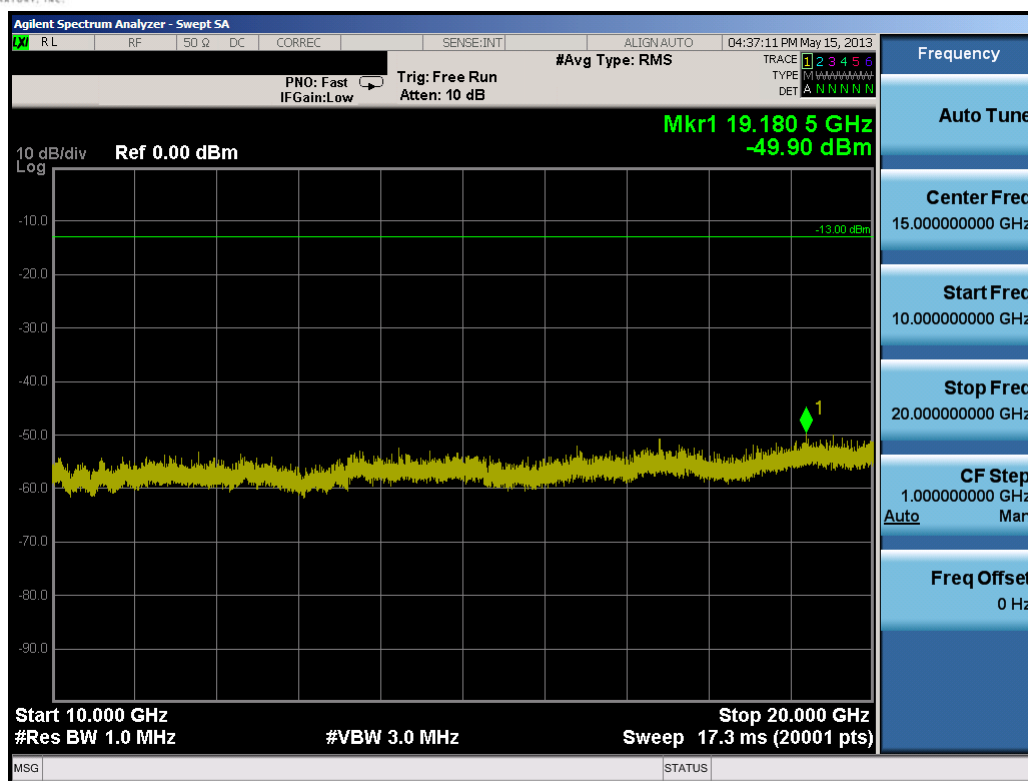


Plot 10-32. Occupied Bandwidth Plot (15.0MHz 16-QAM – RB Size 75)

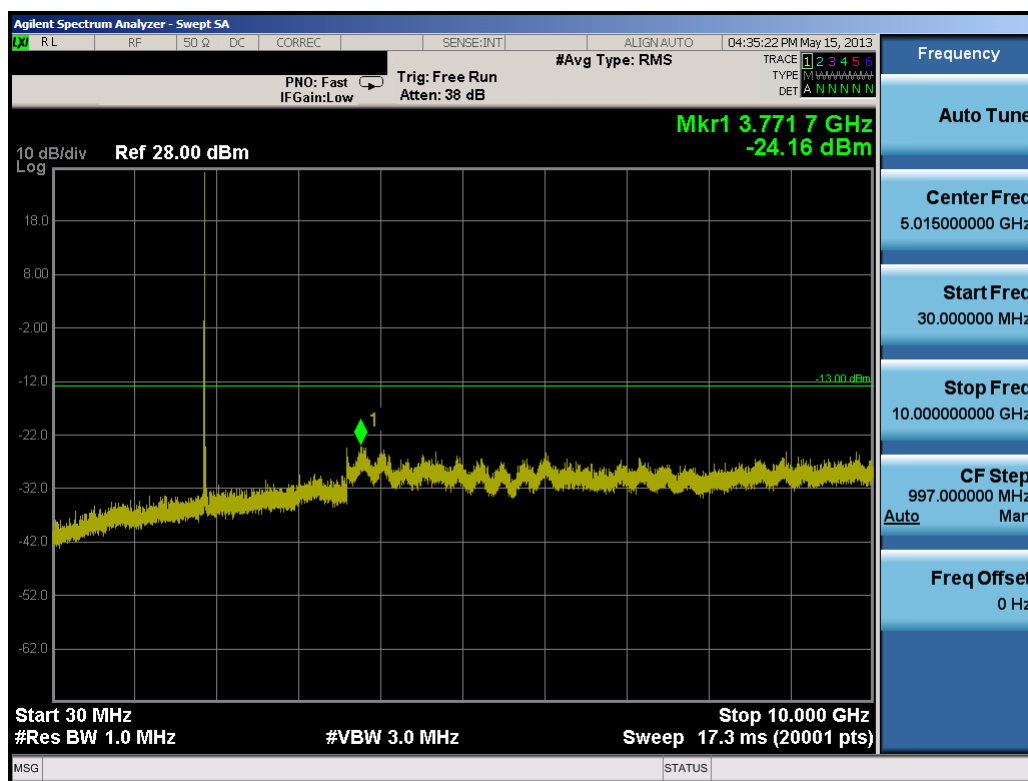


Plot 10-33. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 105 of 118

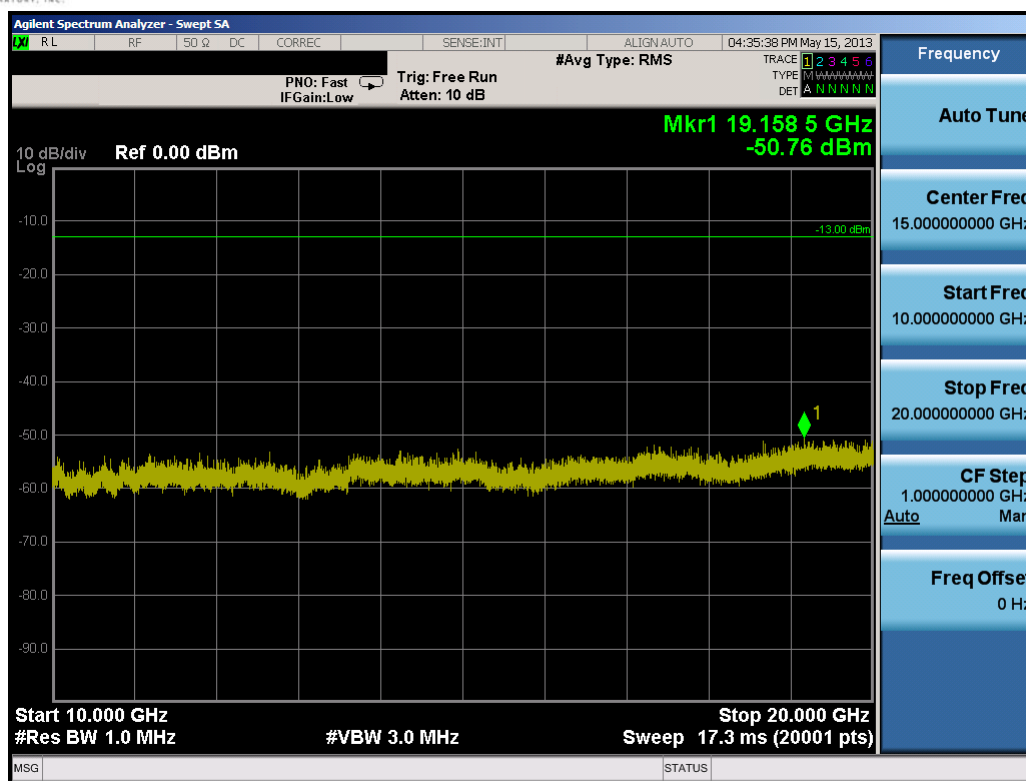


Plot 10-34. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

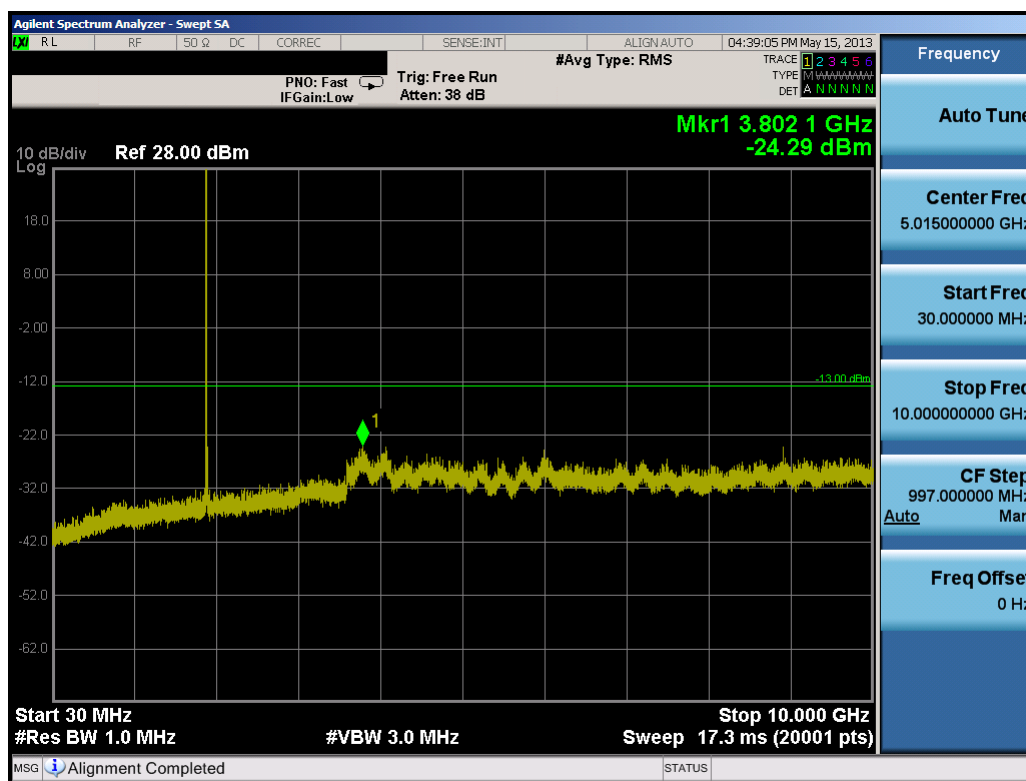


Plot 10-35. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 106 of 118

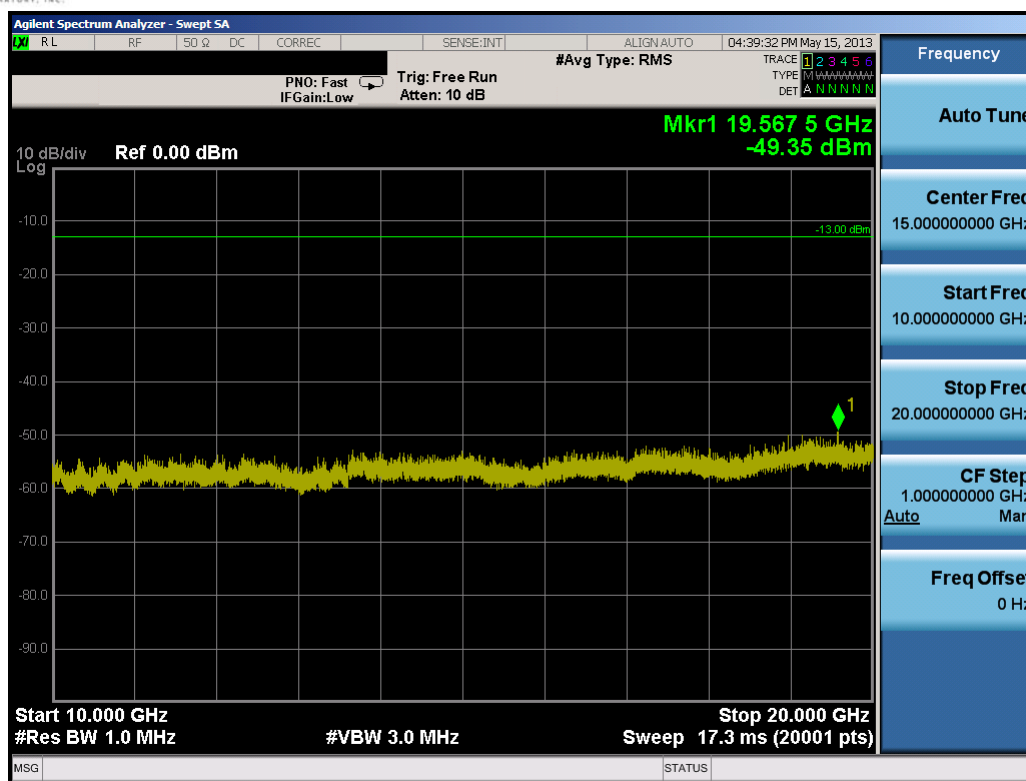


Plot 10-36. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 10-37. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 107 of 118

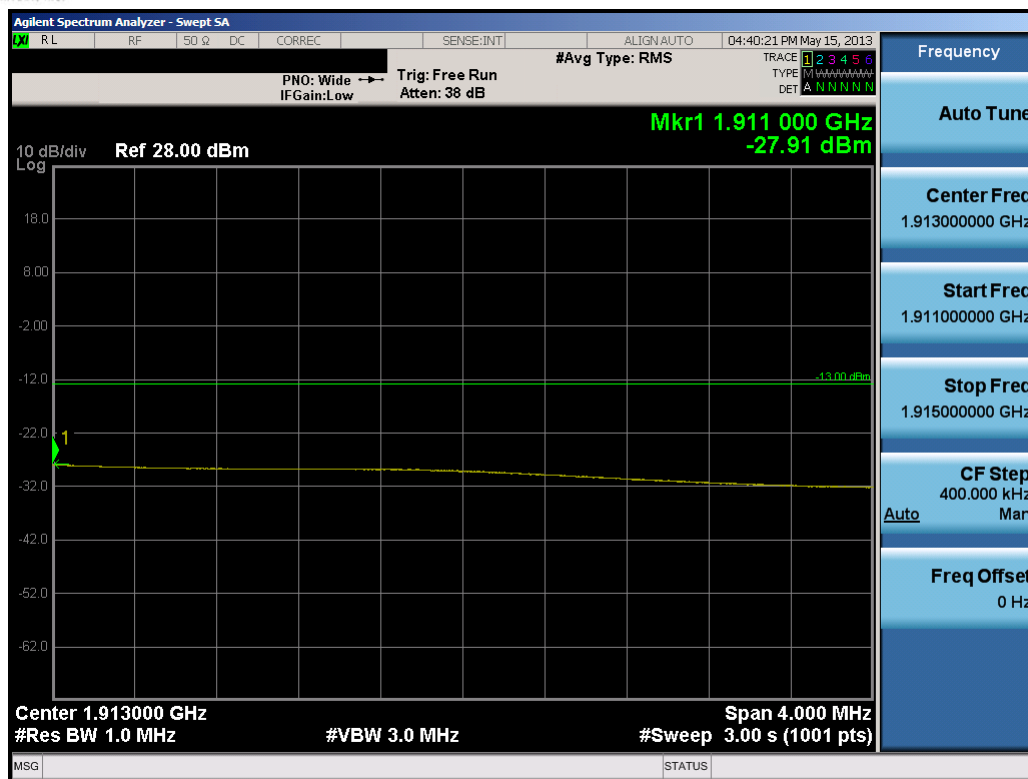


Plot 10-38. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

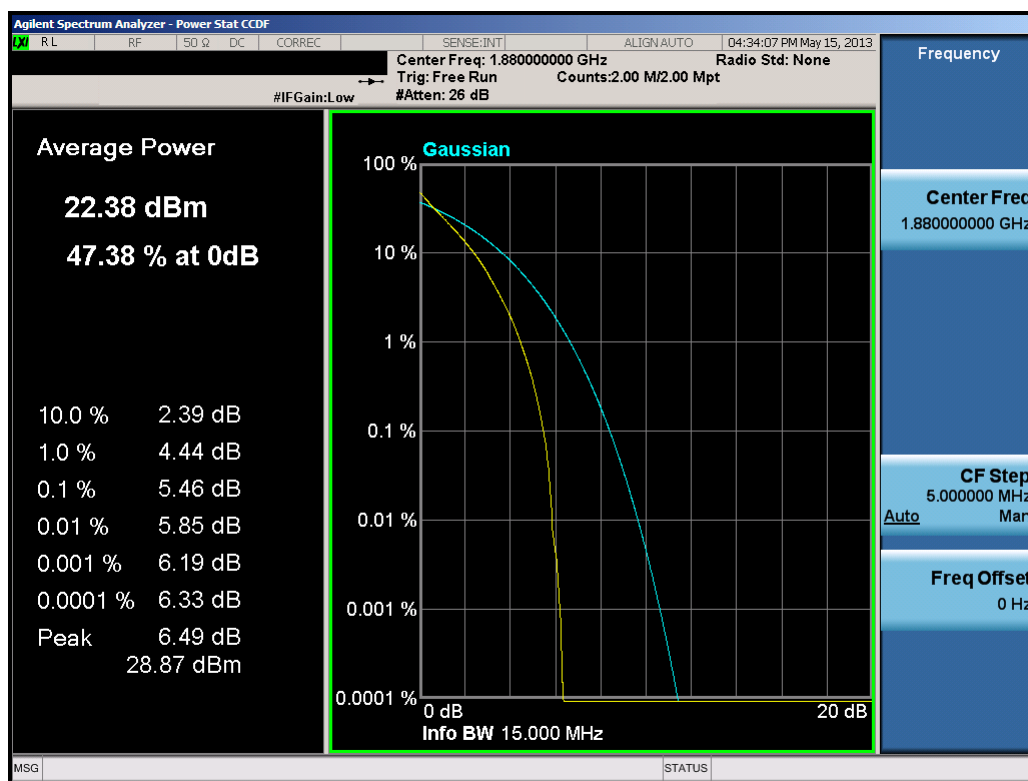


Plot 10-39. Upper Band Edge Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	 FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION) 		Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset	Page 108 of 118

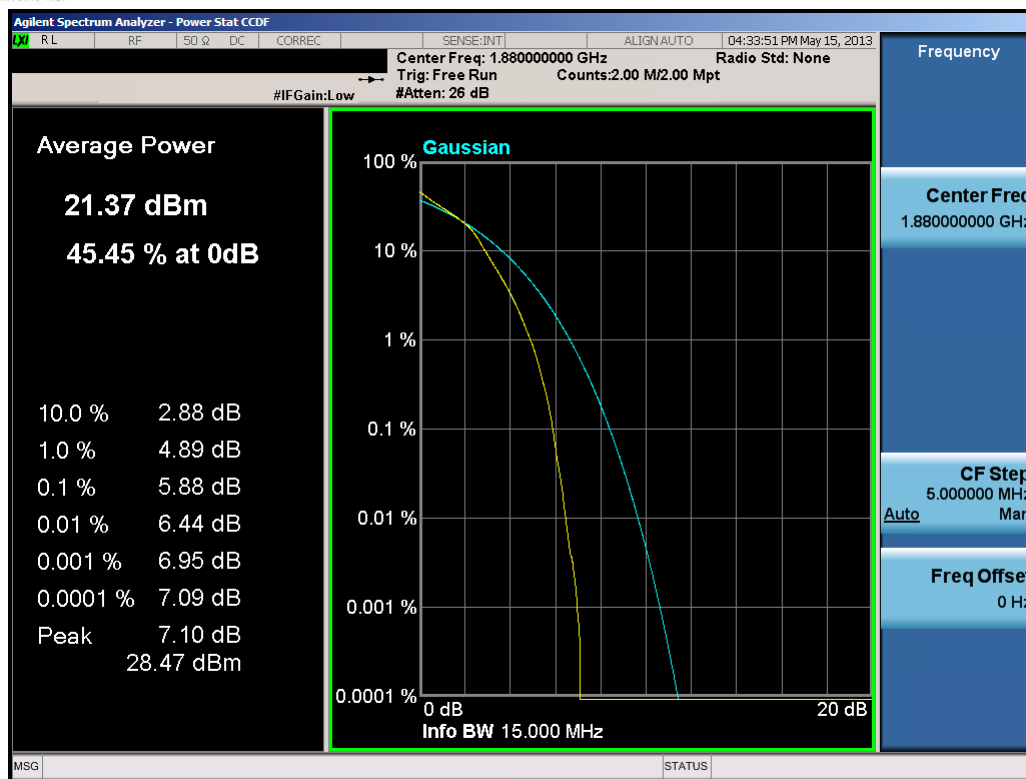


Plot 10-40. Upper Extended Band Edge Plot (15.0MHz QPSK – RB Size 75)



Plot 10-41. PAR Plot (15.0MHz QPSK – RB Size 75)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 109 of 118

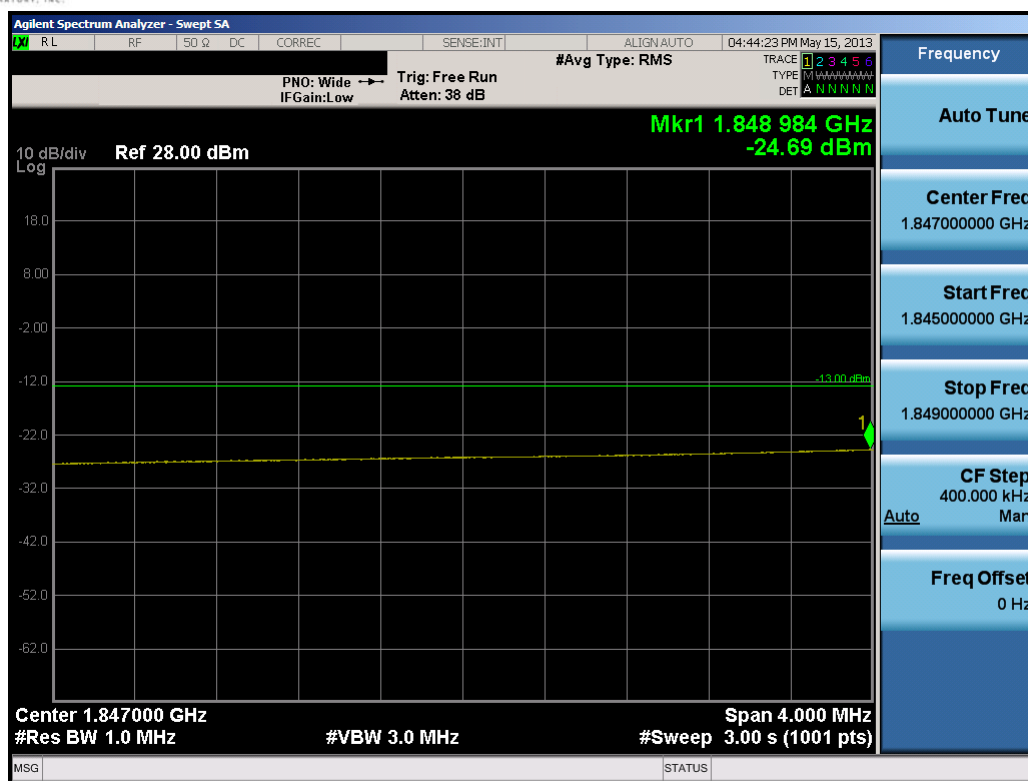


Plot 10-42. PAR Plot (15.0MHz 16-QAM – RB Size 75)

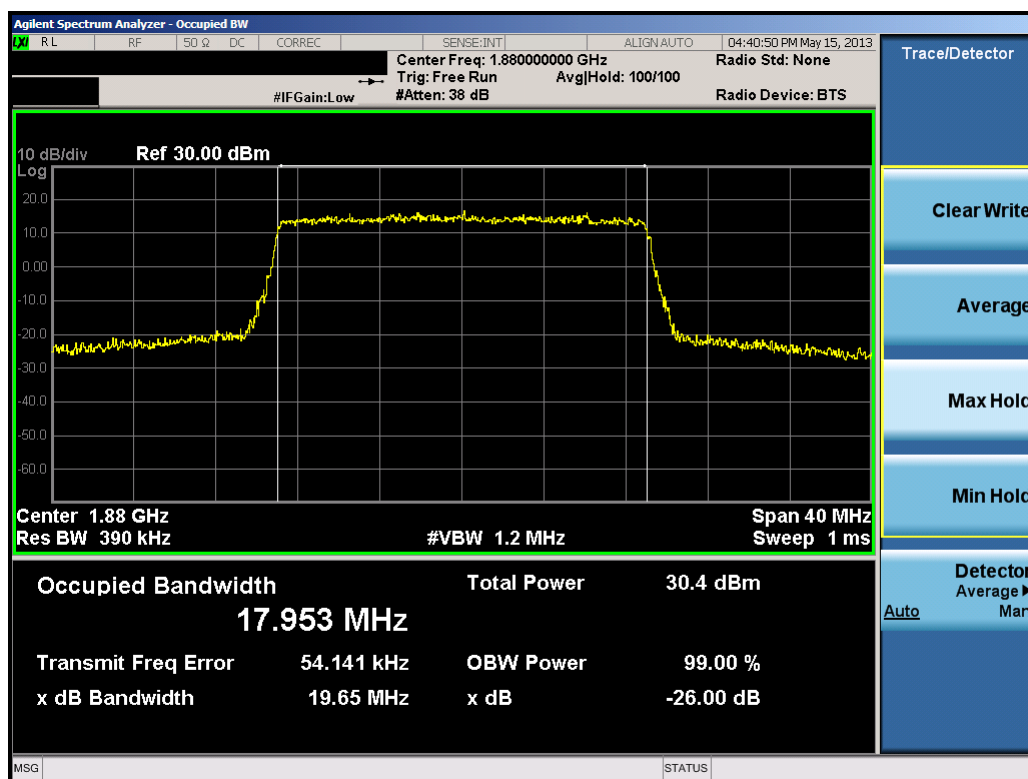


Plot 10-43. Lower Band Edge Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 110 of 118

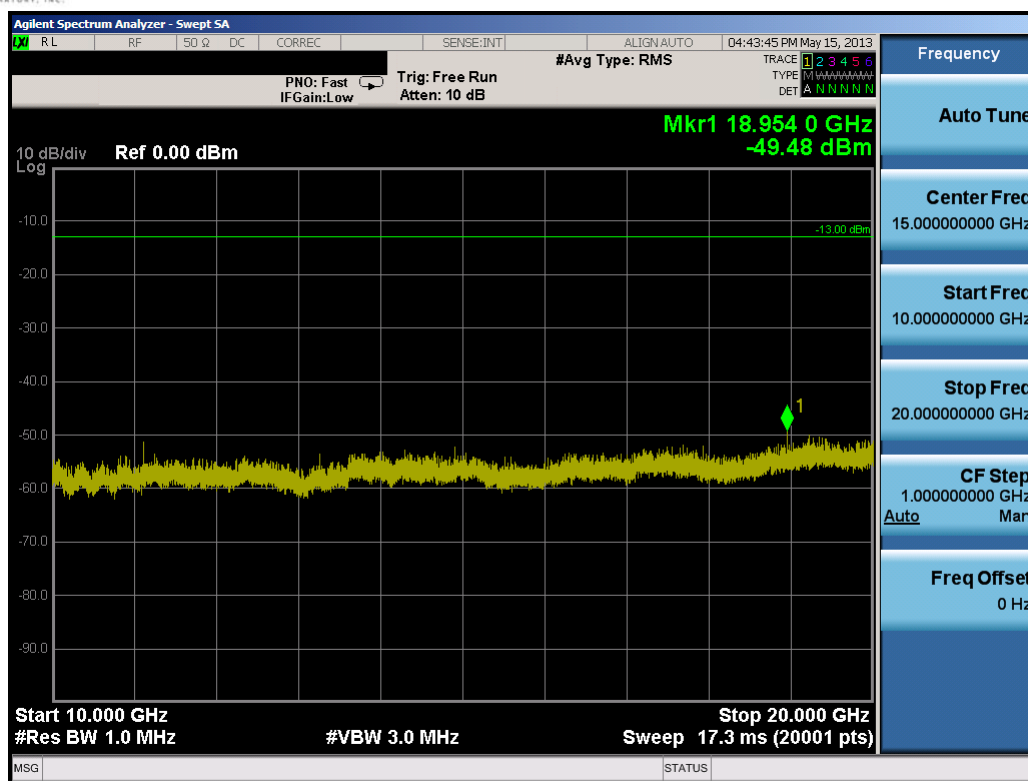


Plot 10-44. Lower Extended Band Edge Plot (20.0MHz QPSK – RB Size 100)

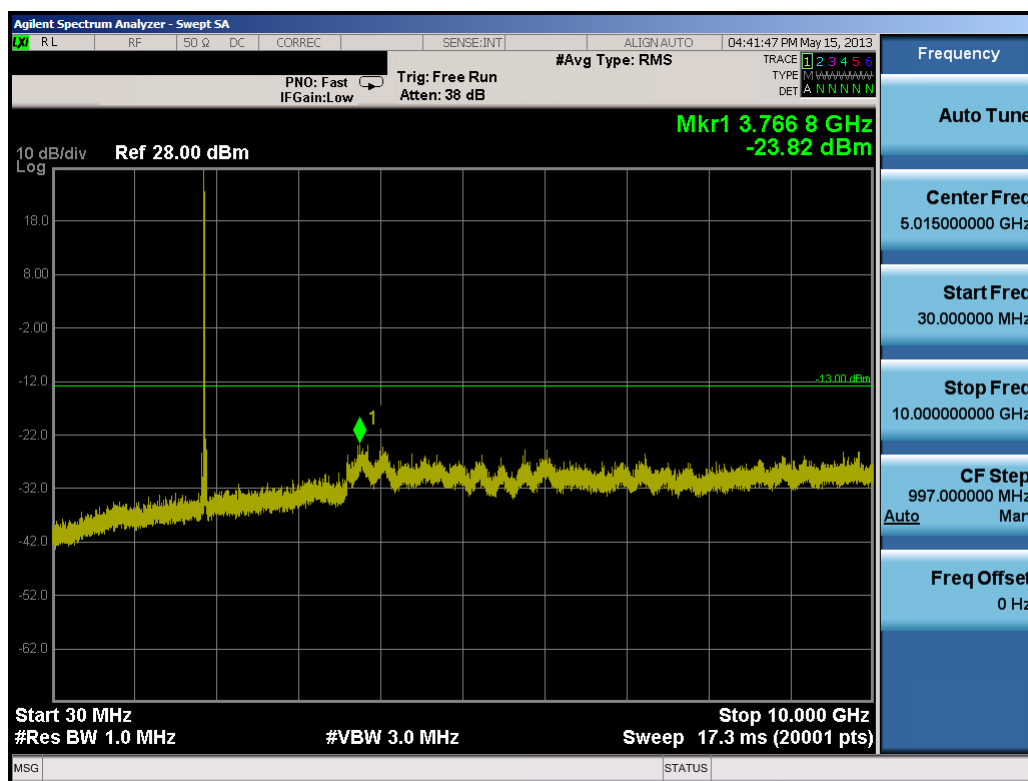


Plot 10-45. Occupied Bandwidth Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 111 of 118

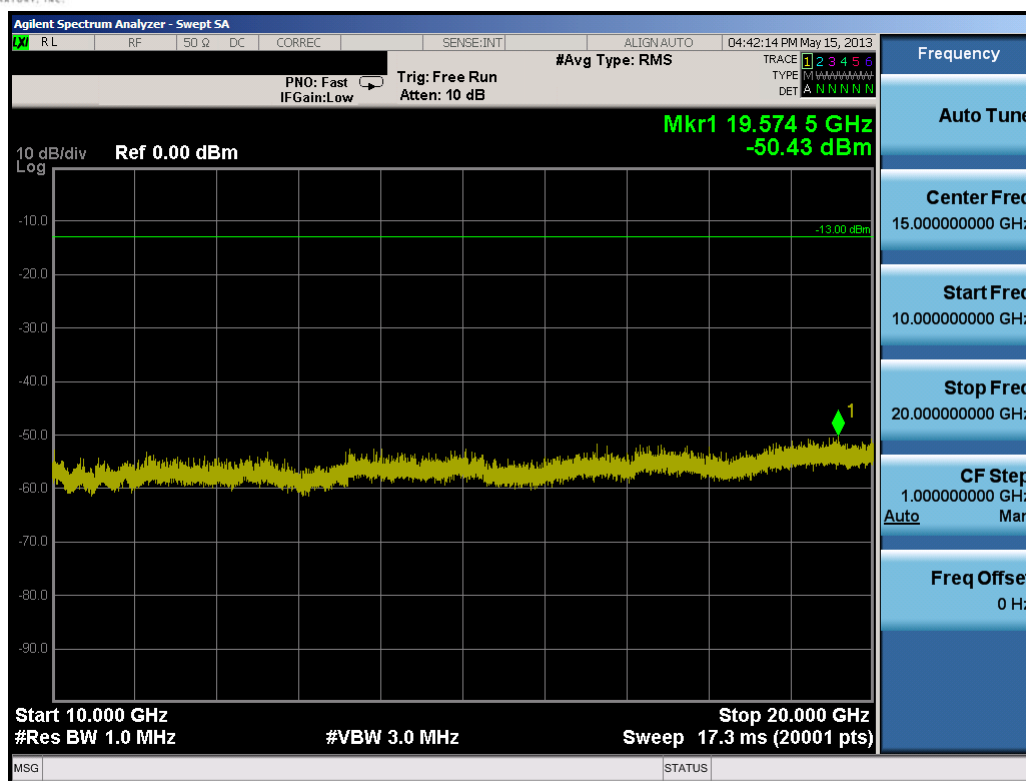


Plot 10-48. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

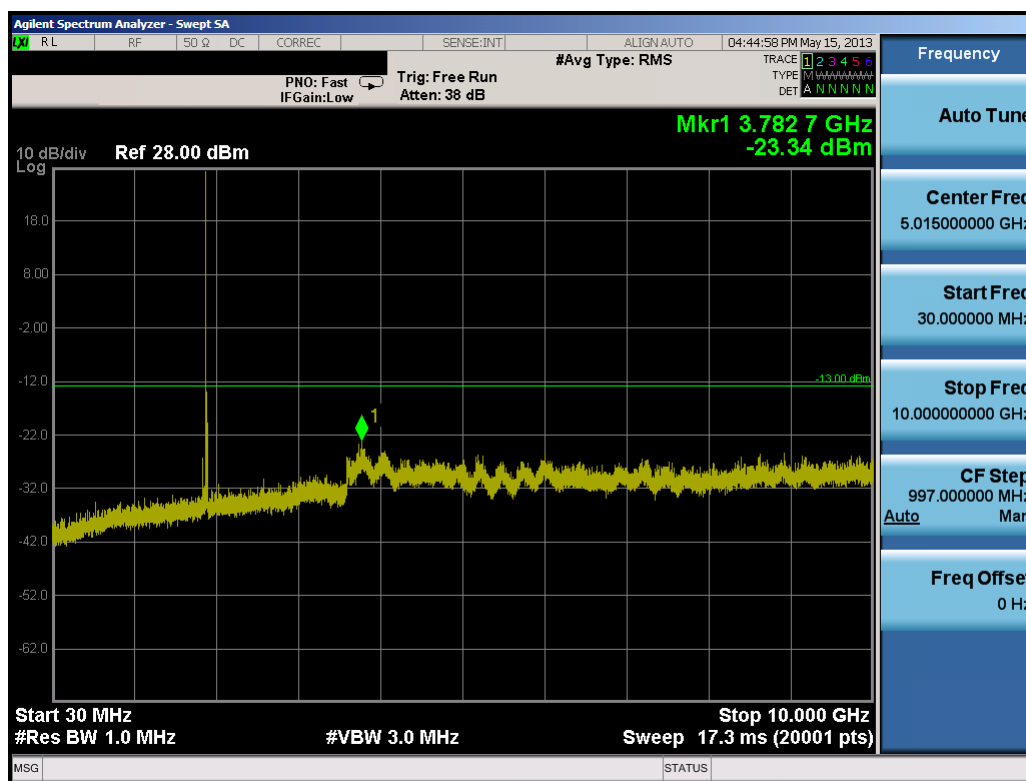


Plot 10-49. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 113 of 118

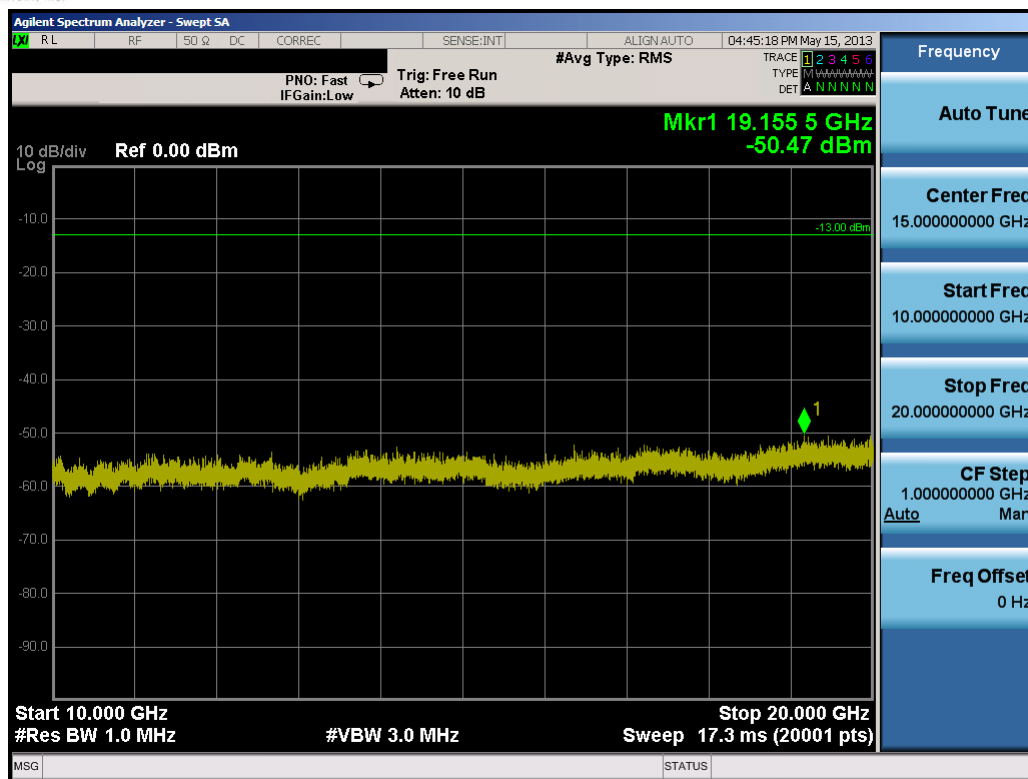


Plot 10-50. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 10-51. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 114 of 118

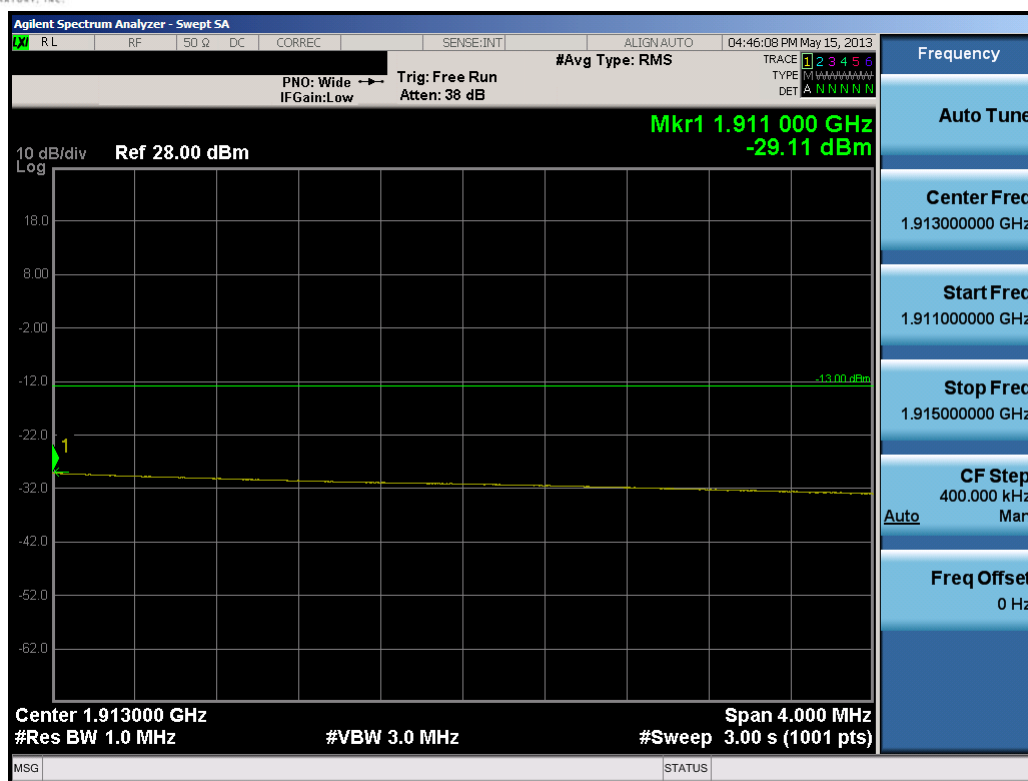


Plot 10-52. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

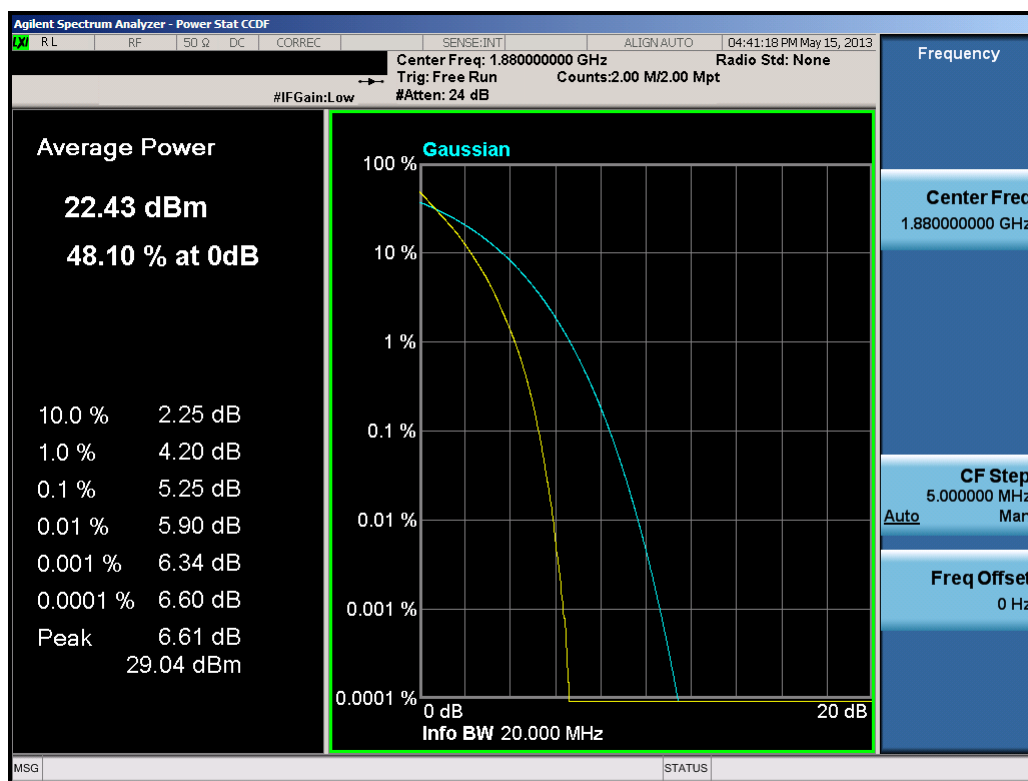


Plot 10-53. Upper Band Edge Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 115 of 118

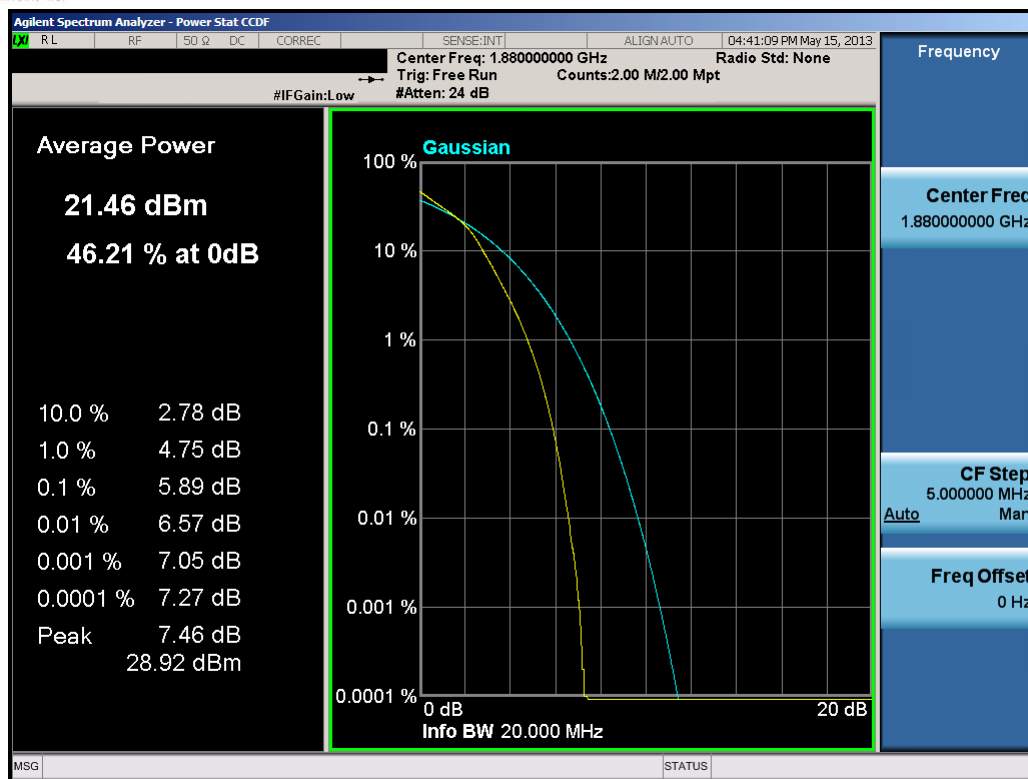


Plot 10-54. Upper Extended Band Edge Plot (20.0MHz QPSK – RB Size 100)



Plot 10-55. PAR Plot (20.0MHz QPSK – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 116 of 118





Plot 10-56. PAR Plot (20.0MHz 16-QAM – RB Size 100)

FCC ID: A3LSGHI527	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset		Page 117 of 118

11.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSGHI527** complies with all the requirements of Parts 2, 22, 24, 27 of the FCC rules for LTE operation only.

FCC ID: A3LSGHI527		FCC Pt. 22, 24, 27 LTE MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1305070815.A3L	Test Dates: 5/15 - 5/22/2013	EUT Type: Portable Handset	Page 118 of 118	